

ARTISAN®
TECHNOLOGY GROUP

Your **definitive** source for quality pre-owned equipment.

Artisan Technology Group
(217) 352-9330 | sales@artisantg.com | artisantg.com

Full-service, independent repair center
with experienced engineers and technicians on staff.

We buy your excess, underutilized, and idle equipment
along with credit for buybacks and trade-ins.

Custom engineering
so your equipment works exactly as you specify.

- Critical and expedited services
- In stock / Ready-to-ship
- Leasing / Rentals / Demos
- ITAR-certified secure asset solutions

Expert team | Trust guarantee | 100% satisfaction

All trademarks, brand names, and brands appearing herein are the property of their respective owners.

Visit our website - *Click HERE*

PPCBug Diagnostics Users Manual

PPCDIAA/UM3

November 2000 Edition

Notice

While reasonable efforts have been made to assure the accuracy of this document, Motorola, Inc. assumes no liability resulting from any omissions in this document, or from the use of the information obtained therein. Motorola reserves the right to revise this document and to make changes from time to time in the content hereof without obligation of Motorola to notify any person of such revision or changes.

Electronic versions of this material may be read online, downloaded for personal use, or referenced in another document as a URL to the Motorola Computer Group website. The text itself may not be published commercially in print or electronic form, edited, translated, or otherwise altered without the permission of Motorola, Inc.

It is possible that this publication may contain reference to or information about Motorola products (machines and programs), programming, or services that are not available in your country. Such references or information must not be construed to mean that Motorola intends to announce such Motorola products, programming, or services in your country.

Limited and Restricted Rights Legend

If the documentation contained herein is supplied, directly or indirectly, to the U.S. Government, the following notice shall apply unless otherwise agreed to in writing by Motorola, Inc.

Use, duplication, or disclosure by the Government is subject to restrictions as set forth in subparagraph (b)(3) of the Rights in Technical Data clause at DFARS 252.227-7013 (Nov. 1995) and of the Rights in Noncommercial Computer Software and Documentation clause at DFARS 252.227-7014 (Jun. 1995).

Motorola, Inc.
Computer Group
2900 South Diablo Way
Tempe, Arizona 85282

Preface

The *PPCBug Diagnostics Manual* provides general information, installation procedures, and a diagnostic firmware guide for the PPCBug Debugging Package. All information contained herein is specific to Motorola's PowerPC™-based boards. In this manual, they are collectively referred to as the *PowerPC board* or *board*. When necessary to refer to them individually, they are identified by their respective models, such as MVME210*x*, MVME240*x*, MVME510*x*, MCP750, and MTX.

Use of the PPCBug debugger, the debugger command set, the one-line assembler/disassembler, and system calls for the debugging package are all described in the two-volume *PPCBug Firmware Package User's Manual (PPCBUGA1/UM and PPCBUGA2/UM)*.

Summary of Changes: A new section on INET was added to this version of the manual. This section describes the Intel Ethernet Controller tests.

This manual is intended for anyone who wants to program these boards in order to design OEM systems, supply additional capability to an existing compatible system, or work in a lab environment for experimental purposes.

A basic knowledge of computers and digital logic is assumed.

To use this manual, you should be familiar with the publications listed in *Appendix A, Related Documentation*.

Conventions Used in This Manual

The following typographical conventions are used in this document:

bold

is used for user input that you type just as it appears; it is also used for commands, options and arguments to commands, and names of programs, directories and files.

italic

is used for names of variables to which you assign values. Italic is also used for comments in screen displays and examples, and to introduce new terms.

`courier`

is used for system output (for example, screen displays, reports), examples, and system prompts.

<Enter>, <Return> or <CR>

represents the carriage return or Enter key.

CTRL

represents the Control key. Execute control characters by pressing the Ctrl key and the letter simultaneously, for example, **Ctrl-d**.

Motorola® and the Motorola symbol are registered trademarks of Motorola, Inc.

PowerStack™ is a trademark of Motorola, Inc.

PowerPC™, and PowerPC 750™ are trademarks of IBM Corp, and are used by Motorola, Inc. under license from IBM Corp.

AIX™ is a trademark of IBM Corp.

All other products mentioned in this document are trademarks or registered trademarks of their respective holders.

©Copyright Motorola 1998, 2000

All Rights Reserved

Printed in the United States of America

Contents

CHAPTER 1 General Information

Introduction 1-1
Overview of PPCBug Firmware 1-1
Debugger and Diagnostic Directories 1-2
Command Entry 1-3
Installation, Configuration, and Start-Up 1-6

CHAPTER 2 Diagnostic Utilities

Introduction 2-1
Utilities 2-1
AEM - Append Error Messages Mode 2-2
CEM - Clear Error Messages 2-3
CF - Test Group Configuration Parameters Editor 2-3
DE - Display Error Counters 2-4
DEM - Display Error Messages 2-4
DP - Display Pass Count 2-5
HE - Help 2-5
HEX - Help Extended 2-8
LA - Loop Always Mode 2-8
LC - Loop-Continue Mode 2-9
LE - Loop-On-Error Mode 2-9
LF - Line Feed Suppression Mode 2-10
LN - Loop Non-Verbose Mode 2-10
MASK - Display/Revise Self Test Mask 2-11
NV - Non-Verbose Mode 2-12
SD - Switch Directories 2-12
SE - Stop-On-Error Mode 2-13
ST and QST - Self Test and Quick Self Test 2-13
ZE - Clear (Zero) Error Counters 2-15
ZP - Zero Pass Count 2-15

CHAPTER 3 Test Descriptions

CL1283 - Parallel Interface Tests 3-2
REG - Register 3-3

DEC - Ethernet Controller Tests 3-4
CINIT - Chip Initialization 3-6
CLOAD - Continuous Load 3-7
CNCTR - Connector 3-8
ERREN - PERREN/SERREN Bit Toggle 3-9
ILR - Interrupt Line Register Access 3-10
IOR - I/O Resource Register Access 3-11
REGA - PCI Header Register Access 3-12
SPACK - Single Packet Send/Receive 3-13
XREGA - Extended PCI Register Access 3-14
DEC Error Messages 3-15
INET - Intel Ethernet Controller Tests 3-20
BINT - Basic Interrupt Test 3-20
EEPT - EEPROM Test 3-21
INST - Internal Self Test 3-22
MDIT - MDI Interface Test 3-22
MPACK - Multiple Packet Interrupt Loopback Test 3-23
PERT - Parity Error Response Test 3-24
SERT - SERR# Enable Response Test 3-25
SPACK - Single Packet Interrupt Loopback Test 3-25
INET Error Messages 3-26
EIDE - EIDE Tests 3-29
General Test Description: 3-29
General Configuration Description: 3-30
ACC - Device Access 3-32
REG - Register Access 3-36
RW - Read/Write Device 3-38
ISABRDGE - PCI/ISA Bridge Tests 3-41
IRQ - Interrupt 3-42
REG - Register 3-43
KBD8730x - Keyboard Controller Tests 3-44
KBCONF - Keyboard Device Confidence/Extended 3-45
KBFAT - Keyboard Test 3-46
KCCONF - Keyboard Controller Confidence/Extended 3-47
KCEXT - Keyboard/Mouse Controller Extended Test 3-48
MSCONF - Mouse Device Confidence/Extended 3-49
MSFAT - Mouse Test 3-50
KBD8730x Error Messages 3-51
L2CACHE - Level 2 Cache Tests 3-55
DISUPD - Disable Updating 3-56
ENUPD - Enable Updating 3-57

PATTERN - WriteThru Pattern 3-58
SIZE - Verify Cache Size 3-59
WBFL - Write Back w/Flush 3-60
WBINV - Write Back w/Invalidate 3-61
WRTHRU - WriteThru 3-62
L2CACHE Error Messages 3-63
NCR - 53C8xx SCSI I/O Processor Tests 3-64
ACC1 - Device Access 3-66
ACC2 - Register Access 3-68
DFIFO - DMA FIFO 3-70
IRQ - Interrupts 3-72
PCI - PCI Access 3-75
SCRIPTS - SCRIPTs Processor 3-77
SFIFO - SCSI FIFO 3-80
PAR8730x - Parallel Port Test 3-81
REG - Register 3-82
UART - Serial Input/Output Tests 3-83
BAUD - Baud Rates 3-84
IRQ - Interrupt Request 3-85
LPBK - Internal Loopback 3-86
LPBKE - External Loopback 3-87
REGA - Device/Register Access 3-88
UART Error Messages 3-89
PCIBUS - Generic PCI/PMC Slot Tests 3-91
REG - PCI/PMC Slot Register Access 3-92
PCIBUS Error Messages 3-93
RAM - Local RAM Tests 3-94
ADR - Memory Addressing 3-95
ALTS - Alternating Ones/Zeros 3-97
BTOG - Bit Toggle 3-98
CODE - Code Execution/Copy 3-100
MARCH - March Pattern 3-101
PATS - Data Patterns 3-102
PED - Local Parity Memory Error Detection 3-103
PERM - Permutations 3-105
QUIK - Quick Write/Read 3-106
REF - Memory Refresh Testing 3-107
RNDM - Random Data 3-109
RTC - MK48Txx Timekeeping Tests 3-110
ADR - MK48Txx BBRAM Addressing 3-111
ALARM - Alarm Interrupt 3-113

CLK - Real Time Clock Function 3-114
RAM - Battery Backed-Up RAM 3-116
WATCHDOG - Watchdog Time-Out Reset 3-117
SCC - Serial Communication Controller (Z85230) Tests 3-118
ACCESS - Device/Register Access 3-120
BAUDS - Baud Rates 3-121
DMA - Receive/Transmit DMA 3-122
ELPBCK - External Loopback 3-124
ILPBCK - Internal Loopback 3-125
IRQ - Interrupt Request 3-126
MDMC - Modem Control 3-127
SCC Error Messages 3-128
VGA54XX - Video Diagnostics Tests 3-130
ATTR - Attribute Register 3-132
BLT - Bit Blitter 3-133
CRTC - CRT Controller Registers 3-134
DSTATE - DAC State Register 3-135
EXTN - Extended Registers 3-136
GRPH - Graphics Controller Registers 3-137
MISC - Miscellaneous Register 3-138
PAL - Color Palette 3-139
PCI - PCI Header Verification 3-140
PELM - Pixel Mask Register 3-141
SEQR - Sequencer Registers 3-142
VRAM - Video Memory 3-143
VME2 - VME Interface ASIC Tests 3-144
VME3- Universe VME to PCI Bridge Tests 3-144
REGR - Register Read 3-146
REGW - Register Write/Read 3-147
VME3 Error Messages 3-148
Z8536 - Counter/Timer Tests 3-149
CNT - Counter 3-150
IRQ - Interrupt 3-151
LNK - Linked Counter 3-152
REG - Register 3-153

APPENDIX A Related Documentation

Motorola Computer Group Documents A-1
Microprocessor and Controller Documents A-3
Related Specifications A-9

List of Figures

Figure 2-1. Help Screen (Sheet 1 of 2) 2-6

List of Tables

Table 2-1. Diagnostic Utilities 2-1
Table 3-1. Diagnostic Test Groups 3-1
Table 3-2. CL1283 Test Group 3-2
Table 3-3. DEC Test Group 3-4
Table 3-4. DEC Error Messages 3-15
Table 3-5. INET Test Group 3-20
Table 3-6. INET Error Messages 3-27
Table 3-7. EIDE Test Group 3-29
Table 3-8. ISABRDGE Test Group 3-41
Table 3-9. KBD8730x Test Group 3-44
Table 3-10. KBD8730x Error Messages 3-51
Table 3-11. L2CACHE Test Group 3-55
Table 3-12. L2CACHE Error Messages 3-63
Table 3-13. NCR Test Group 3-64
Table 3-14. PAR8730x Test Group 3-81
Table 3-15. UART Test Group 3-83
Table 3-16. UART Error Messages 3-89
Table 3-17. PCIBUS Test Group 3-91
Table 3-18. PCIBUS Error Messages 3-93
Table 3-19. RAM Test Group 3-94
Table 3-20. RTC Test Group 3-110
Table 3-21. SCC Test Group 3-118
Table 3-22. SCC Error Messages 3-128
Table 3-23. VGA543X Test Group 3-130
Table 3-24. VME2 Test Group 3-144
Table 3-25. VME3 Test Group 3-145
Table 3-26. VME3 Error Messages 3-148
Table 3-27. Z8536 Test Group 3-149
Table A-1. Motorola Computer Group Documents A-1
Table A-2. Microprocessor and Controller Documents A-3
Table A-3. Related Specifications A-9

General Information 1

Introduction

This manual describes the complete set of hardware diagnostics included in the PPCBug Debugging Package, intended for testing and troubleshooting Motorola's PowerPC-based boards. This member of the PPCBug firmware family, known as PPCBug diagnostics, is implemented on many of the Motorola PowerPC-based products as part of a standard proprietary debugging and diagnostic tool set.

Boards using this tool set are referred to in this manual as the *PowerPC board* or *board*. When necessary to refer to them individually, they are referred to by their individual product names, such as MVME210*x*, MVME230*x*, MVME360*x*, MVME510*x*, MCP750, MTX, etc.

This introductory chapter includes information about the operation and use of the diagnostics. Chapter 2 contains descriptions of the diagnostic utilities. Chapter 3 contains descriptions of the diagnostic test routines.

Before using the PPCBug diagnostics, ensure that the PowerPC board and other hardware are properly configured and connected, according to the installation guide for that particular PowerPC board. The two-volume manual for the PPCBug Debugging Package, *PPCBug Firmware Package User's Manual*, should also be available. It contains a complete description of PPCBug, the start-up procedure, all general software debugging commands, and other information about the debugger.

Overview of PPCBug Firmware

The PPCBug firmware consists of three parts:

- A command-driven, user-interactive *software debugger*, described in the *PPCBug Firmware Package User's Manual*.
- A command-driven *diagnostics package* for the PowerPC board hardware, described in this manual. The diagnostic firmware

contains a battery of utilities and tests for exercise, test, and debug of hardware in the PowerPC board environment. The diagnostics are menu-driven for ease of use.

- A *user interface* or *debug/diagnostics monitor* that accepts commands from the system console terminal. The tests described in this manual are implemented by the firmware, commands are input, and results are reported via this monitor, which is the common device used for both the debugger and the diagnostics. The monitor is command-line driven and provides input and output facilities, command parsing, error reporting, interrupt handling, and a multi-level directory for menu selection.

Debugger and Diagnostic Directories

When using PPCBug, operate from either the debugger directory or the diagnostic directory:

- When in the debugger directory, the debugger prompt `PPCx-Bug>` is displayed and all of the debugger commands are available.

Note Earlier versions of this firmware, e.g., `PPC1Bug`, will not contain all commands available in later versions, such as `PPC6Bug`.

- When in the diagnostic directory, the diagnostic prompt `PPCx-Diag>` is displayed and all of the diagnostic commands are available, as well as all of the debugger commands.

To use the diagnostic part of the firmware, the diagnostic directory must be open. If the `PPCx-Bug>` prompt (debugger directory) is displayed, the wrong directory is open. To switch to the diagnostic directory enter **SD** (Switch Directories command). This displays the diagnostic prompt `PPCx-Diag>`.

To examine the commands in the current open directory use the Help (**HE**) command.

Because PPCBug is command-driven, it performs various operations in response to commands that are entered at the keyboard. PPCBug executes the command and the prompt reappears. However, a command is entered that causes execution of some user target code (e.g., **GO**), then control may or may not return to PPCBug, depending on the outcome of the user program.

The Help (**HE**) command displays a menu of all available diagnostic functions; i.e., the tests and utilities. Several tests have a subtest menu, which may be called using the **HE** command. In addition, some utilities have subfunctions, and as such have subfunction menus.

Command Entry

Enter the name of a diagnostic command when the prompt `PPCx-Diag>` appears, and then press the **RETURN** or **ENTER** key.

The command may be the name of a diagnostic utility routine and may include one or more arguments; or it may be the name of one or more test groups listed in a main (root) directory and may include one or more subcommands (individual test names) listed in the subdirectory for a particular test group.

The utility routines are described in Chapter 2. The test groups are described in Chapter 3. Examples of command entry for both are given below.

Root-Level Command (Utility):

The utility or root-level commands affect the operation of the tests that are subsequently run. A test group name may be entered on the same command line. For example:

```
PPCx-Diag>CF RAM
```

causes an interactive dialog to begin, during which parameters for the **RAM** tests may be entered.

Command entry may also include a subcommand (individual test name). For example:

```
PPCx-Diag>HE DEC2 ERREN
```

causes a help screen to appear that gives information about the **ERREN** test in the **DEC** test group.

Root-Level Command (Test Group):

Entering just the name of a test group causes all individual tests that are part of that group to execute in sequence (with some exceptions). For example:

```
PPCx-Diag>RAM
```

causes all Random Access Memory (**RAM**) tests to execute, except for two that only execute if specified.

Subdirectory-Level Command (Individual Test):

Entering the name of a test group followed by the name of an individual test from that group causes just that test to execute.

For example, to call up a particular Random Access Memory (**RAM**) test, enter:

```
PPCx-Diag>RAM ADR
```

This causes the monitor to find the **RAM** test group subdirectory, and then to execute the Memory Addressing test command **ADR** from that subdirectory.

To call up a particular **DEC** test, enter:

```
PPCx-Diag>DEC REGA
```

This causes the monitor to find the **DEC** test group subdirectory, and then to execute the PCI Register Access command **REGA** from that subdirectory.

Multiple Subdirectory-Level Commands (Individual Tests):

If the first part of a command is a test group name, any number and/or sequence of tests from that test group may be entered after the test group name so long as the debugger's input buffer size limit is not exceeded. For example:

```
PPCx-Diag>RAM PATS ADR
```

This causes both the Data Patterns (**PATS**) and the Memory Addressing (**ADR**) tests from the **RAM** test group to execute.

Multiple Root-Level Commands (Test Groups):

Multiple commands may be entered. If a command expects parameters and another command is to follow it, separate the two with a semicolon (**;**).

For example, to invoke the command **RTC CLK** (to execute the Real Time Clock Function test from the MK48Txx Real Time Clock test group) after the command **RAM ADR**, the command line would read:

```
PPCx-Diag>RAM ADR; RTC CLK
```

Spaces are not required before or after the semicolon but are shown here for legibility. Spaces are required between commands and their arguments. Several commands may be combined on one line.

Installation, Configuration, and Start-Up

The PPCBug firmware is installed by Motorola at the factory when your PowerPC board is manufactured.

Refer to your PowerPC board installation manual and ensure that all necessary hardware preparation, board installation, connection of peripherals, and hardware configuration, including console selection and configuration of Software Readable Headers (where applicable), has been correctly done.

After the hardware is configured and installed according to the installation manual, refer to the *PPCBug Firmware Package User's Manual* for the start-up procedure before powering up the system.

Diagnostic Utilities 2

Introduction

This chapter contains descriptions and examples of the various diagnostic utilities available in PPCBug.

Utilities

In addition to individual or sets of tests, the diagnostic package supports the utilities (root-level commands or general commands) listed in the table below and described on the following pages.

Table 2-1. Diagnostic Utilities

Command	Description
AEM	Append Error Messages Mode
CEM	Clear Error Messages
CF	Test Group Configuration Parameters Editor
DE	Display Error Counters
DEM	Display Error Messages
DP	Display Pass Count
HE	Help
HEX	Help Extended
LA	Loop Always Mode
LC	Loop-Continue Mode
LE	Loop-On-Error Mode
LF	Line Feed Suppression Mode
LN	Loop Non-Verbose Mode
MASK	Display/Revise Self Test Mask
NV	Non-Verbose Mode
QST	Quick Self Test
SD	Switch Directories

Table 2-1. Diagnostic Utilities (Continued)

Command	Description
SE	Stop-On-Error Mode
ST	Self Test
ZE	Clear (Zero) Error Counters
ZP	Zero Pass Count

Notes You may enter command names in either uppercase or lowercase.

Terminate all command lines by pressing the **RETURN** key.

AEM - Append Error Messages Mode

The **AEM** command allows you to accumulate error messages in the internal error message buffer of the diagnostic monitor.

This command sets the internal append error messages flag of the diagnostic monitor. The default of the internal append error messages flag is clear. The internal flag is not set until it is encountered in the command line by the diagnostic monitor.

The contents of the buffer can be displayed with the **DEM** command.

When the internal append error messages flag is not set or is cleared with **CEM**, the diagnostic error message buffer is erased (cleared of all character data) before each test is executed.

The duration of this command is for the life of the command line being parsed by the diagnostic monitor.

Example:

```
PPCx-Diag>aem; ram ref
RAM    REF: Memory Refresh Test..... Running ---> FAILED
```

(error message written to error message buffer)

```
PPCx-Diag>
```

CEM - Clear Error Messages

This command allows you to clear the internal error message buffer of the diagnostic monitor manually.

Example:

```
PPCx-Diag>cem
```

(error message buffer is cleared)

```
PPCx-Diag>
```

CF - Test Group Configuration Parameters Editor

The **CF** parameters control the operation of all tests in a test group.

For example, the **RAM** test group has parameters such as starting address, ending address, parity enable, etc. At the time of initial execution of the diagnostic monitor, the default configuration parameters are copied from the firmware into the debugger work page. Here you can modify the configuration parameters via the **CF** command.

When you invoke the **CF** command, you are interactively prompted with a brief parameter description and the current value of the parameter. You may enter a new value for that parameter, or a **RETURN** to accept the current value and proceed to the next configuration parameter. To discontinue the interactive process, enter a period (**.**) followed by **RETURN**.

You may specify one or more test groups as argument(s) immediately following the **CF** command on the command line. If no arguments follow the **CF** command, the parameters for all test groups are presented so you may change them if you wish.

Examples:

```
PPC1-Diag>cf
RAM Configuration Data:
Starting/Ending Address Enable [Y/N] =N ?RETURN
Starting Address =00004000 ?RETURN
Ending Address   =00F84FFC ?RETURN
Random Data Seed =12301983 ?RETURN
March Address Pattern =00000000 ?RETURN
Instruction (Code) Cache Enable [Y/N] =Y ? .RETURN
PPC1-Diag>cf scc
SCC Configuration Data:
SCC Memory Space Base Address             =80000840 ? RETURN
Internal-Loopback/Baud-Rates Port Mask    =00000003 ? RETURN
External-Loopback/Modem-Control Port Mask =00000003 ?RETURN
PPC1-Diag>
```

DE - Display Error Counters

Each test or command in the diagnostic monitor has an individual error counter. As errors are encountered in a particular test, that error counter is incremented. If you were to run a self test or just a series of tests, the results could be broken down as to which tests passed by examining the error counters.

To display all error counters after the conclusion of a test, enter **DE**. **DE** displays the results of a particular test if the name of that test follows **DE**. Only nonzero values are displayed.

Example:

```
PPCx-Diag>de ram addr
PPCx-Diag>
```

DEM - Display Error Messages

This command allows you to display (dump) the internal error message buffer of the diagnostic monitor manually.

Example:

```
PPCx-Diag>dem
```

(contents of error message buffer are displayed)

```
PPCx-Diag>
```

DP - Display Pass Count

A count of the number of passes in Loop-Continue (**LC**) mode is kept by the monitor. This count is displayed with other information at the conclusion of each pass. To display this information without using **LC**, enter **DP**.

Example:

```
PPCx-Diag>dp
Pass Count =19
PPCx-Diag>
```

HE - Help

The Help command provides on-line documentation. Entering **HE** at the diagnostics prompt (`PPCx-Diag>`) displays a menu of the top level directory of utility commands and test group names if no parameters are entered, or the menu of a subdirectory if the name of that subdirectory, or test group name, is entered following **HE**.

The display of the top level directory lists `"(DIR)"` after the name of each command that has a subdirectory.

Note If **HE** is entered to the debugger prompt (`PPCx-Bug>`), the debugger commands are displayed.

Examples:

To display the menu of all utility and test group names, enter:

```
PPCx-Diag>he
```

(see Figure 2-1)

When a menu is too long to fit on the screen, it pauses until you press **RETURN** again.

```
PPC1-Diag>he
AEM       Append Error Messages Mode
CEM       Clear Error Messages
CF        Configuration Editor
CL1283    Parallel Interface (CL1283) Tests (DIR)
CS4231    cs4231 Audio Codec (DIR)
DE        Display Errors
DEC       Ethernet Controller (DEC21x40) Tests (DIR)
DEM       Display Error Messages
DP        Display Pass Count
EIDE     EIDE Tests (DIR)
HE        Help on Tests/Commands
HEX       Help Extended
ISABRDGE ISA Bridge Tests (DIR)
KBD8730X Keyboard/Mouse Controller Tests (DIR)
L2CACHE  L2-Cache (DIR)
LA        Loop Always Mode
LC        Loop Continuous Mode
LE        Loop on Error Mode
LF        Line Feed Mode
LN        Loop Non-Verbose Mode
MASK      Self Test Mask
NCR       NCR 53C8XX SCSI I/O Processor Tests (DIR)
NV        Non-Verbose Mode
PAR8730X Parallel Interface (PC8730x) Tests (DIR)
PCIBUS    PCI/PMC Generic
Press "RETURN" to continue
```

Figure 2-1. Help Screen (Sheet 1 of 2)

```
QST      Quick Self Test (DIR)
RAM      Random Access Memory Tests (DIR)
RTC      MK48Txx Timekeeping (DIR)
SCC     Serial Communication Controller(Z85C230)Tests (DIR)
SE       Stop on Error Mode
ST       Self Test (DIR)
UART     Serial Input/Output Tests (DIR)
VGA54XX VGA Controller (GD54XX) Tests (DIR)
VME2     VME2Chip2 Tests (DIR)
Z8536    z8536 Counter/Timer Input/Output Tests (DIR)
ZE       Zero Errors
ZP       Zero Pass Count
PPC1-Diag>
```

Figure 2-1. Help Screen (Sheet 2 of 2)

To bring up a menu of all the RAM memory tests, enter:

```
PPC1-Diag>he ram
RAM      Random Access Memory Tests (DIR)
ADR      Addressability
ALTS     Alternating Ones/Zeroes
BTOG     Bit Toggle
CODE     Code Execution/Copy
MARCH    March Address
PATS     Patterns
PED      Local Parity Memory Error Detection
PERM     Permutations
QUIK     Quick Write/Read
REF      Memory Refresh Test
RNDM     Random Data
PPC1-Diag>
```

To review a description of an individual test, enter the full name:

```
PPC1-Diag>he ram code
RAM      Random Access Memory Tests (DIR)
CODE     Code Execution/Copy
PPC1-Diag>
```

This displays information on the RAM Code Execution/Copy test routine.

HEX - Help Extended

The **HEX** command goes into an interactive, continuous mode of the **HE** command.

The prompt displayed for **HEX** is the question mark (**?**). You may then type the name of a directory or command. You must type **QUIT** to exit.

Example:

```
PPCx-Diag>HEX
Extended Help, Type <QUIT> to Exit
? lc
LC       Loop Continuous Mode
? ISABRDGE irq
ISABRDGE   ISA Bridge Tests (DIR)
IRQ      Interrupt Request
? quit
PPCx-Diag>
```

LA - Loop Always Mode

To repeat a test or series of tests endlessly, enter the prefix **LA**. The **LA** command modifies the way that a failed test is endlessly repeated.

The **LA** command has no effect until a test failure occurs, at which time, if the **LA** command has been previously encountered in the user command line, the failed test is endlessly repeated. To break the loop, press the **BREAK** key on the diagnostic video display terminal.

Certain tests disable the **BREAK** key interrupt, so it may become necessary to press the abort or reset switches on the PowerPC board front panel.

Example:

```
PPCx-Diag>la;ram adr
RAM   ADR: Addressability..... Running ---> PASSED
```

*(no errors detected so **LA** is ignored)*

```
PPCx-Diag>
```

LC - Loop-Continue Mode

To repeat a test or series of tests endlessly, enter the prefix **LC**. This loop includes everything on the command line.

To break the loop, press the **BREAK** key on the diagnostic video display terminal. Certain tests disable the **BREAK** key interrupt, so it may become necessary to press the abort or reset switches on the PowerPC board front panel.

Example:

```
PPCx-Diag>lc;ram adr
RAM   ADR: Addressability.............. Running ---> PASSED
Pass Count =1, Errors This Pass =0, Total Errors =0
RAM   ADR: Addressability.............. Running ---> PASSED
Pass Count =2, Errors This Pass =0, Total Errors =0
RAM   ADR: Addressability.............. Running ---> PASSED
Pass Count =3, Errors This Pass =0, Total Errors =0
RAM   ADR: Addressability.............. Running ---> <BREAK>
--Break Detected--
PPCx-Diag>
```

LE - Loop-On-Error Mode

Occasionally, when an oscilloscope or logic analyzer is in use, it becomes desirable to repeat a test endlessly (loop) while an error is detected. The **LE** command modifies the way a failed test is endlessly repeated.

The **LE** command has no effect until a test failure occurs, at which time, if the **LE** command has been previously encountered in the user command line, the failed test is re-executed as long as the previous execution returns failure status.

To break the loop, press the **BREAK** key on the diagnostic video display terminal. Certain tests disable the **BREAK** key interrupt, so it may become necessary to press the abort or reset switches on the PowerPC board front panel.

Example:

```
PPCx-Diag>le;scc
SCC    ACCESS: Device/Register Access...... Running ---> PASSED
SCC    IRQ: Interrupt Request.............. Running ---> FAILED

SCC/IRQ Test Failure Data:
(error message)

SCC    IRQ: Interrupt Request.............. Running ---> FAILED

SCC/IRQ Test Failure Data:
(error message)

SCC    IRQ: Interrupt Request.............. Running --->
<BREAK>
--Break Detected--
PPCx-Diag>
```

LF - Line Feed Suppression Mode

Entering **LF** on a command line sets the internal line feed mode flag of the diagnostic monitor. The duration of the **LF** command is the life of the user command line in which it appears.

The default state of the internal line feed mode flag is clear, which causes the executing test title/status line(s) to be terminated with a line feed character (scrolled).

The line feed mode flag is normally used by the diagnostic monitor when executing a System Mode self test. Although rarely invoked as a user command, the **LF** command is available to the diagnostic user.

Example:

```
PPCx-Diag>LF;RAM
RAM    ADR: Addressability................ Running ---> PASSED

       (display of subsequent RAM test messages overwrite this line)

PPCx-Diag>
```

LN - Loop Non-Verbose Mode

The **LN** command modifies the way a failed test is endlessly repeated.

The **LN** command has no effect until a test failure occurs, at which time, if the **LN** command has been previously encountered in the user command line, further printing of the test title and pass/fail status is suppressed. This is useful for more rapid execution of the failing test; i.e., the **LN** command contributes to a “tighter” loop.

Example:

```
PPC1-Diag>LN;RAM ADR
RAM ADR: RAM   ADR: Addressability........ Running ---> PASSED
Pass Count =1, Errors This Pass =0, Total Errors =0
RAM   ADR: Addressability................. Running ---> PASSED
Pass Count =2, Errors This Pass =0, Total Errors =0
RAM   ADR: Addressability................. Running ---> PASSED
Pass Count =3, Errors This Pass =0, Total Errors =0
RAM   ADR: Addressability................. Running ---> <BREAK>
--Break Detected--
PPC1-Diag>
```

MASK - Display/Revise Self Test Mask

Using **MASK** with an argument enables/disables the specified test from running under self test. The argument must be a specific test name. If **mask** is invoked without arguments, the current self test mask, showing disabled tests, is displayed.

The **mask** command is a “toggle” command -- if the specified test name mask was set, it will be reset; if it was reset, it will be set. After the toggle, the new self test mask is displayed.

If the **mask** command is invoked with an invalid test name or a test directory (as opposed to a specific test name), an appropriate error message is output.

When the **mask** command is used on a PowerPC board system, the mask values are preserved in non-volatile memory. This allows the system to be completely powered down without disturbing the self test mask.

Example:

```
PPC1-Diag>mask ram adr
Update Non-Volatile RAM (Y/N)? y
RAM/ADR
PPC1-Diag>mask
RAM/ADR
PPC1-Diag>
```

NV - Non-Verbose Mode

Upon detecting an error, the tests display a substantial amount of data. To avoid the necessity of watching the scrolling display, you can choose a mode that suppresses all messages except test name and PASSED or FAILED. This mode is called *non-verbose* and you can invoke it prior to calling a command by entering **NV**.

Example:

```
PPC1-Diag>nv;uart lpbke
UART LPBKE:External Loopback .......Running --> FAILED
PPC1-Diag>
```

NV causes the monitor to run the UART external loopback test, but show only the name of the test and the results (pass/fail).

```
PPC1-Diag>uart lpbke
UART LPBKE:External Loopback .......Running --> FAILED

UART/LPBKE Test Failure Data:
RTS loopback to CTS or RI Failed: COM2

PPC1-Diag>
```

Without **nv**, the failure data is displayed.

SD - Switch Directories

The **SD** command allows you to switch back and forth between PPCBug's diagnostic directory (the prompt reads PPC*x*-Diag>) and the debug directory (the prompt reads PPC*x*-Diag>).

If you are in the diagnostic directory and enter **SD**, you will return to the debug directory. At this point, only the debug commands for PPC1Bug can be entered.

If you are in the debug directory and enter **SD**, you will return to the diagnostic directory. You may enter either the diagnostic or debug commands from the diagnostics directory.

Example:

```
PPC1-Diag>sd
PPC1-Bug>sd
PPC1-Diag>
```

SE - Stop-On-Error Mode

Sometimes you may want to stop a test or series of tests at the point where an error is detected. **SE** accomplishes that for most of the tests. To invoke **SE**, enter it before the test or series of tests that is to run in Stop-On-Error mode.

Example:

```
PPC1-Diag>se; dec ior ilr; scc dma irq
DEC IOR:I/O Resource Register Access...Running --> PASSED
DEC ILR:Interrupt Line Register Access.Running --> PASSED
SCC      DMA: DMA Test..................... Running --> FAILED
(error message)
```

(error encountered in DMA test so IRQ test not run)

```
PPC1-Diag>
```

ST and QST - Self Test and Quick Self Test

The diagnostics monitor provides an automated test mechanism called *self test*. This mechanism runs all the tests included in an internal self test directory.

Entering the **QST** command executes the suite of self tests that are run at start-up. Entering **ST** causes more tests to execute than does **QST**, but also requires more test time.

The commands **HE ST** and **HE QST** list the top level commands of the self test directory in alphabetical order. Each test for that particular command is listed in the section pertaining to the command.

For details on extended self test operation, refer to the *PPCBug Firmware Package User's Manual*.

Example:

```
PPC1-Diag>qst
RAM     ADR: Addressability.............. Running ---> PASSED
UART REGA: Register Access............... Running ---> PASSED
UART IRQ: Interrupt...................... Running ---> PASSED
UART BAUD: Baud Rate..................... Running ---> PASSED
UART LPBK: Internal Loopback............. Running ---> PASSED
Z8536   CNT: Counter..................... Running ---> PASSED
Z8536   LNK: Linked Counter.............. Running ---> PASSED
Z8536   IRQ: Interrupt................... Running ---> PASSED
```

(all tests in quick self test directory are run)

```
PPC1-Diag>
```

ZE - Clear (Zero) Error Counters

The error counters originally come up with the value of zero, but it is occasionally desirable to reset them to zero at a later time. This command resets all of the error counters to zero.

Example:

```
PPC1-Diag>ze
PPC1-Diag>
```

This clears all error counters.

ZP - Zero Pass Count

Invoking the **ZP** command resets the pass counter to zero. This is frequently desirable before typing in a command that invokes the Loop-Continue mode. Entering this command on the same line as **LC** results in the pass counter being reset on every pass.

Example:

```
PPC1-Diag>lc;ram adr ;zp
RAM   ADR: Addressability.................. Running ---> PASSED

Pass Count =1, Errors This Pass =0, Total Errors =0
RAM   ADR: Addressability.................. Running ---> PASSED

Pass Count =1, Errors This Pass =0, Total Errors =0
RAM   ADR: Addressability.................. Running ---> PASSED

Pass Count =1, Errors This Pass =0, Total Errors =0
RAM   ADR: Addressability.................. Running --->
<BREAK>
--Break Detected--
PPC1-Diag>
```

Test Descriptions 3

Detailed descriptions of PPCBug's diagnostic tests are presented in this chapter. The test groups are described in the order shown in the following table. Some test groups do not run on all PowerPC boards. The column *PowerPC Board* lists the boards on which each group of tests will run.

Table 3-1. Diagnostic Test Groups

Test Group	Description	PowerPC Board
CL1283	Parallel Interface (CL1283) Tests	MTX
DEC	DEC21*x*40 Ethernet Controller Tests	All
INET	Intel 82559/ER Ethernet Controller Tests	All
EIDE	IDE/EIDE Device Tests	MTX, MCP750
ISABRDGE	PCI/ISA Bridge Tests	All
KBD8730X	PC8730x Keyboard/Mouse Tests	All
L2CACHE	Level 2 Cache Tests	All
NCR	NCR 53C8xx SCSI2 I/O Processor Tests	All
PAR8730X	Parallel Interface (PC8730x) Tests	All
UART	Serial Input/Output Tests	All
PCIBUS	PCI/PMC Generic Tests	All
RAM	Local RAM Tests	All
RTC	MK48Txx Timekeeping Tests	All
SCC	Serial Communication Controller (Z85C230) Tests	All except MVME230*x*
VGA54XX	Video Diagnostics Tests	MVME360*x*, MVME460*x*
VME2	VMEchip2 VME Interface ASIC Tests	None
VME3	VMEchip3 VME Interface ASIC Tests	None
Z8536	Z8536 Counter/Timer Tests	All except MVME230*x*

Notes 1. You may enter command names in either uppercase or lowercase.

2. Some diagnostics depend on restart defaults that are set up only in a particular restart mode. Refer to the documentation on a particular diagnostic for the correct mode.

CL1283 - Parallel Interface Tests

This section describes the CL1283 parallel Interface (CL1283) tests.

Note These tests apply only to the MTX boards. They are not available on the other PowerPC boards: MVME230*x*, MVME260*x*, MVME2700, MVME360*x*, MVME460*x*, and PMCspan.

Entering **CL1283** without parameters causes all **CL1283** tests to execute in the order shown in the following table.

To run an individual test, add that test name to the **CL1283** command.

The individual tests are described in alphabetical order on the following pages.

Table 3-2. CL1283 Test Group

Name	Description
REG	Register

REG - Register

Command Input

```
PPCx-Diag>CL1283 REG
```

Description

This test verifies that the CL1283 registers can be read and written. Data patterns verify that every read/write bit can be modified.

Response/Messages

After the command has been issued, the following line is printed:

```
CL1283 REG: cl1283 Register Access...... Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
CL1283 REG: cl1283 Register Access...... Running ---> PASSED
```

If the board does not support the CL1283, the following is displayed:

```
CL1283 REG: cl1283 Register Access......Running ---> BYPASSED
```

If any failures occur, the following is displayed (more descriptive text then follows):

```
CL1283 REG: cl1283 Register Access...... Running ---> FAILED
```

If the test fails because the pattern written does not match the one read back from the CL1283 register, the following is printed:

```
CL1283 INDIRECT:Local Parity Memory Detection..Running --> FAILED

cl1283 Register: xxx, Expected bit#_ to be high/low, Actual reg
value xx
```

DEC - Ethernet Controller Tests

These sections describe the individual DEC21*x*4x Ethernet Controller tests.

The firmware now provides support for testing of multiple Ethernet controllers within PCI configuration space. This means that the DEC diagnostics can now be run on multiple DEC Controllers. This is "only" true for any firmware supported DEC21x4x Ethernet devices.

Examples of where DEC tests run on multiple controllers include:

1. On a PowerPC that has two (2) DEC21x4x devices on the board.
2. On a PowerPC board that has one (1) DEC21x4x device on the board and one (1) DEC21x4x device on the board and one DEC21x4x PMC/PCI card attached to the board.
3. On a PowerPC board that has one (1) DEC21x4x device on the board and a DEC21x4x card attached to a PMC carrier plugged into the backplane of the chassis.

Entering **DEC** without parameters causes all **DEC** tests to run in the order shown in the table below, except as noted.

To run an individual test, add that test name to the **DEC** command.

The individual tests are described in alphabetical order on the following pages.

Table 3-3. DEC Test Group

Name	Description
REGA	Register Access
XREGA	Extended Register Access
SPACK	Single Packet Transmit and Receive
ILR	Interrupt Line Register Access
ERREN	PERREN and SERREN Bit Toggle
IOR	I/O Resource Register Access

Table 3-3. DEC Test Group

Name	Description
CINIT	Chip Initialization
Executed only when specified:	
CLOAD	Continuous Load
CNCTR	Connector

None of these tests need any external hardware hooked up to the Ethernet port, with the exception of the **CNCTR** test, which needs external loopback “plugs” in the external connector.

CINIT - Chip Initialization

Command Input

```
PPCx-Diag>dec cinit
```

Description

This test checks the DEC chip initialization sequence for proper operation while using interrupts and reading the initialization blocks and rings structures used for Ethernet communications.

Response/Messages

After the command has been issued, the following line is printed:

```
DEC CINIT: Chip Initialization:.........Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
DEC CINIT: Chip Initialization:.........Running ---> PASSED
```

If any part of the test fails, then the display appears as follows:

```
DEC CINIT: Chip Initialization:.........Running ---> FAILED

DEC/CINIT Test Failure Data:
(error message)
```

Refer to the section *DEC Error Messages* for a list of the error messages and their meaning.

CLOAD - Continuous Load

Command Input

```
PPCx-Diag>DEC CLOAD
```

Description

This test verifies that a continuous load can be placed on the controller by transmitting/receiving a sequence of packets totalling at least 1 megabyte of throughput, comparing the input data with the output data.

Response/Messages

After the command has been issued, the following line is printed:

```
DEC CLOAD: Continuous Load:.............Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
DEC CLOAD: Continuous Load:.............Running ---> PASSED
```

If any part of the test fails, then the display appears as follows:

```
DEC CLOAD: Continuous Load:.............Running ---> FAILED

DEC/CLOAD Test Failure Data:
(error message)
```

Refer to the section *DEC Error Messages* for a list of the error messages and their meaning.

CNCTR - Connector

Command Input


```
PPCx-Diag>dec cnctr
```

Description

This test verifies that the data path through the external (AUI or TP (twisted pair)) connection is functional, by transmitting and receiving packets and comparing the data. This test requires the presence of an external loopback “plug” for AUI or TP.

Note It is recommended that the board under test not be connected to a live network while this test is running. The suggested “loopback” setup for AUI is an AUI-to-thinnet transceiver attached to a BNC tee with terminators on each arm of the tee. For TP setup, an external shunt needs to be put in the TP socket (it cannot be connected to a live network).

Response/Messages

After the command has been issued, the following line is printed:

```
DEC CNCTR: Connector:.................Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
DEC CNCTR: Connector:..............Running ---> PASSED
```

If any part of the test fails, then the display appears as follows:

```
DEC CNCTR: Connector:...................Running ---> FAILED
DEC/CNCTR Test Failure Data:
(error message)
```

Refer to the section *DEC Error Messages* for a list of the error messages and their meaning.

You can use the **CF** command to select the port to be tested (whether AUI or TP). The following example uses the **CF** command to select port 1 (the TP port), skipping port 0 (the AUI port).

Example:

```
PPCx-Diag>CF DEC
DEC Configuration Data:
Port Select =00000000 ? 1
```

ERREN - PERREN/SERREN Bit Toggle

Command Input

```
PPCx-Diag>DEC ERREN
```

Description

This test toggles the PERREN and SERREN (Address and Data Parity Error status) bits in the command register found in the PCI header address space to verify that this register functions properly. Each bit is toggled (written) and then read to verify that they are indeed toggled.

Response/Messages

After the command has been issued, the following line is printed:

```
DEC ERREN:PERREN and SERREN bit toggle:...Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
DEC ERREN:PERREN and SERREN bit toggle:...Running ---> PASSED
```

If any part of the test fails, then the display appears as follows:

```
DEC ERREN:PERREN and SERREN bit toggle:...Running ---> FAILED

DEC/ERREN Test Failure Data:
(error message)
```

Refer to the section *DEC Error Messages* for a list of the error messages and their meaning.

ILR - Interrupt Line Register Access

Command Input

```
PPCx-Diag>DEC ILR
```

Description

This test sends all possible byte patterns (0x00 - 0xFF) to the Interrupt Line register in the PCI register space. It verifies that the register can be read and written for all possible bit combinations. It checks that the byte read is the same as the byte previously written to verify that the register holds data correctly.

Response/Messages

After the command has been issued, the following line is printed:

```
DEC ILR:Interrupt Line Register Access:..Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
DEC ILR:Interrupt Line Register Access:. Running ---> PASSED
```

If any part of the test fails, then the display appears as follows:

```
DEC ILR:Interrupt Line Register Access:..Running ---> FAILED

DEC/ILR Test Failure Data:
(error message)
```

Refer to the section *DEC Error Messages* for a list of the error messages and their meaning.

IOR - I/O Resource Register Access

Command Input

```
PPCx-Diag>dec ior
```

Description

This test reads all the I/O resource registers (pointed to by the PCI Base Address register) and all the indexed registers read indirectly through the RAP index register, and CSR/BCR data registers. This test verifies that the registers can be accessed and that the data paths to the device are functioning.

Response/Messages

After the command has been issued, the following line is printed:

```
DEC IOR: I/O Resource Register Access:....Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
DEC IOR: I/O Resource Register Access:....Running --->PASSED
```

If any part of the test fails, then the display appears as follows:

```
DEC IOR: I/O Resource Register Access:....Running ---> FAILED

DEC/IOR Test Failure Data:
(error message)
```

Refer to the section *DEC Error Messages* for a list of the error messages and their meaning.

REGA - PCI Header Register Access

Command Input

```
PPCx-Diag>DEC REGA
```

Description

This test performs a read test on the Vendor ID and the Device ID registers in the DEC PCI header space and verifies that they contain the correct values. This test verifies that the registers can be accessed and that the data paths to the device are functioning.

Response/Messages

After the command has been issued, the following line is printed:

```
DEC   REGA: PCI Register Access.......... Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
DEC   REGA: PCI Register Access........Running --->PASSED
```

If any part of the test fails, then the display appears as follows:

```
DEC   REGA: PCI Register Access........Running ---> FAILED

DEC/REGA Test Failure Data:
(error message)
```

Refer to the section *DEC Error Messages* for a list of the error messages and their meaning.

SPACK - Single Packet Send/Receive

Command Input

```
PPCx-Diag>DEC SPACK
```

Description

This test verifies that the DEC Ethernet Controller can successfully send and receive an Ethernet packet, using interrupts in internal loopback mode.

Response/Messages

After the command has been issued, the following line is printed:

```
DEC   SPACK: Single Packet Xmit/Recv:..... Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
DEC   SPACK: Single Packet Xmit/Recv:..Running --->PASSED
```

If any part of the test fails, then the display appears as follows:

```
DEC   SPACK: Single Packet Xmit/Recv:..Running --->FAILED

DEC/SPACK Test Failure Data:
(error message)
```

Refer to the section *DEC Error Messages* for a list of the error messages and their meaning.

XREGA - Extended PCI Register Access

Command Input

```
PPCx-Diag>DEC XREGA
```

Description

This test performs a read test on all of the registers in the DEC PCI header space and verifies that they contain the correct values. This test verifies that the registers can be accessed and that the data paths to the device are functioning.

Response/Messages

After the command has been issued, the following line is printed:

```
DEC   XREGA:Extended PCI register Access:.Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
DEC   XREGA:Extended PCI register Access..Running ---> PASSED
```

If any part of the test fails, then the display appears as follows:

```
DEC   XREGA:Extended PCI register Access:.Running ---> FAILED

DEC/XREGA Test Failure Data:
(error message)
```

Refer to the section *DEC Error Messages* for a list of the error messages and their meaning.

DEC Error Messages

The **DEC** test group error messages generally take the following form:

```
DEC CLOAD: Continuous Load:.........Running ---> FAILED

DEC/CLOAD Test Failure Data:

Ethernet packet data mismatch:
Iter: nnnn Element: nnn Value sent: xxxx Value returned: xxxx
```

The first line of the test failure data identifies what type of failure occurred. The following line provides additional information about the failure.

Table 3-4. DEC Error Messages

Error Message	Symptom or Cause
`Initialization Error: Init.Block Address mismatch`	Init. Block address given to controller was not properly stored after initialization.
`Initialization Error: Transmit Ring Size mismatch`	Controller did not properly detect Transmit Descriptor Ring size after initialization.
`Initialization Error: Receive Ring Size mismatch`	Controller did not properly detect Receive Descriptor Ring size after initialization.
`Initialization Error: Logical Ethernet Address Filter, byte N mismatch`	Controller not properly storing *N*th byte of the Logical Ethernet filter address after initialization.
`Initialization Error: Physical Ethernet Address, byte N mismatch`	Controller not properly storing *N*th byte of the Physical Ethernet Address after initialization.
`Initialization Error: Mode Register mismatch`	Controller not properly storing the operating mode register after initialization.
`Initialization Error: Receive Descriptor Ring address mismatch`	Controller not properly storing the address of the Receive Descriptor ring after initialization.

Table 3-4. DEC Error Messages (Continued)

Error Message	Symptom or Cause
`Initialization Error: Transmit Descriptor Ring address mismatch`	Controller not properly storing the address of the Transmit Descriptor ring after initialization.
`Not enough diagnostics memory to accommodate DEC buffers.`	There was not enough diagnostics memory space available for use by the Initialization block, Descriptor Rings, and buffers.
`PCI` *`XXX`* `register contains invalid data. Detected Value:` *`NNN`* `Should Be:` *`NNN`*	The PCI Header Register, as listed, contains a bad value, other than a fixed, predetermined constant. May indicate a bad device, or faulty interface to it.
`Interrupt Line register mismatch error Value sent:` *`NNN`* `Value returned:` *`NNN`*	The value read is not the same as what was written, indicating that there is a problem storing data in the PCI Header register space.
`Unable to set(reset) the PERREN(SERREN) bit in the PCI command register.`	Inability to toggle bits in the PCI command register, which may indicate faulty interface to the PCI header registers.
`Unsolicited Exception: Exception Time IP` *`NNN`* `Vector` *`NNN`*	An interrupt occurred where it was not supposed to, usually because of a bus error, indicating a basic system problem interfacing to the controller.
`Transmit of Ethernet Packet Failed: Lost Carrier (LCAR)`	Carrier Signal got lost during a packet transmit, in AUI or TP (twisted pair) mode.

Table 3-4. DEC Error Messages (Continued)

Error Message	Symptom or Cause
`Transmit of Ethernet Packet Failed: Late Collision (LCOL)`	A Collision occurred after the slot time of the channel had elapsed.
`Transmit of Ethernet Packet Failed: Too many Retries (RTRY)`	Transmit failed too many times, indicating a transmission problem over the network.
`Transmit of Ethernet Packet Failed: Buffer Error (BUFF)`	ENP flag not found at the end of a transmitted frame, and the next packet is not owned by controller.
`Transmit of Ethernet Packet Failed: Underflow error (UFLO)`	Transmitter truncated a message, due to data unavailability.
`Transmit of Ethernet Packet Failed: Excessive Deferral (EXDEF)`	IEEE/ANSI 802.3 defined excessive deferral of transmitted packet.
`Receive of Ethernet Packet Failed: Invalid Checksum (CRC)`	Packet Checksum vs. Data is invalid, indicating bad transmission of packet.
`Receive of Ethernet Packet Failed: Framing Error (FRAM)`	Some bits were missing on an incoming byte in a frame.
`Receive of Ethernet Packet Failed: Overflow condition (OFLO)`	FIFO unable to store incoming packet, usually because packet is too large to fit in buffer.
`Receive of Ethernet Packet Failed: Buffer error (BUFF)`	Buffer is not available to receive incoming frame, usually because ownership has not been given back to controller.

Table 3-4. DEC Error Messages (Continued)

Error Message	Symptom or Cause
`Time out waiting for Interrupt`	An expected interrupt, either from Initialization, Transmit or Receive was never received, indicating some other problem has occurred.
`Memory Error interrupt encountered (MERR)`	Interrupt that occurs when the controller cannot access the memory bus.
`Time Out interrupt encountered (BABL)`	Interrupt indicating that transmitter has taken too long to transmit a frame.
`Collision Error interrupt encountered (CERR)`	Interrupt indicating that the AUI port collision inputs failed to activate in a timely manner after a frame was transmitted.
`Missed Frame interrupt encountered (MISS)`	Interrupt indicating that the receiver missed an incoming frame because there was no place to put it (no buffers owned by controller).
`Jabber Error interrupt encountered (JAB)`	Interrupt indicating that the twisted pair transmission limit has been exceeded.
`Collision Counter Overflow interrupt encountered (RCVCCO)`	Too many collisions have occurred.

Table 3-4. DEC Error Messages (Continued)

Error Message	Symptom or Cause
`Receive interrupt occurred, but no data available.`	Controller interrupted indicating that data has been received, but the incoming byte count does not reflect this.
`Received packet is the wrong size.`	Size of packet is not the same size as it was when it was sent.
`Requested packet size of %d illegal Must be in range` *`NN`* `to` *`NNN`*	Size of packet to send is out of boundaries, as defined by standard Ethernet packet sizings.
`Ethernet packet data mismatch Iter:` *`NNN`* `Element:` *`NN`* `Value sent:` *`XXXX`* `Value returned:` *`XXXX`*	Data in packet received does not equal data in the packet that was sent.

INET - Intel Ethernet Controller Tests

These sections describe the individual Intel 82559/ER Ethernet Controller tests.

Entering INET without parameters causes all INET tests to run in the order shown in the table below, except as noted.

To run an individual test, add that test name to the INET command.

The individual tests are described in alphabetical order on the following pages.

Table 3-5. INET Test Group

Name	Description
BINT	Basic Interrupt Test
EEPT	EEPROM Test
INST	Internal Self Test
MDIT	MDI Interface Test
MPACK	Multiple Packet Interrupt Loopback Test
PERT	Parity Error Response Test
SERT	SERR# Enable Response Test
SPACK	Single Packet Interrupt Loopback Test
Executed only when specified:	

Note An external hardware connection to the Ethernet port is not required for any INET test.

BINT - Basic Interrupt Test

Command Input

```
PPCx-Diag>inet bint
```

Description

This test verifies that the Interrupt Line Register of the PCI Header of the device can be programmed to any possible value.

Response/Messages

After the command has been issued, the following line is printed:

```
INET BINT: Basic Interrupt Testing...Running-->
```

If all parts of the test are completed correctly, the test passes:

```
INET BINT: Basic Interrupt Testing...Running-->PASSED
```

If any part of the test fails, the display appears as follows:

```
INET BINT: Basic Interrupt Testing...Running-->FAILED

INET/BINT Test Failure Data:
(error message)
```

Refer to the section *INET Error Messages* for a list of the error messages and their meaning.

EEPT - EEPROM Test

Command Input

```
PPCx-Diag>inet eept
```

Description

This test verifies that the EEPROM can be read and that the checksum is valid.

Response/Messages

After the command has been issued, the following line is printed:

```
INET EEPT: EEPROM Test.................Running -->
```

If all parts of the test are completed correctly, the test passes:

```
INET EEPT: EEPROM Test................Running-->PASSED
```

If any part of the test fails, the display appears as follows:

```
INET EEPT: EEPROM Test.................Running-->FAILED

INET/EEPT Test Failure Data:
(error message)
```

Refer to the section *INET Error Messages* for a list of the error messages and their meaning.

INST - Internal Self Test

Command Input

```
PPCx-Diag>inet inst
```

Description

This test configures the device to perform an internal self test and determines whether the device itself detected an error.

Response/Messages

After the command has been issued, the following line is printed:

```
INET INST: Internal Self Test ........Running--->
```

If all parts of the test are completed correctly, the test passes:

```
INET INST: Internal Self Test ....Running-->PASSED
```

If any part of the test fails, the display appears as follows:

```
INET INST: Internal Self Test.....Running-->FAILED

INET/INST Test Failure Data:
(error message)
```

Refer to the section *INET Error Messages* for a list of the error messages and their meaning.

MDIT - MDI Interface Test

Command Input

```
PPCx-Diag>inet mdit
```

Description

This test verifies that the bits in the MDI Control Register can be set and reset.

Response/Messages

After the command has been issued, the following line is printed:

```
INET MDIT: MDI Interface Test.........Running-->
```

If all parts of the test are completed correctly, the test passes:

```
INET MDIT: MDI Interface Test........Running-->PASSED
```

If any part of the test fails, the display appears as follows:

```
INET MDIT: MDI Interface Test........Running-->FAILED

INET/MDIT Test Failure Data:
(error message)
```

Refer to the section *INET Error Messages* for a list of the error messages and their meaning.

MPACK - Multiple Packet Interrupt Loopback Test

Command Input

```
PPCx-Diag>inet mpack
```

Description

This test verifies that the Intel Ethernet Controller can successfully send and receive multiple Ethernet packets, using interrupts in the internal loopback mode.

Response/Messages

After the command is issued, the following line is printed:

```
INET MPACK: Multi Pkt Interrupt LB Testing. Running->
```

If all parts of the test are completed correctly, the test passes:

```
INET MPACK: Multi Pkt Interrupt LB Testing. Running->PASSED
```

If any part of the test fails, the display appears as follows:

```
INET MPACK: Multi Pkt Interrupt LB Testing. Running->FAILED

INET/MPACK Test Failure Data:
(error message)
```

Refer to the section *INET Error Messages* for a list of the error messages and their meaning.

PERT - Parity Error Response Test

Command Input

```
PPCx-Diag>inet pert
```

Description

This test toggles the PER (Parity Error Response) bit in the command register found in the PCI header address space to verify that this register functions properly. The bit is toggled (written) and then read to verify that it is indeed toggled.

Response/Messages

After the command has been issued, the following line is printed:

```
INET PERT: Parity Error Response Test....Running --->
```

If all parts of the test are completed correctly, the test passes

```
INET PERT: Parity Error Response Test..Running--> PASSED
```

If any part of the test fails, the display appears as follows:

```
INET PERT: Parity Error Response Test..Running--> FAILED

INET/PERT Test Failure Data:
(error message)
```

Refer to the section titled *INET Error Messages* for a list of the error messages and their meaning.

SERT - SERR# Enable Response Test

Command Input

```
PPCx-Diag>inet sert
```

Description

This test toggles the SERR (System Enable Response) bit in the command register found in the PCI header address space to verify that this register functions properly. The bit is toggled (written) and then read to verify that it is indeed toggled.

Response/Messages

After the command has been issued, the following line is printed:

```
INET SERT: SERR# Enable Response Test...Running--->
```

If all parts of the test are completed correctly, the test passes:

```
INET SERT: SERR# Enable Response Test..Running-->PASSED
```

If any part of the test fails, the display appears as follows:

```
INET SERT: SERR# Enable Response Test..Running-->FAILED

INET/SERT Test Failure Data:
(error message)
```

Refer to the section *INET Error Messages* for a list of the error messages and their meaning.

SPACK - Single Packet Interrupt Loopback Test

Command Input

```
PPCx-Diag>inet spack
```

Description

This test verifies that the Intel Ethernet Controller can successfully send and receive Ethernet packets, using interrupts in internal loopback mode.

Response/Messages

After the command is issued, the following line is printed:

```
INET SPACK: Single Pkt Interrupt LB Testing. Running-->
```

If all parts of the test are completed correctly, the test passes:

```
INET SPACK: Single Pkt Interrupt LB Testing. Running->PASSED
```

If any part of the test fails, the display appears as follows:

```
INET SPACK: Single Pkt Interrupt LB Testing. Running->FAILED

INET/SPACK Test Failure Data:
(error message)
```

Refer to the section *INET Error Messages* for a list of the error messages and their meaning.

INET Error Messages

The INET test group error messages generally take the following form:

```
INET SPACK: Single Pkt Interrupt LB Testing. Running-->FAILED
INET/SPACK Test Failure Data:
RX data mismatch
Iteration =     NN
Element =     NN
Value sent = 0xXX
Value received = 0xXX
```

The first line of the test failure data identifies what type of failure occurred. The following line provides additional information about the failure.

Table 3-6. INET Error Messages

Error Message	Symptom or Cause
EEPROM read error	Acknowledgement for an EEPROM address is not being returned during a read access.
EEPROM checksum error	The checksum calculated from the EEPROM data does not match the checksum stored in the data itself.
Unable to allocate PORT test memory	Software is unable to allocate the memory needed for the PORT self test results.
Port self-test failed	The device reports a failure after performing a PORT self test.
CU command execution error	The CBL status bits (C and OK) indicate that a previous action command has not completed successfully.
Illegal CU action command requested	An illegal or unknown CU action command is being requested.
Requested TX exceeds devices transmit buffers	The desired transmit data size is larger than the devices allocated TX buffers can support.
RX TCO packet processing	The receiver is processing a TCO packet.
RX Individual Address mismatch	The destination address of the received frame does not match the individual address.
RX no Individual Address match	The destination address of the received frame does not match the individual address, the multicast address or the broadcast address.
RX invalid header type size	The received frame is a TYPE frame (Ethernet header Type/Length is 0 or greater than 1500).
RX indeterminant error	Unknown receive error is encountered.
Unable to allocate memory for diagnostics	Software is unable to allocate memory for the diagnostic tests.
PCI Config Header Parity Error Response error	Inability to toggle PER bit in the PCI command register, which may indicate faulty interface to the PCI header registers.
PCI Config Header SERR Bit error	Inability to toggle SERR bit in the PCI command register, which may indicate faulty interface to the PCI header registers.

Table 3-6. INET Error Messages (Continued)

Error Message	Symptom or Cause
PCI Config Header Interrupt Line error. Written Value = 0xXX Read Value = 0xXX	Value written to the PCI header Int Line register does not match the value read back.
MDI control register error	Value written to the MDI control register does not match the value read back.
CU unexpectedly active	Command Unit expected to be idle or suspended but is actually active.
Device self diagnostic reports failure	Self diagnose command reports failure.
RX header destination address mismatch	Received loopback packet header destination address does not match the one transmitted.
RX header source address mismatch	Received loopback packet header source address does not match the one transmitted.
RX header type mismatch	Received loopback packet header TYPE field does not match the one transmitted.
RX data mismatch Iteration = NN Element = NN Value sent = 0xXX Value received = 0xXX	Received loopback packet data portion does not match the one transmitted.
No interrupts detected	No interrupts were detected by the MPU and handler was not invoked.
Unexpected number of received packets. Expected pckts = NN Received pckts = NN	Number of correctly received loopback packets does not match the number that was requested for.
Undefined program error	Software detected an undefined error.

EIDE - EIDE Tests

This section describes the EIDE tests. These tests consist of REG, ACC, and RW.

Entering **EIDE** without parameters causes all **EIDE** tests to execute in the order shown in the table below.

Table 3-7. EIDE Test Group.

Name	Description
REG	Register Access Test.
ACC	Device Address Test.
RW	Read/Write Device (Destructive Device Access)

To run an individual test, append the test name to the **EIDE** command. Note that the EIDE test needs to be manually configured using the "cf" command prior to execution.

General Test Description:

The EIDE tests require the attachment of an IDE/EIDE device to the interface since all tests access registers in the physical device. The device may be either a hard drive, an ATA-compatible compact flash memory, or an ATAPI CD-ROM. The use of ATA hard drives is strongly recommended since results are generally more predictable and test coverage is more thorough.

ATAPI CD-ROM's may be tested, but, due to the emerging nature of the CD interface, testing is less complete. Also, the newer technology of writeable CD-ROMs is not covered and causes the RW test to be bypassed when attempted on a CD-ROM.

The tests listed in Table 3-7 are arranged in order of severity to the drive's configuration and/or data. The REG test is the least intrusive while the RW test is not only intrusive, but will corrupt data as well.

Data is written to the disk for the number of blocks specified by the configuration parameters. Since these blocks are overwritten with test data, use a disk with expendable or no data.

Prior to the execution of any of the EIDE tests, a validity check is performed on the CLUN/DLUN pair specified by the EIDE “cf” parameters. If either one of the values provided is invalid, the test aborts and an error message is displayed.

General Configuration Description:

The EIDE diagnostics require some manual setup using the “cf” command prior to execution. The default values are shown below:

Before running these tests, make sure that the CLUN/DLUN fields have valid data as illustrated in Step 1 below. Additional parameters may be changed as shown in Step 2 through Step 6.

```
PPC1-Diag>cf eide
EIDE Configuration Data:
EIDE CLUN =00 ?
EIDE DLUN [00 - 70] =00 ?
Test Sector Number (start) =00000000 ?
Number of Sectors To Test (Sector Size: HD = 256, CD-ROM =2048)
=00000001 ?
Fill Data =0000 ?
Test Data Increment/Decrement Step =0001 ?
Enable Destructive Tests (R/W, DMA) [Y/N] =N ?
PPC1-Diag>
```

1. EIDE CLUN and DLUN Fields.

   The “EIDE CLUN and DLUN” fields are the most important fields in the “cf” EIDE setup since they specify which drive is tested. The best way to determine CLUN and DLUN field values for use in the “cf” setup is to run the “ioi” command.

```
PPC1-Bug>ioi
I/O Inquiry Status:
CLUN  DLUN  CNTRL-TYPE  DADDR  DTYPE  RM  Inquiry-Data
  1    0  PC8477    0     $00   Y  <None>
 14    0  PBC-EIDEF1  0     $00   N  WDC     AC21200H       1E55
PPC1-Bug>
```

2. Test Sector Number Field.

   The “Test Sector Number” field specifies a sector number to be used as a starting location for several of the EIDE tests.

3. Number of Sectors to Test.

   The “Number of Sectors to Test” field specifies the number of device sectors to be tested. For example, if two (2) sectors are specified and the test sector number field is specified as zero (0), then sectors 0 and 1 are tested.

4. Fill Data.

   The “Fill Data” field is used as a seed data value for tests that write to the disk. Depending upon the “Test Data Increment/Decrement Step” field, “Fill Data” may remain constant, be incremented, or be decremented after each 16-bit word write operation.

5. Test Data Increment/Decrement Step.

   The “Test Data Increment/Decrement Step” parameter increments or decrements the data pattern using a user-assigned value. This value is added to the current data pattern after each 16-bit write operation. The initial data pattern is defined by the “Fill Data” parameter and, if set to zero, allows writing a fixed data pattern.

6. Enable Destructive Tests [Y/N]?

   If “N” is specified, destructive data tests are disabled. If “Y” is specified, destructive data tests are enabled. It is important to use a “scratch” EIDE device since destructive read/write tests are used as part of the EIDE or “EIDE R/W” test commands.

ACC - Device Access

Command Input

```
PPCx-Diag>eide acc
```

Description

The ACC test performs five non-data EIDE commands: NOP, EXECUTE DEVICE DIAGNOSTICS, RESET, IDENTIFY DEVICE, and SEEK. The test is non-destructive since data is not read from or written to the disk itself. Data integrity of the disk is not altered.

The BSY bit in the status register is first checked to verify that the device registers are valid (provided a device is attached). If a time-out occurs while waiting for a “ready” condition, the test aborts and an error is reported. Otherwise, a short walking bit test is performed followed by execution of the following five commands:

1. NOP.

   “NOP” forces an abort error condition, setting the ERR bit in the status register and the ABORT bit in the error register. The test ensures that this condition occurs.

2. EXECUTE DEVICE DIAGNOSTICS.

   “EXECUTE DEVICE DIAGNOSTICS” forces pre-determined values into cylinder high, cylinder low, error, sector count, sector number, and device/head registers. These values are compared to expected values. Allowances are made for differences between ATA drives and ATAPI CD-ROM dirves.

3. RESET

   “RESET” performs two functions: it tests the reset bit of the Device Control register and establishes known device signatures. Once the device signature is in place, the correct interface protocol (ATA or ATAPI) may be invoked.

4. IDENTIFY DEVICE

   "IDENTIFY DEVICE" provides further testing of the EIDE interface in that it causes the first transfer of data across the channel, although in one direction only (data in). Several of the identify words provide configuration information to allow the test driver to properly construct a command packet.

5. SEEK.

   "SEEK" is issued three times. It first seeks block 0, then the last block, and then block 0 again.

Response/Messages

After the command has been issued, this message is displayed:

```
EIDE ACC: EIDE Device Access Tests... Running --->
```

If all parts of the test are completed correctly, the test has been passed and this message is displayed:

```
EIDE ACC: EIDE Device Access Tests... Running ---> PASSED
```

If any part of the test fails, then this message is displayed:

```
EIDE ACC: EIDE Device Access Tests... Running ---> FAILED

EIDE/ACC Test Failure Data:
(ERROR MESSAGE)
```

(ERROR MESSAGE) may be one of the following:

Status Register Error.

```
EIDE Device Access Test, Status Register Error:
 Register Address = _________,  Error Bits = __,  Bit Test Mask = __
 Register Contents = __
```

Walking Bit High Error.

```
EIDE Device Access Test, Walking Bit High Error:
 Register Address = _________,  Error Bits = __,  Bit Test Mask = __
```

Walking Bit Low Error.

```
EIDE Device Access Test, Walking Bit Low Error:
 Register Address = _________,  Error Bits = __,  Bit Test Mask = __
```

NOP Command Test Error #1.

```
EIDE Device Access Test, NOP Command Test Error:
 Register Address = _________,  Error Bits = __,  Bit Test Mask = __
 Register Contents = __
```

NOP Command Test Error #2.

```
EIDE Device Access Test, NOP Command Test Error:
 Register Address = _________,  Error Bits = __,  Bit Test Mask = __
 Register Contents = __
 Register Address = _________,  Error Bits = __,  Bit Test Mask = __
 Register Contents = __
```

Execute Device Diagnostics Test Error.

```
EIDE Device Access Test, Execute Device Diagnostics Test Error:
 Register Address = _________,  Error Bits = __,  Bit Test Mask = __
 Register Contents = __
```

Device Reset Error.

```
EIDE Device Access Test, Device Reset Error:
 Register Address = _________,  Error Bits = __,  Bit Test Mask = __
 Register Contents = __
```

```
 Identify Device, Start Unit, Seek Tests Aborted: Can Not Identify
 Device Type
```

Identify Device Command Test Error

```
EIDE Device Access Test, Identify Device Command Test Error:
 (DEVICE ACCESS ERROR)
```

Seek Operation Error.

```
EIDE Device Access Test, Seek Operation Error:
 (DEVICE ACCESS ERROR)
```

Start Unit Command Test Error.

```
EIDE Device Access Test, Start Unit Command Test Error:
 (DEVICE ACCESS ERROR)
```

Initialize Device Parameters Error.

```
EIDE Device Access Test, Initialize Device Parameters Error:
 (DEVICE ACCESS ERROR)
```

`(DEVICE ACCESS ERROR)` may be one of the following:

```
Register Address = ___________,  Error Bits = __,  Bit Test Mask = __
Register Contents = __

Register Address = ___________,  Error Bits = __,  Bit Test Mask = __
Register Contents = __
Additional Error: Register Address = _____, Register Contents = __

Illegal Data Request Entered
```

REG - Register Access

Command Input

```
PPCx-Diag>eide reg
```

Description

The REG test performs non-intrusive device access for initial address and accessibility checks. Bit patterns of data written to and read from several of the ATA Task File registers are compared with expected values. Failures indicate addressing errors or data line corruption of data bits 0 through 7 only (D0-D7).

The BSY bit in the status register is first checked to verify that the device registers are valid (provided a device is attached). If a time-out occurs while waiting for a “ready” condition, the failure is logged and the test continues.

The test walks both a '1' and a '0' through the modifiable Task File registers and performs a sanity check on the feature/error register pair as well as the control/alternate status register pair. Finally, the alternate status register is compared to the status register.

This test is run in its entirety regardless of failures. All failures are reported after the test is complete to aid analysis of failures.

Response/Messages

After the command has been issued, the following is displayed:

```
EIDE REG: EIDE Register Access Tests... Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
EIDE REG: EIDE Register Access Tests... Running ---> PASSED
```

If any part of the test fails, then the following is displayed:

```
EIDE REG: EIDE Register Access Tests... Running ---> FAILED

EIDE/REG Test Failure Data:
(ERROR MESSAGE)
```

(ERROR MESSAGE) may be one of the following:

Status Register Error.

```
EIDE Register Test, Status Register Error:
 Register Address = __________,  Error Bits = __,  Bit Test Mask = __
 Register Contents = __
```

Walking Bit High Error.

```
EIDE Register Test, Walking Bit High Error:
 Register Address = __________,  Error Bits = __,  Bit Test Mask = __
```

Walking Bit Low Error.

```
EIDE Register Test, Walking Bit Low Error:
 Register Address = __________,  Error Bits = __,  Bit Test Mask = __
```

Feature/Error Register Error.

```
EIDE Register Test, Feature/Error Register Error:
 Change in a Non-Changeable Bit Detected:
 Register Address = ___________, Error Bits = __,  Bit Test Mask = __
 Register Contents = __
```

Device Control/Alternate Status Error.

```
EIDE Register Test, Device Control/Alternate Status Error:
 Change in a Non-Changeable Bit Detected:
 Register Address = ___________, Error Bits = __,  Bit Test Mask = __
 Register Contents = __
```

Alternate Status Register Error.

```
EIDE Register Test, Alternate Status Register Error:
 Register Address = __________,  Error Bits = __,  Bit Test Mask = __
 Register Contents = %02X
```

RW - Read/Write Device

Command Input

```
PPC1-Diag>eide rw
```

Note **The test must first be enabled by setting the EIDE "cf" destructive test parameter to true.**

Description

The **RW** test performs a write-read-verify cycle that verifies the overall integrity of the IDE/EIDE interface. The starting block and number of test sectors are defined by the EIDE **"cf"** parameters.

The RW test first checks the BSY bit in the status register to ensure the device registers are valid (provided a device is attached). If a timeout occurs while waiting for the device to become ready, the test aborts and an error condition is reported. If no error is detected, the RW test performs a short walking bit test (sanity check), and issues an Identify Device Command to determine the device type prior to executing the remainder of the test. If the attached device is determined to be an ATAPI device, the test is bypassed.

Once the device type is determined, the RW test performs a read, a write, and another read. The first read tests the waters, so to speak, prior to attempting a write which could potentially destroy data on the disk. The write-read-verify cycle is then executed. If an error is detected, the test is aborted and an error condition reported. Otherwise, the test executes on all specified sectors.

The read-write-read-verify cycle is performed on a sector-by-sector basis. The starting sector and sector count are configurable through the "cf" parameters for EIDE. The test data value and increment size are specified by the "cf" parameters as well.

Response/Messages

After the command has been issued, the following is displayed:

```
EIDE RW: EIDE Read/Write Tests... Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
EIDE RW: EIDE Read/Write Tests... Running ---> PASSED
```

If any part of the test fails, the following is displayed:

```
EIDE RW: EIDE Read/Write Tests... Running ---> FAILED

EIDE/RW Test Failure Data:
(ERROR MESSAGE)
```

`(ERROR MESSAGE)` may be one of the following:

Status Register Error.

```
EIDE Read/Write Test, Status Register Error:
 Register Address = _________,  Error Bits = __,  Bit Test Mask = __
 Register Contents = __
```

Walking Bit High Error.

```
EIDE Read/Write Test, Walking Bit High Error:
 Register Address = _________,  Error Bits = __,  Bit Test Mask = __
```

Walking Bit Low Error.

```
EIDE Read/Write Test, Walking Bit Low Error:
 Register Address = _________,  Error Bits = __,  Bit Test Mask = __
```

Identify Device Error.

```
EIDE Read/Write Test, Identify Device Error:
 Register Address = _________,  Error Bits = __,  Bit Test Mask = __
 Register Contents = __
```

Probe Operation Error.

```
EIDE Read/Write Test, Probe Operation Error:
 (DEVICE ACCESS ERROR)
```

Initialize Device Parameters Error.

```
EIDE Read/Write Test, Initialize Device Parameters Error:
 (DEVICE ACCESS ERROR)
```

Read Operation Error.

```
EIDE Read/Write Test, Read Operation Error:
```

```
 Block # = _____:
 (DEVICE ACCESS ERROR)
```

Write Operation Error.

```
EIDE Read/Write Test, Write Operation Error:
 Block # = _____:
 (DEVICE ACCESS ERROR)
```

Data Verification Error.

```
EIDE Read/Write Test, Data Verification Error:
 Block # = _____:
 (DEVICE ACCESS ERROR)
```

Write Operation (Restore Data) Error.

```
EIDE Read/Write Test, Write Operation (Restore Data) Error:
 Block # = _____:
 (DEVICE ACCESS ERROR)
```

`(DEVICE ACCESS ERROR)` may be one of the following:

```
Register Address = __________,  Error Bits = __,  Bit Test Mask = __
Register Contents = __

Register Address = __________,  Error Bits = __,  Bit Test Mask = __
Register Contents = __
Additional Error: Register Address = _____, Register Contents = __

Illegal Data Request Entered
```

ISABRDGE - PCI/ISA Bridge Tests

This section describes the individual Isabrdge (PCI/ISA Bridge) tests.

Entering **ISABRDGE** without parameters causes all **ISABRDGE** tests to execute in the order shown in the following table.

To run an individual test, add that test name to the **ISABRDGE** command.

The individual tests are described in alphabetical order on the following pages.

Table 3-8. ISABRDGE Test Group

Name	Description
REG	Register
IRQ	Interrupt

IRQ - Interrupt

Command Input

```
PPCx-Diag>ISABRDGE IRQ
```

Description

This test verifies that the ISABRDGE can generate interrupts.

Response/Messages

After the command has been issued, the following line is printed:

```
ISABRDGE IRQ: Interrupt..................... Running --->
```

If all parts of the test are completed correctly, then the test passes.

```
ISABRDGE IRQ: Interrupt..................... Running ---> PASSED
```

If any failures occur, the following is displayed (more descriptive text then follows):

```
ISABRDGE IRQ: Interrupt..................... Running ---> FAILED
```

If the test fails because an interrupt request from the ISABRDGE is pending, after masking the ISABRDGE interrupt in the IEN register, the following is displayed:

```
ISABRDGE/IRQ Test Failure Data:
Unexpected ISABRDGE IRQ pending
Address =________, Expected =________, Actual =________
```

This test makes use of the ISABRDGE counters, to generate the test interrupt. If after running the counters to “terminal count”, an interrupt has not been requested by the ISABRDGE, the following message is displayed:

```
ISABRDGE/IRQ Test Failure Data:
ISABRDGE IRQ not pending in IST register
Address =________, Expected =________, Actual =________
```

REG - Register

Command Input:

```
PPC1-Diag>ISABRDGE REG
```

Description

This test verifies that the ISABRDGE registers can be written and read. Data patterns verify that every read/write bit can be modified.

Response/Messages

After the command has been issued, the following line is printed:

```
ISABRDGE REG: Register..................... Running --->
```

If all parts of the test are completed correctly, then the test passes.

```
ISABRDGE REG: Register..................... Running ---> PASSED
```

If any failures occur, the following is displayed (more descriptive text then follows):

```
ISABRDGE REG: Register..................... Running ---> FAILED
```

If the test fails because the pattern written does not match the data read back from the ISABRDGE register, the following is printed:

```
ISABRDGE/LNK Test Failure Data:
Register xxx Miscompare Error:Address =____,Expected =_,Actual =_
```

KBD8730x - Keyboard Controller Tests

These sections describe the individual PC8730x Keyboard Controller, Mouse, and Keyboard Device tests.

Entering **KBD8730x** without parameters causes all **KBD8730x** tests to run in the order shown in the table below, except as noted.

To run an individual test, add that test name to the **KBD8730x** command.

The individual tests are described in alphabetical order on the following pages.

Table 3-9. KBD8730x Test Group

Name	Description
KCCONF	Keyboard Controller Confidence
KBCONF	Keyboard Device Confidence/Extended
MSCONF	Mouse Device Confidence/Extended
Executed only when specified:	
KCEXT	Keyboard/Mouse Controller Extended Test
KBFAT	Keyboard Test
MSFAT	Mouse Test

There are no configuration parameters for these tests. The KBFAT and MSFAT tests assume that there is a keyboard and a mouse present, otherwise they will fail. The other tests need not have any keyboard or mouse connected in order to operate successfully.

KBCONF - Keyboard Device Confidence/Extended

Command Input

```
PPCx-Diag>KBD8730x KBCONF
```

Description

This test performs an interface test of the keyboard controller to ensure correct operation of the interface to the keyboard device.

Response/Messages

After the command has been issued, the following line is printed:

```
KBD8730x kbconf:Keyboard Device Confidence/Extended:Running ->
```

If all parts of the test are completed correctly, then the test passes:

```
KBD8730x kbconf:Keyboard Device Confidence/Extended:Running ->
PASSED
```

If any part of the test fails, then the display appears as follows:

```
KBD8730x kbconf:Keyboard Device Confidence/Extended:Running ->
FAILED

KBD8730x/kbconf Test Failure Data:
(error message)
```

Refer to the section *KBD8730x Error Messages* for a list of the error messages and their meaning.

KBFAT - Keyboard Test

Command Input

```
PPCx-Diag>kbd8730x kbfat
```

Description

This test performs all the tests found in the keyboard device confidence/extended (**kbconf**) tests, issues an echo test to the keyboard device, issues a reset command to the keyboard device, and reads the keyboard device ID from the keyboard to ensure that the keyboard is plugged in and functioning correctly. These tests can only function with a keyboard device present.

Response/Messages

After the command has been issued, the following line is printed:

```
KBD8730x KBFAT: Keyboard Test:.............. Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
KBD8730x KBFAT: Keyboard Test:.............. Running --->
PASSED
```

If any part of the test fails, then the display appears as follows:

```
KBD8730x KBFAT: Keyboard Test:.............. Running --->
FAILED

KBD8730x/KBFAT Test Failure Data:
(error message)
```

Refer to the section *KBD8730x Error Messages* for a list of the error messages and their meaning.

KCCONF - Keyboard Controller Confidence/Extended

Command Input

```
PPCx-Diag>KBD8730x KCCONF
```

Description

This test writes a command byte and reads it back from the PC8730x keyboard controller to place it in correct operation mode, and test that the registers can be accessed and that the data paths to the device are functioning. It then issues a keyboard controller self-command to invoke the internal diagnostics that are performed in the keyboard controller itself.

Response/Messages

After the command has been issued, the following line is printed:

```
KBD8730x KCCONF:Keyboard Controller Confidence:.Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
KBD8730x KCCONF:Keyboard Controller Confidence:.Running --->
PASSED
```

If any part of the test fails, then the display appears as follows:

```
KBD8730x KCCONF:Keyboard Controller Confidence:.Running --->
FAILED

KBD8730x/KCCONF Test Failure Data:
(error message)
```

Refer to the section *KBD8730x Error Messages* for a list of the error messages and their meaning.

KCEXT - Keyboard/Mouse Controller Extended Test

Command Input

```
PPC1-Diag>KBD8730x KCEXT
```

Description

This test performs all the functions in the keyboard controller confidence tests (**kcconf**), tests the keyboard controller RAM locations by writing all possible byte values (0x00-0xff) to all possible RAM locations, and tests the Password functionality of the controller.

Response/Messages

After the command has been issued, the following line is printed:

```
KBD8730x KCEXT:Keyboard Controller Extended/Test:.Running ->
```

If all parts of the test are completed correctly, then the test passes:

```
KBD8730x KCEXT:Keyboard Controller Extended/Test:.Running ->
PASSED
```

If any part of the test fails, then the display appears as follows:

```
KBD8730x KCEXT:Keyboard Controller Extended/Test:.Running ->
FAILED

KBD8730x/KCEXT Test Failure Data:
(error message)
```

Refer to the section *KBD8730x Error Messages* for a list of the error messages and their meaning.

MSCONF - Mouse Device Confidence/Extended

Command Input

```
PPCx-Diag>kbd8730x msconf
```

Description

This test performs an interface test of the keyboard controller to ensure correct operation of the interface to the mouse device.

Response/Messages

After the command has been issued, the following line is printed:

```
KBD8730x MSCONF:Mouse Device Confidence/Extended:.Running -->
```

If all parts of the test are completed correctly, then the test passes:

```
KBD8730x MSCONF:Mouse Device Confidence/Extended:.Running --> PASSED
```

If any part of the test fails, then the display appears as follows:

```
KBD8730x MSCONF:Mouse Device Confidence/Extended:.Running --> FAILED

KBD8730x/MSCONF Test Failure Data:
(error message)
```

Refer to the section *KBD8730x Error Messages* for a list of the error messages and their meaning.

MSFAT - Mouse Test

Command Input

```
PPC1-Diag>KBD8730x MSFAT
```

Description

This test performs all the tests found in the mouse device confidence/extended (**msconf**) tests, reads the Mouse Device Type byte from the mouse device, and reads the status bytes from the mouse device to ensure that the mouse is plugged in and functioning correctly. These tests can only function with a mouse device present.

Response/Messages

After the command has been issued, the following line is printed:

```
KBD8730x MSFAT: Mouse Test:.................. Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
KBD8730x MSFAT: Mouse Test:.................. Running ---> PASSED
```

If any part of the test fails, then the display appears as follows:

```
KBD8730x MSFAT: Mouse Test:.................. Running ---> FAILED

KBD8730x/MSFAT Test Failure Data:
(error message)
```

Refer to the section *KBD8730x Error Messages* for a list of the error messages and their meaning.

KBD8730x Error Messages

The KBD8730x test group error messages generally take the following form:

```
KBD8730x KBFAT: Keyboard Test:.............. Running ---> FAILED

KBD8730x/KBFAT Test Failure Data:
Failure during command: XX
Keyboard Controller timed out waiting for Output Buffer Full
```

The first line of the test failure data identifies what type of failure occurred. The following line provides additional information about the failure.

Table 3-10. KBD8730x Error Messages

Error Message	Symptom or Cause

`Failure during command: XX`
`(Writing byte: XX to controller port 60h)`
`Keyboard Controller timed out waiting for Input Buffer Empty`
	Keyboard controller never became ready to receive command or data byte. Possible problem with keyboard controller embedded firmware.

`Failure during Keyboard command: XX` `Time out: possible device not present`	Failure of keyboard controller or keyboard device to send back a byte as a result of a command given to the keyboard device. Indicates problem with keyboard controller embedded firmware or the keyboard device itself.
`Failure during Mouse command: XX` `Time out: possible device not present`	Failure of keyboard controller or mouse device to send back a byte as a result of a command given to the mouse device. Indicates problem with keyboard controller embedded firmware or the mouse device itself.

Table 3-10. KBD8730x Error Messages (Continued)

Error Message	Symptom or Cause
`Failure during command: XX` `Keyboard Controller timed out waiting for Output Buffer Full`	Failure of keyboard controller to send back a byte as a result of a command given to the keyboard controller itself. Indicates a possible problem with the keyboard controller embedded firmware or hardware.
`Controller Command mismatch error` `Value written: XX Value read: XX`	Command byte read from keyboard controller does not equal what was sent. Indicates possible problem with bus interface to keyboard controller, or its embedded firmware.
`Keyboard Controller Failed Self Test (0xAA)`	Keyboard controller self-test command returned result that indicates a failure. May indicate a problem with the embedded firmware.
`Controller RAM mismatch error` `Value written: XX Value read: XX`	The value read from one of the keyboard controller RAM locations does not equal to what was written, indicating a possible problem with the controller, or it's embedded firmware.
`Invalid result from Password Test command`	The password test command failed, returning an invalid result, indicating that there may be a problem with the embedded firmware.

Table 3-10. KBD8730x Error Messages (Continued)

Error Message	Symptom or Cause
`Password Test failed, password should exist, but doesn't`	A password that was given to the keyboard controller was not stored properly, indicating a possible problem with the embedded firmware.
`Password Test failed, password should not exist, but does`	There was a failure in clearing out the password from the keyboard controller, indicating a possible problem with the embedded firmware.
`Unsolicited Exception:` `Exception Time IP` *`NNNN`* `Vector` *`NNNN`*	An unexpected interrupt occurred, indicating a possible bus error, or faulty interface to the keyboard controller.
`Keyboard Interface test failed` `Clock(Data) line is stuck high(low).`	There is a problem with the interface to the keyboard device, or the keyboard device itself. One of the data or clock lines is not operating correctly.
`Keyboard Interface test failed` `Invalid test result from controller`	There was a complete failure of the interface test to the keyboard device. May be a problem with the embedded firmware itself.
`Keyboard Echo test failed:Invalid result code=` *`XX`*	The echo test to the keyboard failed, indicating that the keyboard may not be present or working properly.

Table 3-10. KBD8730x Error Messages (Continued)

Error Message	Symptom or Cause
`Keyboard Internal Diagnostic test failure: Check keyboard` `Invalid result code (%x) from Keyboard Internal Diagnostic test`	The keyboard device internal diagnostics test failed, indicating a problem with the keyboard device itself.
`Invalid ACK from Keyboard Read ID test.Getting` *`XX`*	Keyboard device failed to send an Acknowledge byte, indicating that it may be not present or working correctly.
`Keyboard Read ID failed: First(Second) byte,` *`XX`*`, should be` *`XX`*`.`	Keyboard sending the wrong ID byte(s) back, indicating wrong device type being used, or a problem with the device.
`Mouse Interface test failed` `Clock(Data) line is stuck high(low).`	There is a problem with the interface to the mouse device, or the mouse device itself. One of the data or clock lines is not operating correctly.
`Mouse Interface test failed` `Invalid test result from controller`	Indicates a complete failure of the interface test to the mouse device. May be a problem with the embedded firmware itself
`Mouse Read ID failed, returning` *`XX`*`, should be` *`XX`*`.`	Mouse is sending the wrong ID byte(s) back, indicating wrong device type being used, or a problem with the device.

L2CACHE - Level 2 Cache Tests

This section describes the individual Level 2 (L2) Cache tests.

Entering **L2CACHE** without parameters causes all **L2CACHE** tests to run in the order shown in the table below, except as noted.

To run an individual test, add that test name to the **L2CACHE** command.

The individual tests are described in alphabetical order on the following pages.

Table 3-11. L2CACHE Test Group

Name	Description
WBFL	Write Back w/Flush
WBINV	Write Back w/Invalidate
WRTHRU	WriteThru
DISUPD	Disable Updating
ENUPD	Enable Updating
PATTERN	WriteThru Pattern
Executed only when specified:	
SIZE	Verify Cache Size

DISUPD - Disable Updating

Command Input

```
PPC1-Diag>l2cache disupd
```

Description

This test performs a write/read test on the L2 Cache. The main objective of this test is to exercise the L2 Cache with Cache Updating disabled. The test flow is as follows:

Turn on the cache with updating and WriteBack. Write an incrementing pattern to cache original region. Verify the incrementing pattern. Turn off cache updating. Write a decrementing pattern to displacing memory region. Turn off the cache. Write decrementing pattern to original memory region. Verify the decrementing pattern. Turn on the cache with WriteBack. Verify the decrementing pattern in the cache.

Response/Messages

After the command has been issued, the following line is printed:

```
L2CACHE DISUPD: L2-Cache Disable Updating... Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
L2CACHE DISUPD: L2-Cache Disable Updating... Running ---> PASSED
```

If any part of the test fails, then the display appears as follows:

```
L2CACHE DISUPD: L2-Cache Disable Updating... Running ---> FAILED

L2CACHE/DISUPD Test Failure Data:
(error message)
```

Refer to the section *L2CACHE Error Messages* for a list of the error messages and their meaning.

ENUPD - Enable Updating

Command Input

```
PPC1-Diag>l2cache enupd
```

Description

This test performs a write/read test on the L2 Cache. The main objective of this test is to exercise the L2 Cache with Cache Updating enabled. The test flow is as follows:

Turn on the cache with WriteBack. Write an incrementing pattern to cache original region. Verify the incrementing pattern. Turn off cache. Write a decrementing pattern to original memory region. Turn on the cache with WriteBack and enable updating. Write decrementing pattern to displacing memory region. Verify the incrementing pattern from the original region.

Response/Messages

After the command has been issued, the following line is printed:

```
L2CACHE ENUPD: L2-Cache Enable Updating... Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
L2CACHE ENUPD: L2-Cache Enable Updating... Running ---> PASSED
```

If any part of the test fails, then the display appears as follows:

```
L2CACHE ENUPD: L2-Cache Enable Updating... Running ---> FAILED

L2CACHE/ENUPD Test Failure Data:
(error message)
```

Refer to the section *L2CACHE Error Messages* for a list of the error messages and their meaning.

PATTERN - WriteThru Pattern

Command Input

```
PPC1-Diag>l2cache pattern
```

Description

This test performs a write/read test on the L2 Cache. The main objective of this test is to exercise the L2 Cache WriteThru control, using multiple bit patterns. The test flow is as follows:

Turn on the cache with WriteThru. Write an incrementing pattern to memory and the cache. Verify pattern is in the cache. Turn off the cache. Verify the pattern is outside of cache.

Response/Messages

After the command has been issued, the following line is printed:

```
L2CACHE PATTERN: L2-Cache WriteThru Pattern... Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
L2CACHE PATTERN: L2-Cache WriteThru Pattern... Running ---> PASSED
```

If any part of the test fails, then the display appears as follows:

```
L2CACHE PATTERN: L2-Cache WriteThru Pattern... Running ---> FAILED

L2CACHE/PATTERN Test Failure Data:
(error message)
```

Refer to the section *L2CACHE Error Messages* for a list of the error messages and their meaning.

SIZE - Verify Cache Size

Command Input

```
PPCx-Diag>l2cache size
```

Description

The main objective of this test is to verify the size of the L2 Cache, as indicated by the CPU Type Register. An error is reported if the size is incorrect.

Response/Messages

After the command has been issued, the following line is printed:

```
SIZE: Verify Cache Size..............  Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
SIZE: Verify Cache Size..............  Running ---> PASSED
```

If any part of the test fails, then the display appears as follows:

```
SIZE: Verify Cache Size..............  Running ---> FAILED

L2CACHE/SIZE Test Failure Data:
(error message)
```

Refer to the section *L2CACHE Error Messages* for a list of the error messages and their meaning.

WBFL - Write Back w/Flush

Command Input

```
PPCx-Diag>l2cache wbfl
```

Description

This test performs a write/read test on the L2 Cache. This test verifies that the device can be both accessed and that the L2 Cache Flush control works. The test flow is as follows:

Turn off the cache. Write an incrementing pattern to memory and verify that the pattern is in memory. Turn on the cache with WriteBack. Write a decrementing pattern to the cache. Turn off the cache. Verify that the incrementing pattern is still in memory. Turn on the cache with WriteBack. Flush the cache, which should flush the cache contents to memory. Turn off the cache. Verify that the decrementing pattern is in memory.

Response/Messages

After the command has been issued, the following line is printed:

```
L2CACHE WBFL: L2-Cache WriteBack w/ Flush... Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
L2CACHE WBFL: L2-Cache WriteBack w/ Flush... Running ---> PASSED
```

If any part of the test fails, then the display appears as follows:

```
L2CACHE WBFL: L2-Cache WriteBack w/ Flush... Running ---> FAILED

L2CACHE/WBFL Test Failure Data:
(error message)
```

Refer to the section *L2CACHE Error Messages* for a list of the error messages and their meaning.

WBINV - Write Back w/Invalidate

Command Input

```
PPCx-Diag>l2cache wbinv
```

Description

This test performs a write/read test on the L2 Cache. This test verifies that the device can be both accessed and that the L2 Cache Invalidate control is working. The test flow is as follows:

Turn off the cache. Write an incrementing pattern to memory. Turn on the cache with WriteBack. Write a decrementing pattern to cache while invalidating the cache. Flush the cache, which should have no effect. Verify that the incrementing pattern is still in memory.

Response/Messages

After the command has been issued, the following line is printed:

```
L2CACHE WBINV: L2-Cache WriteBack w/Invalidate... Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
L2CACHE WBINV: L2-Cache WriteBack w/Invalidate... Running --->
PASSED
```

If any part of the test fails, then the display appears as follows:

```
L2CACHE WBINV: L2-Cache WriteBack w/Invalidate... Running --->
FAILED

L2CACHE/WBINV Test Failure Data:
(error message)
```

Refer to the section *L2CACHE Error Messages* for a list of the error messages and their meaning.

WRTHRU - WriteThru

Command Input

```
PPC1-Diag>l2cache wrthru
```

Description

This test performs a write/read test on the L2 Cache. This test verifies that the device can be both accessed and that the L2 Cache WriteThru control is working. The test flow is as follows:

Turn on the cache with WriteThru. Write an incrementing pattern to memory and the cache. Verify the incrementing pattern. Turn off the cache. Verify that the incrementing pattern is in memory. Write decrementing pattern to memory. Verify the decrementing pattern. Turn on the cache with WriteThru, and verify the incrementing pattern in cache.

Response/Messages

After the command has been issued, the following line is printed:

```
L2CACHE WRTHRU: L2-Cache WriteThru..... Running --->
```

If all parts of the test are completed correctly, then the test passes.

```
L2CACHE WRTHRU: L2-Cache WriteThru..... Running ---> PASSED
```

If all parts of the test are not completed correctly, then the test does not pass:

```
L2CACHE WRTHRU: L2-Cache WriteThru..... Running ---> FAILED

L2CACHE/WRTHRU Test Failure Data:
(error message)
```

Refer to the section *L2CACHE Error Messages* for a list of the error messages and their meaning.

L2CACHE Error Messages

The L2 Cache test group error messages generally take the following form:

```
L2CACHE DISUPD: L2-Cache Disable Updating... Running ---> FAILED

L2CACHE/DISUPD Test Failure Data:
Data Miscompare Failure:
Address =00040000, Expected =00000000, Actual =FFFFFFFF
```

The first line of the failure identifies what type of failure occurred. The following line provides additional information about the failure.

Table 3-12. L2CACHE Error Messages

Error Message	Symptom or Cause
`f_l2cache_init: internal error: unexpected cmd=0xYY`	Init function called with something other than INIT, DONE, or SETUP.
`L2-Cache Size Miscompare Error: Address = %08X, Expected = %s, Actual = %s`	Cache Size does not match expected.
`Data Miscompare Failure: Address =00040000, Expected =00000000, Actual =FFFFFFFF`	Data write does not match data read.

NCR - 53C8xx SCSI I/O Processor Tests

These sections describe the individual NCR 53C8xx (SCSI I/O Processor) tests.

The firmware now provides support for testing of multiple SCSI controllers within PCI configuration space. This means that the SCSI diagnostics can now be run on multiple SCSI controllers. This is "only" true for any firmware supported SCSI devices.

Examples of where SCSI tests run include:

1. On a PowerPC board that has two (2) SCSI devices on the board.
2. On a PowerPC board that has one (1) SCSI device on the board and one (1) SCSI PMC/PCI card attached to the board.
3. On a PowerPC board that has one (1) SCSI device on the board and a SCSI PMC attached to the PMC Carrier plugged into the backplane of the chassis.

Entering **NCR** without parameters causes all **NCR** tests in the order shown in the table below.

To run an individual test, add that test name to the **NCR** command.

The individual tests are described in alphabetical order on the following pages.

Table 3-13. NCR Test Group

Name	Description
PCI	PCI Access
ACC1	Device Access
ACC2	Register Access
SFIFO	SCSI FIFO
DFIFO	DMA FIFO
SCRIPTS	SCRIPTs Processor
IRQ	Interrupts

The error message displays following the explanation of an **NCR** test pertain to the test being discussed.

ACC1 - Device Access

Command Input

```
PPCx-Diag>NCR ACC1
```

Description

This procedure tests the basic ability to access the NCR 53C8xx device.

1. All device registers are accessed (read) on 8-bit and 32-bit boundaries. (No attempt is made to verify the contents of the registers.)
2. The device data lines are checked by successive writes and reads to the SCRATCH register, by walking a 1 bit through a field of zeros and walking a 0 bit through a field of ones.

If no errors are detected, the NCR device is reset; otherwise the device is left in the test state.

Response/Messages

After the command has been issued, the following line is printed:

```
NCR  ACC1: Device Access..................... Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
NCR  ACC1: Device Access..................... Running ---> PASSED
```

If any part of the test fails, then the display appears as follows:

```
NCR  ACC1: Device Access..................... Running ---> FAILED

NCR/ACC1 Test Failure Data:
(error message)
```

Here *(error message)* is one of the following:

```
SCRATCH Register is not initially cleared

Device Access Error:
Address =________, Expected =________, Actual =________

Device Access Error:
```

```
Bus Error Information:
              Address ________
              Data ________
              Access Size __
              Access Type _
              Address Space Code _
              Vector Number ___


Unsolicited Exception:
              Program Counter ________
              Vector Number ___
              Status Register ____
              Interrupt Level _
```

Notes 1. All error message data is displayed as hexadecimal values.

2. The Unsolicited Exception information is only displayed if the exception was not a Bus Error.

3. Access Size is displayed in bytes.

4. Access Type is: 0 (write), or 1 (read).

ACC2 - Register Access

Command Input

```
PPCx-Diag>ncr acc2
```

Description

This procedure tests the basic ability to access the NCR 53C8xx registers, by checking the state of the registers from a software reset condition and checking their read/write ability. Status registers are checked for initial clear condition after a software reset. Writable registers are written and read with a walking 1 through a field of zeros.

If no errors are detected, the NCR device is reset; otherwise the device is left in the test state.

Response/Messages

After the command has been issued, the following line is printed:

```
NCR  ACC2: Register Access.................. Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
NCR  ACC2: Register Access.................. Running ---> PASSED
```

If any part of the test fails, then the display appears as follows:

```
NCR  ACC2: Register Access.................. Running ---> FAILED

NCR/ACC2 Test Failure Data:
(error message)
```

Here *(error message)* is one of the following:

```
ISTAT Register is not initially cleared

SSTAT0 Register is not initially cleared

SSTAT1 Register is not initially cleared

SSTAT2 Register is not initially cleared

SIEN Register Error:
Address =________, Expected =__, Actual =__
```

```
SDID Register Error:
Address =________, Expected =__, Actual =__

SODL Register Error:
Address =________, Expected =__, Actual =__

SXFER Register Error:
Address =________, Expected =__, Actual =__

SCID Register Error:
Address =________, Expected =__, Actual =__

DSA Register Error:
Address =________, Expected =________, Actual =________

TEMP Register Error:
Address =________, Expected =________, Actual =________

DMA Next Address Error:
Address =________, Expected =________, Actual =________

Register Access Error:

Bus Error Information:
               Address ________
               Data ________
               Access Size __
               Access Type _
               Address Space Code _
               Vector Number ___

Unsolicited Exception:
               Program Counter ________
               Vector Number ___
               Status Register ____
               Interrupt Level _
```

Notes 1. All error message data is displayed as hexadecimal values.

2. The Unsolicited Exception information is only displayed if the exception was not a Bus Error.

3. Access Size is displayed in bytes.

4. Access Type is: 0 (write), or 1 (read).

DFIFO - DMA FIFO

Command Input

```
PPCx-Diag>NCR DFIFO
```

Description

This procedure tests the basic ability to write data into the DMA FIFO and retrieve it in the same order as written. The DMA FIFO is checked for an empty condition following a software reset, then the FBL2 bit is set and verified. The FIFO is then filled with 16 bytes of data in the four byte lanes verifying the byte lane full or empty with each write. Next the FIFO is read verifying the data and the byte lane full or empty with each read.

If no errors are detected, the NCR device is reset; otherwise the device is left in the test state.

Response/Messages

After the command has been issued, the following line is printed:

```
NCR  DFIFO: DMA FIFO..................... Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
NCR  DFIFO: DMA FIFO..................... Running ---> PASSED
```

If any part of the test fails, then the display appears as follows:

```
NCR  DFIFO: DMA FIFO..................... Running ---> FAILED

NCR/DFIFO Test Failure Data:
(error message)
```

Here *(error message)* is one of the following:

```
DMA FIFO is not initially empty

DMA FIFO Byte Control not enabled
Address =________, Expected =__, Actual =__

DMA FIFO Byte Control Error:
Address =________, Expected =__, Actual =__

DMA FIFO Empty/Full Error:
Address =________, Expected =__, Actual =__
```

```
DMA FIFO Parity Error:
Address =________, Expected =__, Actual =__ DMA FIFO Byte Lane _

DMA FIFO Error:
Address =________, Expected =__, Actual =__ DMA FIFO Byte Lane _
```

IRQ - Interrupts

Command Input

```
PPCx-Diag>NCR IRQ
```

Description

This test verifies that interrupts can be generated and received and that the appropriate status is set.

Response/Messages

After the command has been issued, the following line is printed:

```
NCR  IRQ: NCR 53C8xx Interrupts.............. Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
NCR  IRQ: NCR 53C8xx Interrupts.............. Running ---> PASSED
```

If any part of the test fails, then the display appears as follows:

```
NCR  IRQ: NCR 53C8xx Interrupts.............. Running ---> FAILED

NCR/IRQ Test Failure Data:
 (error message)
```

Here *(error message)* is one of the following:

```
Test Initialization Error:
Not Enough Memory, Need =________, Actual =________

Test Initialization Error:
Memory Move Byte Count to Large, Max =00ffffff, Requested
=________

Test Initialization Error:
Test Memory Base Address Not 32 Bit Aligned =________

SCSI Status Zero “SGE” bit not set
Address =________, Expected =__, Actual =__

Interrupt Status “SIP” bit not set
Address =________, Expected =__, Actual =__

SCSI Status Zero “SGE” bit will not clear
Address =________, Expected =__, Actual =__
```

```
Interrupt Status “SIP” bit will not clear
Address =________, Expected =__, Actual =__

Interrupt Control Reg. not initially clear
Address =________, Expected =__, Actual =__

SCSI Interrupt Enable “SGE” bit not set
Address =________, Expected =__, Actual =__

Interrupt Control “IEN” bit not set
Address =________, Expected =__, Actual =__

Interrupt Status bit did not set
Status: Expected =__, Actual =__
Vector: Expected =__, Actual =__
State : IRQ Level =_, VBR =__

Interrupt Control “INT” bit will not clear
Address =________, Expected =__, Actual =__

SCSI Interrupt Enable Reg. will not mask interrupts
Address =________, Expected =__, Actual =__

Incorrect Vector type
Status: Expected =__, Actual =__
Vector: Expected =__, Actual =__
State : IRQ Level =_, VBR =__

SCSI Interrupt
Status: Expected =__, Actual =__
DMA Interrupt
Status: Expected =__, Actual =__

Unexpected Vector taken
Status: Expected =__, Actual =__
Vector: Expected =__, Actual =__
State : IRQ Level =_, VBR =__

Interrupt did not occur
Status: Expected =__, Actual =__
Vector: Expected =__, Actual =__
State : IRQ Level =_, VBR =__

Interrupt Status bit did not set
Status: Expected =__, Actual =__
Vector: Expected =__, Actual =__
State : IRQ Level =_, VBR =__

Interrupt Control “INT” bit will not clear
Address =________, Expected =__, Actual =__
```

```
Bus Error Information:
                Address ________
                Data ________
                Access Size __
                Access Type _
                Address Space Code _
                Vector Number ___

Unsolicited Exception:
                Program Counter ________
                Vector Number ___
                Status Register ____
                Interrupt Level _
```

PCI - PCI Access

Command Input

```
PPC1-Diag>ncr pci
```

Description

This procedure tests the basic ability to access the PCI Configuration register address space for the NCR 53C8xx device. It performs a read of the address space and copies it into local memory and checks for bus errors and other catastrophic errors during this process.

If no errors are detected, the NCR device is reset; otherwise the device is left in the test state.

Response/Messages

After the command has been issued, the following line is printed:

```
NCR   PCI: PCI Access..................... Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
NCR   PCI: PCI Access..................... Running ---> PASSED
```

If any part of the test fails, then the display appears as follows:

```
NCR   PCI: PCI Access..................... Running ---> FAILED

NCR/PCI Test Failure Data:
(error message)
```

Here *(error message)* is one of the following:

```
Unsolicited Exception:
Exception Time IP xxxxxxx
Vector nnnn
```

If it happens that the exception is a bus error, more information follows:

```
Data-Access/Machine-Check Information:
Address xxxxxxxx
Data dddddddd
Access Size nnnn
Access Type xxxx
Address Space Code xxxx
bus error vector xxxxxxxx
```

Notes

1. All error message data is displayed as hexadecimal values.
2. Access Size is displayed in bytes.
3. Access Type is: 0 (write), or 1 (read).

SCRIPTS - SCRIPTs Processor

Command Input

```
PPCx-Diag>NCR SCRIPTS
```

Description

This test initializes the test structures and makes use of the diagnostic registers for test, as follows:

- Verifies that the following registers are initially clear:

SIEN	SCSI Interrupt Enable
DIEN	DMA Interrupt Enable
SSTAT0	SCSI Status Zero
DSTAT	DMA Status
ISTAT	Interrupt Status
SFBR	SCSI First Byte Received

- Sets SCSI outputs in high impedance state, disables interrupts using the “MIEN”, and sets NCR device for Single Step Mode.
- Loads the address of a simple “INTERRUPT instruction” SCRIPT into the DMA SCRIPTs Pointer register. The SCRIPTs processor is started by hitting the “STD” bit in the DMA Control Register.

  Single Step is checked by verifying that ONLY the first instruction executed and that the correct status bits are set. Single Step Mode is then turned off and the SCRIPTs processor started again. The “INTERRUPT instruction” should then be executed and a check for the correct status bits set is made.
- Loads the address of the “JUMP instruction” SCRIPT into the DMA SCRIPTs Pointer register, and the SCRIPTs processor is automatically started. JUMP “if TRUE” (Compare = True, Compare = False) conditions are checked, then JUMP “if FALSE” (Compare = True, Compare = False) conditions are checked.

- Builds the “Memory Move instruction” SCRIPT in a script buffer to allow the “Source Address”, “Destination Address”, and “Byte Count” to be changed by use of the “config” command. If a parameter is changed, the only check for validity is the “Byte Count” during test structures initialization.

  The “Memory Move” SCRIPT copies the specified number of bytes from the source address to the destination address.

Response/Messages

After the command has been issued, the following line is printed:

```
NCR  SCRIPTS: NCR 53C8xx SCRIPTs Processor... Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
NCR  SCRIPTS: NCR 53C8xx SCRIPTs Processor... Running ---> PASSED
```

If any part of the test fails, then the display appears as follows:

```
NCR  SCRIPTS: NCR 53C8xx SCRIPTs Processor... Running ---> FAILED

NCR/SCRIPTS Test Failure Data:
(error message)
```

Here *(error message)* is one of the following:

```
Test Initialization Error:
Not Enough Memory, Need =________, Actual =________

Test Initialization Error:
Memory Move Byte Count to Large, Max =00ffffff, Requested
=________

Test Initialization Error:
Test Memory Base Address Not 32 Bit Aligned =________

SCSI Interrupt Enable Reg. not initially clear
Address =________, Expected =__, Actual =__

DMA Interrupt Enable Reg. not initially clear
Address =________, Expected =__, Actual =__

SCSI Status Zero Reg. not initially clear
Address =________, Expected =__, Actual =__

DMA Status Reg. not initially clear
Address =________, Expected =__, Actual =__
```

```
Interrupt Status Reg. not initially clear
Address =________, Expected =__, Actual =__

SCSI First Byte Received Reg. not initially clear
Address =________, Expected =__, Actual =__

SCSI First Byte Received Reg. not set
Address =________, Expected =__, Actual =__

DMA Status "SSI" bit not set
Address =________, Expected =__, Actual =__

Interrupt Status "DIP" bit not set
Address =________, Expected =__, Actual =__

SCSI Status Zero Reg. set during single step
Address =________, Expected =__, Actual =__

Test Timeout during: INTERRUPT SCRIPTs Test
Address =________, Expected =__, Actual =__

"SIR" not detected during: INTERRUPT SCRIPTs Test
Address =________, Expected =__, Actual =__

Test Timeout during: JUMP SCRIPTs Test
Address =________, Expected =__, Actual =__

"SIR" not detected during: JUMP SCRIPTs Test
Address =________, Expected =__, Actual =__

Jump if "True", and Compare = True; Jump not taken

Jump if "True", and Compare = False; Jump taken

Jump if "False", and Compare = True; Jump taken

Jump if "True", and Compare = False; Jump not taken

Test Timeout during: Memory Move SCRIPTs Test
Address =________, Expected =__, Actual =__

"SIR" not detected during: Memory Move SCRIPTs Test
Address =________, Expected =__, Actual =__
```

SFIFO - SCSI FIFO

Command Input

```
PPCx-Diag>ncr sfifo
```

Description

This procedure tests the basic ability to write data into the SCSI FIFO and retrieve it in the same order as written. The SCSI FIFO is checked for an empty condition following a software reset, then the SFWR bit is set and verified. The FIFO is then filled with 8 bytes of data verifying the byte count with each write. Next the SFWR bit is cleared and the FIFO read, verifying the byte count with each read.

If no errors are detected, the NCR device is reset; otherwise the device is left in the test state.

Response/Messages

After the command has been issued, the following line is printed:

```
NCR  SFIFO: SCSI FIFO..................... Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
NCR  SFIFO: SCSI FIFO..................... Running ---> PASSED
```

If any part of the test fails, then the display appears as follows:

```
NCR  SFIFO: SCSI FIFO..................... Running ---> FAILED

NCR/SFIFO Test Failure Data:
 (error message)
```

Here *(error message)* is one of the following:

```
SCSI FIFO is not initially empty

SCSI FIFO writes not enabled

SCSI FIFO Count Error:
Address =________, Expected =__, Actual =__

SCSI FIFO Error:
Address =________, Expected =__, Actual =__
```

PAR8730x - Parallel Port Test

This section describes the PC8730x parallel port test. This test is performed using only one processor.

You may enter **PAR8730x** with or without specifying the **REG** test. **REG** is the only test in the **PAR8730x** group.

The **REG** test is described on the following page.

Table 3-14. PAR8730x Test Group

Name	Description
REG	Register

REG - Register

Command Input:

```
PPCx-Diag>PAR8730x REG
```

Description

This test verifies that all of the PC8730x registers can be written and read. Data patterns verify that every read/write bit can be modified.

Response/Messages

After the command has been issued, the following line is printed:

```
PAR8730x REG:PC8730x Parallel Port's Register/Data..Running -->
```

If all parts of the test are completed correctly, then the test passes:

```
PAR8730x REG:PC8730x Parallel Port's Register/Data..Running -->
PASSED
```

If any failures occur, the following is displayed (more descriptive text then follows):

```
PAR8730x REG:PC8730x Parallel Port's Register/Data..Running -->
FAILED
```

If the test fails because the pattern written doesn't match the data read back from the PAR8730x register, the following is printed:

```
PAR8730x/REG Test Failure Data:
Register xxx Miscompare Error:Address =____,Expected =_,Actual =_
```

UART - Serial Input/Output Tests

These sections describe the individual UART tests.

Entering **UART** without parameters causes all **UART** tests to run in the order shown in the table below, except as noted.

To run an individual test, add that test name to the **UART** command.

The individual tests are described in alphabetical order on the following pages.

Table 3-15. UART Test Group

Name	Description
REGA	Register Access
IRQ	Interrupt Request
BAUD	Baud Rate tests
LPBK	Internal loopback
Executed only when specified:	
LPBKE	External Loopback

You can use the **CF** command to select the ports to be tested. This example uses the **CF** command to select port 0, skipping 1.

Example:

```
PPCx-Diag>CF UART
External-Loopback Port Mask =00000002? 01
```

(Bit 0 selects port 0, Bit 1 selects port 1, etc. -- see note below.)

The next parameter is the port selection mask. This mask is used during testing to identify which ports are to be tested. The default is to test every port except the console port. The External-Loopback Port Mask is used for the **LPBKE** test suite.

BAUD - Baud Rates

Command Input

```
PPCx-Diag>UART BAUD
```

Description

This test transmits 18 characters at various baud rates. The data is received and compared. If any protocol errors are created or the data is not correct when received, the test failed.

The bauds tested are:

300	9600
1200	19200
2400	38400

Response/Messages

After the command has been issued, the following line is printed:

```
UART   BAUD: Baud Rates.................. Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
UART   BAUD: Baud Rates.................. Running ---> PASSED
```

If any part of the test fails, then the display appears as follows:

```
UART   BAUD: Baud Rates.................. Running ---> FAILED

UART/BAUD Test Failure Data:
(error message)
```

Refer to the section *UART Error Messages* for a list of the error messages and their meaning.

IRQ - Interrupt Request

Command Input

```
PPCx-Diag>UART IRQ
```

Description

This test verifies that the UARTs can generate interrupts to the local processor. This is done using the transmitter empty interrupt from the UART under test.

Response/Messages

After the command has been issued, the following line is printed:

```
UART   IRQ: Interrupt Request..... Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
UART   IRQ: Interrupt Request..... Running --->PASSED
```

If any part of the test fails, then the display appears as follows:

```
UART   IRQ: Interrupt Request..... Running --->FAILED

UART/IRQ Test Failure Data:
(error message)
```

Refer to the section *UART Error Messages* for a list of the error messages and their meaning.

LPBK - Internal Loopback

Command Input

```
PPCx-Diag>UART lpbk
```

Description

This test transmits 18 characters at 9600 baud. The data is received and compared. If any protocol errors are created or the data is not correct when received, the test failed.

Response/Messages

After the command has been issued, the following line is printed:

```
UART   LPBK: Internal Loopback.......... Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
UART   LPBK: Internal Loopback.......... Running --->PASSED
```

If any part of the test fails, then the display appears as follows:

```
UART   LPBK: Internal Loopback.......... Running --->FAILED

UART/LPBK Test Failure Data:
(error message)
```

Refer to the section *UART Error Messages* for a list of the error messages and their meaning.

LPBKE - External Loopback

Command Input

```
PPCx-Diag>UART lpbke
```

Description

This test transmits 18 characters at 9600 baud. The data is received and compared. If any protocol errors are created or the data is not correct when received, the test failed. This test also verifies that modem control lines may be asserted and deasserted and that these signals are received back by the UART.

This test *does* require an external loopback connector to be installed. For this test, the following connections need to be made in the loopback connector:

TxD connected to **RxD**

DTR connected to **DCD** and **DSR**

RTS connected to **CTS** and **RI**

Response/Messages

After the command has been issued, the following line is printed:

```
UART   LPBKE: External Loopback.......... Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
UART   LPBKE: External Loopback.......Running --->PASSED
```

If any part of the test fails, then the display appears as follows:

```
UART   LPBKE: External Loopback......Running --->FAILED

UART/LPBKE Test Failure Data:
(error message)
```

Refer to the section *UART Error Messages* for a list of the error messages and their meaning.

REGA - Device/Register Access

Command Input

```
PPCx-Diag>UART REGA
```

Description

This test performs a read test on all registers in the UARTs. It also verifies that the UART scratch registers are readable and writable. This test verifies that the device can be both accessed and that the data paths to the device are functioning.

Response/Messages

After the command has been issued, the following line is printed:

```
UART   REGA: Register Access.............. Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
UART   REGA: Register Access.........Running ---> PASSED
```

If any part of the test fails, then the display appears as follows:

```
UART   REGA: Register Access.........Running ---> FAILED

UART/REGA Test Failure Data:
(error message)
```

Refer to the section *UART Error Messages* for a list of the error messages and their meaning.

UART Error Messages

The **UART** test group error messages generally take the following form:

```
UART  BAUD: Baud Rates.............Running ---> FAILED

UART/BAUD Test Failure Data:
Data Miscompare Error:
Address =XXXXXXXX, Register Index =XX
Expected =XX, Actual =XX
```

The first line of the test failure data identifies what type of failure occurred. The following line provides additional information about the failure.

Table 3-16. UART Error Messages

Error Message	Symptom or Cause
`Unsolicited Exception:` `Vector` *XX*	An unexpected exception occurred.
`Data Miscompare Error:` `Address =`*XXXXXXXX*`, Register Index =`*XX* `Expected =`*XX*`, Actual =`*XX*	Data write does not match data read.
`Transmit buffer failed to empty: channel %d`	Transmitter buffer remained full.
`Time out waiting for transmitter interrupt:channel` *XX*	During Interrupt testing, no interrupt was generated or received.
`Baud rate failure, expected %d took %d:channel` *XX*	Measured baud rate was not the same as that expected.
`Receiver line status interrupt occurred:channel` *XX* *<additional error information>*	Data transmission error occurred. Possible errors are: framing, parity, or data overrun.
`Unexpected modem status interrupt occurred:channel` *XX*	An unexpected change of modem signals was received during testing.

Table 3-16. UART Error Messages (Continued)

Error Message	Symptom or Cause
`Transmit/Receive character mismatch:channel XX`	Data transmitted does not match data received.
`Receiver Ready (Character Available) Time-Out PC16550 Base Address =`*`XXXXXXXX`*`, Channel =XX Baud Rate =`*`XXXX`*	The receiver has not received a character in the allotted time.
`DTR loopback to DSR and DCD Failed: Channel=`*`XX`*	When DTR was driven, DCD or DSR did not follow.
`RTS loopback to CTS and RI Failed: Channel=`*`XX`*	When RTS was driven, CTS or RI did not follow.

PCIBUS - Generic PCI/PMC Slot Tests

These sections describe the individual **PCIBUS** tests. These tests are available on all PowerPC boards.

Entering **PCIBUS** without parameters causes all **PCIBUS** tests to run in the order shown in the table below, except as noted.

To run an individual test, add that test name to the **PCIBUS** command.

The individual tests are described in alphabetical order on the following pages.

Table 3-17. PCIBUS Test Group

Name	Description
REG	Register Access

REG - PCI/PMC Slot Register Access

Command Input

```
PPCx-Diag>pcibus reg
```

Description

The purpose of this function is to test any available PCI or PMC slots on PowerPC based boards. The test loops through all possible slots for the current board. The test then checks to see if the slot is inhabited, if not, the test is not performed. If a device is present, then access to the device's PCI configuration space is made, and the interrupt line register is written with a sixteen byte pattern. Each of these bytes written is verified, and finally the register is restored to its initial value.

Note The test passes if all the conditions are met, **or** if the slot is not populated (some boards have multiple slots).

Response/Messages

After the command has been issued, the following line is printed:

```
PCIBUS REG: PCI/PMC Slot Register Access:... Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
PCIBUS REG: PCI/PMC Slot Register Access:..Running ---> PASSED
```

If any part of the test fails, then the display appears as follows:

```
PCIBUS REG: PCI/PMC Slot Register Access:...Running ---> FAILED
(error message)
```

Refer to the section *PCIBUS Error Messages* for a list of the error messages and their meaning.

PCIBUS Error Messages

The **PCIBUS** test group error messages generally take the following form:

```
PCIBUS REG: PCI/PMC:.......... Running ---> FAILED
BIST failed to complete.
```

The first line of the test failure data identifies what type of failure occurred.

Table 3-18. PCIBUS Error Messages

Error Message	Symptom or Cause
`BIST failed to complete.`	The Built-In-Self-Test of the PCI or PMC device did not complete before timing out.
`Interrupt Line Register Write Error.`	The value read from the Interrupt Line Register does match what was written.

RAM - Local RAM Tests

These sections describe the individual Random Access Memory (RAM) tests.

Entering **RAM** without parameters causes all **RAM** tests to execute in the order shown in the table below.

To run an individual test, add that test name to the **RAM** command.

The individual tests are described in alphabetical order on the following pages.

Table 3-19. RAM Test Group

Name	Description
MARCH	March Pattern
QUIK	Quick Write/Read
ALTS	Alternating Ones/Zeros
PATS	Data Patterns
ADR	Memory Addressing
CODE	Code Execution/Copy
PERM	Permutations
RNDM	Random Data
BTOG	Bit Toggle
PED	Parity Error Detection
REF	Memory Refresh

ADR - Memory Addressing

Command Input

```
PPCx-Diag>RAM ADR
```

Description

This is the memory addressability test, the purpose of which is to verify addressing of memory in the range specified by the configuration parameters for the **RAM** test group. Addressing errors are sought by using a memory locations address as the data for that location. This test is coded to use only 32-bit data entities. The test proceeds as follows:

1. A Locations Address is written to its location (*n*).
2. The next location (*n*+4) is written with its address complemented.
3. The next location (*n*+8) is written with the most significant (MS) 16 bits and least significant (LS) 16 bits of its address swapped with each other.
4. Steps 1, 2, and 3 are repeated throughout the specified memory range.
5. The memory is read and verified for the correct data pattern(s) and any errors are reported.
6. The test is repeated using the same algorithm as above (steps 1 through 5) except that inverted data is used to insure that every data bit is written and verified at both “0” and “1”.

Response/Messages

After the command has been issued, the following line is printed:

```
RAM   ADR: Addressability.............. Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
RAM   ADR: Addressability.............Running ---> PASSED
```

If the test fails, then the display appears as follows:

```
RAM   ADR: Addressability.............Running ---> FAILED

RAM/ADR Test Failure Data:
Data Miscompare Error:
Address =________, Expected =________, Actual =________
```

ALTS - Alternating Ones/Zeros

Command Input

```
PPCx-Diag>RAM ALTS
```

Description

This test verifies addressing of memory in the range specified by the configuration parameters for the **RAM** test group. Addressing errors are sought by using a memory locations address as the data for that location. This test is coded to use only 32-bit data entities. The test proceeds as follows:

1. Location (*n*) is written with data of all bits 0.
2. The next location (*n*+4) is written with all bits 1.
3. Steps 1 and 2 are repeated throughout the specified memory range.
4. The memory is read and verified for the correct data pattern(s) and any errors are reported.

Response/Messages

After the command has been issued, the following line is printed:

```
RAM   ALTS: Alternating Ones/Zeroes.......... Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
RAM   ALTS: Alternating Ones/Zeroes...Running ---> PASSED
```

If the test fails, then the display appears as follows:

```
RAM   ALTS: Alternating Ones/Zeroes...Running ---> FAILED

RAM/ALTS Test Failure Data:
Data Miscompare Error:
Address =________, Expected =________, Actual =________
```

BTOG - Bit Toggle

Command Input

```
PPCx-Diag>ram btog
```

Description

The memory range is specified by the RAM test directory configuration parameters. (Refer to *CF - Test Group Configuration Parameters Editor* in Chapter 2.) The RAM test directory configuration parameters also determine the value of the global random data seed used by this test. The global random data seed is incremented after it is used by this test. This test uses the following test data pattern generation algorithm:

1. Random data seed is copied into a work register.
2. Work register data is shifted right one bit position.
3. Random data seed is added to work register using unsigned arithmetic.
4. Data in the work register may or may not be complemented.
5. Data in the work register is written to current memory location.

If the RAM test directory configuration parameter for code cache enable equals “Y”, the microprocessor code cache is enabled. This test is coded to operate using the 32-bit data size only. Each memory location in the specified memory range is written with the test data pattern. Each memory location in the specified memory range is then written with the test data pattern complemented before it is written. The memory under test is read back to verify that the complement test data is properly retained. Each memory location in the specified memory range is then written with the test data pattern. The memory under test is read back to verify that the test data is properly retained.

Response/Messages

After the command has been issued, the following line is printed:

```
RAM   BTOG: Bit Toggle..................... Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
RAM   BTOG: Bit Toggle..................... Running ---> PASSED
```

If the test fails, then the display appears as follows:

```
RAM   BTOG: Bit Toggle..................... Running ---> FAILED

RAM/BTOG Test Failure Data:
Data Miscompare Error:
Address =________, Expected =________, Actual =________
```

CODE - Code Execution/Copy

Command Input

```
PPCx-Diag>RAM CODE
```

Description

Copy test code to memory and execute. The code in the memory under test copies itself to the next higher memory address and executes the new copy. This process is repeated until there is not enough memory, as specified by the configuration parameters, to perform another code copy and execution.

Response/Messages

After the command has been issued, the following line is printed:

```
RAM  CODE: Code Execution/Copy.............Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
RAM  CODE: Code Execution/Copy.......Running ---> PASSED
```

The test failure mode is typified by the nonjudicial of the `PASSED` message above after more than about 1 minute, which indicates that the MPU has irrecoverably crashed.

Hardware reset is required to recover from this error.

MARCH - March Pattern

Command Input

```
PPCx-Diag>ram march
```

Description

This is the memory march test, the purpose of which is to verify addressing of memory in the range specified by the configuration parameters for the **RAM** test group. Addressing errors are sought by writing a pattern and its complement to each location. This test is coded to use only 32-bit data entities. The test proceeds as follows:

1. Starting at the beginning test address and proceeding towards the ending address, each location is written with the starting pattern.
2. Starting at the beginning test address and proceeding towards the ending address, each location is verified to contain the starting pattern and is written with the complement of the starting pattern.
3. Starting at the ending test address and decreasing to the starting test address, each location is verified to contain the complement of the starting pattern and is then written with the starting pattern.

Response/Messages

After the command has been issued, the following line is printed:

```
RAM   MARCH: March Address.............. Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
RAM   MARCH: March Address.....Running ---> PASSED
```

If the test fails, then the display appears as follows:

```
RAM   MARCH: March Address.....Running ---> FAILED

RAM/MARCH Test Failure Data:
Data Miscompare Error:
Address =________, Expected =________, Actual =________
```

PATS - Data Patterns

Command Input

```
PPCx-Diag>RAM PATS
```

Description

If the test address range (test range) is less than 8 bytes, the test immediately returns pass status. The effective test range end address is reduced to the next lower 8-byte boundary if necessary. Memory in the test range is filled with all ones ($FFFFFFFF). For each location in the test range, the following patterns are used:

```
$00000000
$01010101
$03030303
$07070707
$0F0F0F0F
$1F1F1F1F
$3F3F3F3F
$7F7F7F7F
```

Each location in the test range is, individually, written with the current pattern and the 1's complement of the current pattern. Each write is read back and verified. This test is coded to use only 32-bit data entities.

Response/Messages

After the command has been issued, the following line is printed:

```
RAM   PATS: Patterns.................. Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
RAM   PATS: Patterns.................. Running ---> PASSED
```

If the test fails, then the display appears as follows:

```
RAM   PATS: Patterns.................. Running ---> FAILED

RAM/PATS Test Failure Data:
Data Miscompare Error:
Address =________, Expected =________, Actual =_________
```

PED - Local Parity Memory Error Detection

Command Input

```
PPCx-Diag>RAM PED
```

Description

The memory range and address increment is specified by the RAM test directory configuration parameters. (Refer to *CF - Test Group Configuration Parameters Editor* in Chapter 2.)

First, each memory location to be tested has the data portion verified by writing/verifying all zeros, and all ones. Each memory location to be tested is tested once with parity interrupt disabled, and once with parity interrupt enabled. Parity checking is enabled, and data is written and verified at the test location that causes the parity bit to toggle on and off (verifying that the parity bit of memory is good). Next, data with incorrect parity is written to the test location. The data is read, and if a parity error exception does occur, the fault address is compared to the test address. If the addresses are the same, the test passed and the test location is incremented until the end of the test range has been reached.

Response/Messages

After the command has been issued, the following line is printed:

```
RAM   PED: Local Parity Memory Detection.....Running --->
```

If the board under test does not support Parity error detection, the test is bypassed:

```
RAM   PED: Local Parity Memory Detection....Running --> BYPASS
```

If all parts of the test are completed correctly, then the test passes:

```
RAM   PED: Local Parity Memory Detection.....Running ---> PASSED
```

If any part of the test fails, then the display appears as follows:

```
RAM   PED: Local Parity Memory Detection...... Running ---> FAILED

RAM/PED Test Failure Data:
(error message)
```

Here *(error message)* is one of the following:

If a data verification error occurs:

```
Data Miscompare Error:
Address =________, Expected =________, Actual =________
```

If an unexpected exception, such as a parity error being detected as the parity bit was being toggled:

```
Unexpected Exception Error, Vector =________
Address Under Test =________
```

If no exception occurred when data with bad parity was read:

```
Parity Error Detection Exception Did Not Occur

Exception Vector =________
Address Under Test =________
```

If the exception address was different from that of the test location:

```
Fault Address Miscompare, Expected =________, Actual =________
```

PERM - Permutations

Command Input

```
PPCx-Diag>RAM PERM
```

Description

This command performs a test which verifies that the memory in the test range can accommodate 8-bit, 16-bit, and 32-bit writes and reads in any combination. The test range is the memory range specified by the **RAM** test group configuration parameters for starting and ending address. If the test address range (test range) is less than 16 bytes, the test immediately returns pass status. The effective test range end address is reduced to the next lower 16-byte boundary if necessary.

This test performs three data size test phases in the following order: 8, 16, and 32 bits. Each test phase writes a 16-byte data pattern (using its data size) to the first 16 bytes of every 256-byte block of memory in the test range. The 256-byte blocks of memory are aligned to the starting address configuration parameter for the **RAM** test group. The test phase then reads and verifies the 16-byte block using 8-bit, 16-bit, and 32-bit access modes.

Response/Messages

After the command has been issued, the following line is printed:

```
RAM   PERM: Permutations..................Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
RAM   PERM: Permutations............Running ---> PASSED
```

If the test fails, then the display appears as follows:

```
RAM   PERM: Permutations............Running ---> FAILED

RAM/PERM Test Failure Data:
Data Miscompare Error:
Address =________, Expected =________, Actual =________
```

QUIK - Quick Write/Read

Command Input

```
PPCx-Diag>ram quik
```

Description

Each pass of this test fills the test range with a data pattern by writing the current data pattern to each memory location from a local variable and reading it back into that same register. The local variable is verified to be unchanged only after the write pass through the test range. This test uses a first pass data pattern of 0, and $FFFFFFFF for the second pass. This test is coded to use only 32-bit data entities.

Response/Messages

After the command has been issued, the following line is printed:

```
RAM   QUIK: Quick Write/Read.................. Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
RAM   QUIK: Quick Write/Read.................. Running ---> PASSED
```

If the test fails, then the display appears as follows:

```
RAM   QUIK: Quick Write/Read.................. Running ---> FAILED

RAM/QUIK Test Failure Data:
Data Miscompare Error:
Expected =________, Actual =________
```

REF - Memory Refresh Testing

Command Input

```
PPCx-Diag>RAM REF
```

Description

The memory range and address increment is specified by the **RAM** test directory configuration parameters. (Refer to *CF - Test Group Configuration Parameters Editor* in Chapter 2.)

First, the real time clock is checked to see if it is functioning properly. Second, each memory location to be tested has the data portion verified by writing/verifying all zeros, and all ones. Next a data pattern is written to the test location. After all the data patterns are filled for all test locations, a refresh wait cycle is executed. After the wait cycle, the data is read, and if the previously entered data pattern does not match the data pattern read in, a failure occurs. If the data patterns match, then the test is passed.

Response/Messages

After the command has been issued, the following line is printed:

```
RAM   REF: Memory Refresh Test.............Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
RAM   REF: Memory Refresh Test........Running ---> PASSED
```

If any part of the test fails, then the display appears as follows:

```
RAM   REF: Memory Refresh Test........Running ---> FAILED

RAM/REF Test Failure Data:
(error message)
```

Here *(error message)* is one of the following:

If the real time clock is not functioning properly, one of the following is printed:

```
RTC is stopped, invoke SET command.
```

Or:

```
RTC is in write mode, invoke SET command.
```

Or:

```
RTC is in read mode, invoke SET command.
```

If a data verification error occurs before the refresh wait cycle:

```
Immediate Data Miscompare Error:
Address =________, Expected =________, Actual =________
```

If a data verification error occurs following the refresh wait cycle:

```
Unrefreshed Data Miscompare Error:
Address =________, Expected =________, Actual =________
```

RNDM - Random Data

Command Input

```
PPCx-Diag>RAM RNDM
```

Description

The test block is the memory range specified by the **RAM** test group configuration parameters. The test proceeds as follows:

1. A random pattern is written throughout the test block.
2. The random pattern complemented is written throughout the test block.
3. The complemented pattern is verified.
4. The random pattern is rewritten throughout the test block.
5. The random pattern is verified.

This test is coded to use only 32-bit data entities. Each time this test is executed, the random seed in the **RAM** test group configuration parameters is post incremented by 1.

Response/Messages

After the command has been issued, the following line is printed:

```
RAM   RNDM: Random Data.....................Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
RAM   RNDM: Random Data.............Running ---> PASSED
```

If the test fails, then the display appears as follows:

```
RAM   RNDM: Random Data.............Running ---> FAILED

RAM/RNDM Test Failure Data:
Data Miscompare Error:
Address =________, Expected =________, Actual =________
```

RTC - MK48Txx Timekeeping Tests

These tests check the BBRAM and clock portions of the MK48Txx Real Time Clock (RTC) chips.

Entering **RTC** without parameters causes all **RTC** tests to execute in the order shown in the table below, except as noted.

To run an individual test, add that test name to the **RTC** command.

The individual tests are described in alphabetical order on the following pages.

Table 3-20. RTC Test Group

Name	Description
RAM	Battery Backed-Up RAM
ADR	BBRAM Addressing
ALARM	Alarm Interrupt
Executed only when specified:	
CLK	Real Time Clock Function
WATCHDOG	Watchdog Time-Out Reset

ADR - MK48Txx BBRAM Addressing

Command Input

```
PPCx-Diag>RTC ADR
```

Description

This test is designed to assure proper addressability of the MK48Txx BBRAM. The algorithm used is to fill the BBRAM with data pattern “a”, a single address line of the MK48Txx is set to one, and pattern “b” is written to the resultant address. All other locations in the BBRAM are checked to ensure that they were not affected by this write. The “a” pattern is then restored to the resultant address. All address lines connected to the MK48Txx are tested in this manner.

Since this test overwrites all memory locations in the BBRAM, the BBRAM contents are saved in debugger system memory prior to writing the BBRAM. The RTC test group features a configuration parameter which overrides automatic restoration of the BBRAM contents. The default for this parameter is to restore BBRAM contents upon test completion.

Response/Messages

After the command has been issued, the following line is printed:

```
RTC  ADR: MK48Txx RAM Addressing............Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
RTC  ADR: MK48Txx RAM Addressing.....Running ---> PASSED
```

If any part of the test fails, then the display appears as follows:

```
RTC  ADR: MK48Txx RAM Addressing.....Running ---> FAILED

RTC/ADR Test Failure Data:
(error message)
```

Here *(error message)* is one of the following:

If debugger system memory cannot be allocated for use as a save area for the BBRAM contents:

```
RAM allocate

memc.next=________ memc.size=________
```

If the BBRAM cannot be initialized with pattern “a”:

```
Data Verify Error: Address =________, Expected =__, Actual =__
Memory initialization error
```

If a pattern “b” write affects any BBRAM location other than the resultant address:

```
Data Verify Error: Address =________, Expected =__, Actual =__
Memory addressing error - wrote __ to ________
```

ALARM - Alarm Interrupt

Command Input

```
PPCx-Diag>rtc alarm
```

Description

This test sets the alarm of the Real Time Clock (RTC) MK48Txx to go off every second, and verifies that interrupt IRQ8 occurs and the AF (Alarm Flag) bit of the RTC is set.

Response/Messages

After the command has been issued, the following line is printed:

```
RTC  ALARM: MK48Txx Alarm Interrupt........Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
RTC  ALARM: MK48Txx Alarm Interrupt...Running ---> PASSED
```

If any part of the test fails, then the display appears as follows:

```
RTC  ALARM: MK48Txx Alarm Interrupt...Running ---> FAILED

RTC/ALARM Test Failure Data:
(error message)
```

Here *(error message)* is one of the following:

If the expected interrupt IRQ8 did not occur, *(error message)* is:

```
Interrupt failed to occur. Int Stat Reg : xx hex
```

where xx is the contents in hex of the Interrupt Status Register of the PCI-to_ISA Bridge.

If an interrupt other than IRQ8 occurred, *(error message)* is:

```
Spurious interrupt occurred instead of IRQ8.
Int Stat Reg : xx hex
```

If interrupt IRQ8 did occur but the AF (Alarm Flag) was not set, *(error message)* is:

```
AF (Alarm Flag) bit was not set
```

CLK - Real Time Clock Function

Command Input

```
PPCx-Diag>RTC CLK
```

Description

This test verifies the functionality of the Real Time Clock (RTC). This test does not check clock accuracy.

This test requires approximately nine seconds to run. At the conclusion of the test, nine seconds are added to the clock time to compensate for the test delay. Because the clock can only be set to the nearest second, this test may induce one second of error into the clock time.

Response/Messages

After the command has been issued, the following line is printed:

```
RTC  CLK: MK48Txx Real Time Clock..... Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
RTC  CLK: MK48Txx Real Time Clock..... Running ---> PASSED
```

If the test fails, then the display appears as follows:

```
RTC  CLK: MK48Txx Real Time Clock..... Running ---> FAILED

RTC/CLK Test Failure Data:
(error message)
```

Here *(error message)* is one of the following:

If the check for low battery fails:

```
RTC low battery
```

The RTC time registers are configured for constant updating by the clock internal counters. The seconds register is read initially and then monitored (read) to verify that the seconds value changes. A predetermined number of reads are made of the seconds register.

If the predetermined number of reads are made before the seconds register changed, the following message is printed:

```
RTC not running
```

The RTC time registers are configured for reading. A pre-determined number of MPU “do nothing” loops are executed. If the seconds register changes before the full count of MPU loops is executed, the following message is printed:

```
RTC did not freeze for reading
```

If the real-time clock registers fail the data pattern test:

```
Data Miscompare Error:
Address =________, Expected =________, Actual =________
```

The following message indicates a programming error and should never be seen by the diagnostics user:

```
WARNING -- Real Time Clock NOT compensated for test delay.
```

RAM - Battery Backed-Up RAM

Command Input

```
PPCx-Diag>rtc ram
```

Description

This test performs a data test on each BBRAM location of the MK48Txx "Timekeeper" RAM. RAM contents are unchanged upon completion of test, regardless of pass or fail test return status. This test is coded to test only byte data entities. The test proceeds as follows:

For each of the following patterns: $1, $3, $7, $f, $1f, $3f, $7f;
for each valid byte of the "Timekeeper" RAM:

1. Write and verify the current data test pattern.
2. Write and verify the complement of the current data test pattern.

Response/Messages

After the command has been issued, the following line is printed:

```
RTC   RAM: MK48Txx Battery Backed Up RAM..... Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
RTC   RAM: MK48Txx Battery Backed Up RAM..... Running ---> PASSED
```

If the test fails, then the display appears as follows:

```
RTC   RAM: MK48Txx Battery Backed Up RAM..... Running ---> FAILED

RTC/RAM Test Failure Data:
(error message)
```

Here *(error message)* is the following:

```
Data Miscompare Error:
Address =________, Expected =________, Actual =________
```

WATCHDOG - Watchdog Time-Out Reset

Command Input

```
PPCx-Diag>rtc watchdog
```

Description

This test sets the Real Time Clock's Watchdog Timer to time out in one second. If the Watchdog Timer is functional, the WDF (Watchdog Flag) bit will be set and a microprocessor reset will be generated.



Caution

If this test passes, the Real Time Clock will reset the board.

Response/Messages

After the command has been issued, the following line is printed:

```
RTC   WATCHDOG: MK48Txx Battery Backed Up RAM.. Running --->
```

If all parts of the test are completed correctly, then the test passes by resetting the board.

If the test fails, then the display appears as follows:

```
RTC   WATCHDOG: MK48Txx Battery Backed Up RAM.. Running ---> FAILED

RTC/WATCHDOG Test Failure Data:
(error message)
```

Here *(error message)* is the following:

If the Watchdog Timer failed to reset the microprocessor when a time-out condition occurred, *(error message)* is:

```
Processor reset failed to occur.
```

If the WDT bit failed to be set when a time-out condition occurred, *(error message)* is:

```
WDF (Watchdog Flag) bit was not set.
```

SCC - Serial Communication Controller (Z85230) Tests

These sections describe the individual Serial Communication Controller (SCC) tests. These tests are not available on the MVME230*x* boards.

Entering **SCC** without parameters causes all **SCC** tests to run in the order shown in the table below, except as noted.

To run an individual test, add that test name to the **SCC** command.

The individual tests are described in alphabetical order on the following pages.

Table 3-21. SCC Test Group

Name	Description
ACCESS	Device/Register Access
IRQ	Interrupt Request
Executed only when specified:	
BAUDS	Baud Rates
ELPBCK	External Loopback
ILPBCK	Internal Loopback
MDMC	Modem Control
DMA	Receive/Transmit DMA

Note These tests number the ports of the Z85230 starting with the first Z85230 channel 0 as being port A, the second channel 1 as being port B. For the PowerPC family of boards there are only ports A and B.

You can use the **CF** command to select the ports to be tested. The following example uses the **CF** command to select port 1, skipping port 0.

Example:

```
PPC1-Diag>CF SCC
SCC Memory Space Base Address           =80000840?RETURN
Internal-Loopback/Baud-Rates Port Mask =00000003? 2
```

(Bit 0 selects port 0, Bit 1 selects port 1; see note below.)

```
External-Loopback/Modem-Control Port Mask=00000003?
```

The first parameter is the base address space for the Z85230 devices. This is preset for the PowerPC family of boards and should not be changed.

The next two parameters are the port selection masks. These masks are used during testing to identify which ports are to be tested. The default is to test every port. The Internal-Loopback/Baud-Rates Port Mask is used for the **BAUDS** and **ILPBCK** test suites. The External-Loopback/Modem-Control Port Mask is only used for the **ELPBCK** and **MDMC** test suites.

ACCESS - Device/Register Access

Command Input

```
PPCx-Diag>SCC ACCESS
```

Description

This test performs a write/read test on two registers in the Z85230. This test verifies that the device can be both accessed and that the data paths to the device are functioning.

Response/Messages

After the command has been issued, the following line is printed:

```
SCC  ACCESS: Device/Register Access...... Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
SCC  ACCESS: Device/Register Access...... Running ---> PASSED
```

If any part of the test fails, then the display appears as follows:

```
SCC  ACCESS: Device/Register Access...... Running ---> FAILED

SCC/ACCESS Test Failure Data:
(error message)
```

Refer to the section *SCC Error Messages* for a list of the error messages and their meaning.

BAUDS - Baud Rates

Command Input

```
PPCx-Diag>scc bauds
```

Description

This test transmits 256 characters at various baud rates. The data is received and compared. If any protocol errors are created or the data is not correct when received, the test failed.

The bauds tested are:

1200	9600
2400	19200
4800	38400

Note Because of the design of the Z85230, when internal loopback testing is performed, data is still transmitted out of the device on the TxD line. This may cause problems with terminals, modem, printers, and any other device attached.

Response/Messages

After the command has been issued, the following line is printed:

```
SCC  BAUDS: Baud Rates.................. Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
SCC  BAUDS: Baud Rates..............Running ---> PASSED
```

If any part of the test fails, then the display appears as follows:

```
SCC  BAUDS: Baud Rates..............Running ---> FAILED

SCC/BAUDS Test Failure Data:
(error message)
```

Refer to the section *SCC Error Messages* for a list of the error messages and their meaning.

DMA - Receive/Transmit DMA

Command Input

```
PPCx-Diag>SCC DMA
```

Description

This test will verify that the SCC can transmit and receive via internal loopback, a 256-byte block of data that consists of all numbers between 0x00 and 0xFF.

The test will be performed under DMA control. A match of the contents of the transmit and receive buffers will be verified. Due to the nature of DMA, use of the ISA Bridge IC is also necessary.

Note Because of the design of the Z85230, when DMA testing is performed, data is still transmitted out of the device on the TxD line. This may cause problems with terminals, modem, printers, and any other device attached.

Response/Messages

After the command has been issued, the following line is printed:

```
SCC  DMA: DMA Test..................... Running --->
```

If all parts of the test are completed correctly, then the test passes.

```
SCC  DMA: DMA Test.................Running ---> PASSED
```

If all parts of the test are not completed correctly, then the test does not pass. The receiver buffer may not be filled with the data before terminal count. This results in either one or both controllers giving error messages:

```
SCC  DMA: DMA Test.................Running ---> FAILED

SCC/DMA Test Failure Data:
(error message)
```

In the first case, the Serial Port 3 Receiver (Z85230 Port A Rx, ISA DMA Controller 1 and Channel 0) has reached terminal count before receiving all the data. In the second case, the Serial Port 4 Receiver (Z85230 Port B Rx, ISA DMA Controller 2 and Channel 5) has reached terminal count before receiving all the data.

If the receiver buffer is filled with data before terminal count, it may still be an incorrect match to the data transmitted. This results in an error:

```
SCC  DMA: DMA Test..................Running ---> FAILED

SCC/DMA Test Failure Data:
(error message)
```

The Verify Counter used in this error message gives the amount of data transferred correctly. The values in the two buffers that did not match are shown also.

Refer to the section *SCC Error Messages* for a list of the error messages and their meaning.

ELPBCK - External Loopback

Command Input

```
PPCx-Diag>SCC ELPBCK
```

Description

This test transmits 256 characters at 38400 baud. The data is received and compared. If any protocol errors are created or the data is not correct when received, the test fails.

This test *does* require an external loopback connector to be installed. For this test, the following connections need to be made in the loopback connector:

TxD connected to **RxD**

Response/Messages

After the command has been issued, the following line is printed:

```
SCC ELPBCK: External Loopback..... Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
SCC  ELPBCK: External Loopback.......Running ---> PASSED
```

If any part of the test fails, then the display appears as follows:

```
SCC  ELPBCK: External Loopback.......Running ---> FAILED

SCC/ELPBCK Test Failure Data:
(error message)
```

Refer to the section *SCC Error Messages* for a list of the error messages and their meaning.

ILPBCK - Internal Loopback

Command Input

```
PPCx-Diag>SCC ILPBCK
```

Description

This test transmits 256 characters at 38400 baud. The data is received and compared. If any protocol errors are created or the data is not correct when received, the test failed.

Note Because of the design of the Z85230, when internal loopback testing is performed, data is still transmitted out of the device on the TxD line. This may cause problems with terminals, modem, printers, and any other device attached.

Response/Messages

After the command has been issued, the following line is printed:

```
SCC  ILPBCK: Internal Loopback.......... Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
SCC  ILPBCK: Internal Loopback......Running ---> PASSED
```

If any part of the test fails, then the display appears as follows:

```
SCC  ILPBCK: Internal Loopback......Running ---> FAILED

SCC/ILPBCK Test Failure Data:
(error message)
```

Refer to the section *SCC Error Messages* for a list of the error messages and their meaning.

IRQ - Interrupt Request

Command Input

```
PPCx-Diag>scc irq
```

Description

This test verifies that the Z85230 can generate interrupts to the local processor. This is done using the baud rate zero counter interrupt from the Z85230.

Response/Messages

After the command has been issued, the following line is printed:

```
SCC  IRQ: Interrupt Request.............. Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
SCC  IRQ: Interrupt Request.........Running ---> PASSED
```

If any part of the test fails, then the display appears as follows:

```
SCC  IRQ: Interrupt Request.........Running ---> FAILED

SCC/IRQ Test Failure Data:
(error message)
```

Refer to the section *SCC Error Messages* for a list of the error messages and their meaning.

MDMC - Modem Control

Command Input

```
PPCx-Diag>SCC MDMC
```

Description

This test verifies that the Z85230 can negate/assert selected modem control lines and that the appropriate input control functions properly.

This test *does* require an external loopback connector to be installed. For this test the following connections need to be made in the loopback connector:

DTR connected to **DCD**

RTS connected to **CTS** and **DSR**

Note that DTR is asserted through the Z8536, not the Z85230, in this test.

Response/Messages

After the command has been issued, the following line is printed:

```
SCC  MDMC: Modem Control.............. Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
SCC  MDMC: Modem Control..........Running ---> PASSED
```

If any part of the test fails, then the display appears as follows:

```
SCC  MDMC: Modem Control..........Running ---> FAILED

SCC/MDMC Test Failure Data:
(error message)
```

Refer to the section *SCC Error Messages* for a list of the error messages and their meaning.

SCC Error Messages

The SCC test group error messages generally take the following form:

```
SCC   BAUDS: Baud Rates..................... Running ---> FAILED

SCC/BAUDS Test Failure Data:
Transmit/Receive Character Miscompare Error:
Expected =55, Actual =5F
SCC Base Address =80000840, Channel =01
Baud Rate =1200
```

The first line of the failure identifies what type of failure occurred. The following line provides additional information about the failure.

Table 3-22. SCC Error Messages

Error Message	Symptom or Cause
`Exception, Vector` *xx*	An unexpected exception occurred.
`Data Miscompare Error:` `Address =`*xxxxxxxx*`, Register Index =`*xx* `Expected =`*xx*`, actual =`*xx*	Data write does not match data read.
`Exception Vector Serviced Error:` `Expected =`*xxx*`, Actual =`*xxx* `Interrupt Level =`*x* `SCC Base Address =`*xxxxxxxx*`, Channel =`*xx*	Incorrect vector taken or provided during interrupt service.
`Exception failed to occur, Vector Expected =`*xxx* `Interrupt Level =`*X* `SCC Base Address =`*xxxxxxxx*`, Channel =`*xx*	During Interrupt testing, no interrupt was generated or received.
`Interrupt Not (Stuck-At) Error:` `Vector =`*xxx*`, Interrupt Level =`*x* `SCC Base Address =`*xxxxxxxx*`, Channel =`*xx*	A preexisting interrupt could not be cleared.
`SCC Receiver Error: Status =`*XXX* `SCC Base Address =`*xxxxxxxx*`, Channel =`*xx* `Baud Rate =`*xxxx* *<Additional error info>*	Data transmission error occurred. Possible error are: framing, parity, or data overrun

Table 3-22. SCC Error Messages (Continued)

Error Message	Symptom or Cause
SCC Receiver Error: Status =*xx* Break Sequence detected in the RXD stream SCC Base Address =*xxxxxxxx*, Channel =*xx* Baud Rate =*xxxx*	An unexpected break was received during testing.
Transmit/Receive Character Miscompare Error: Expected =*xx*, Actual =*xx* SCC Base Address =*xxxxxxxx*, Channel =*xx* Baud Rate =*xxxx*	Data transmitted does not match data received.
Transmitter Ready Time-Out SCC Base Address =*xxxxxxxx*, Channel =*xx* Baud Rate =*xxxx*	The selected ports transmitter never indicated ready to transmit.
Receiver Ready (Character Available) Time-Out SCC Base Address =*xxxxxxxx*, Channel =*xx* Baud Rate =*xxxx*	The receiver has not received a character in the allotted time.
DTR assertion failed to assert DCD SCC Base Address =*xxxxxxxx*, Channel =*xx*	When DTR was driven, DCD did not follow.
DTR negation failed to negate DCD SCC Base Address =*xxxxxxxx*, Channel =*xx*	
RTS assertion failed to assert CTS SCC Base Address =*xxxxxxxx*, Channel =*xx*	When RTS was driven, CTS did not follow.
RTS negation failed to negate CTS SCC Base Address =*xxxxxxxx*, Channel =*xx*	
SCC DMA #1 Error: Time-out before Terminal Count SCC Base Address =*xxxxxxxx*	The receiver (controller #1) did not receive all the data before TC.
SCC DMA #2 Error: Time-out before Terminal Count SCC Base Address =*xxxxxxxx*	The receiver (controller #2) did not receive all the data before TC.
SCC DMA Error: Data Miscompare Error SCC Base Address =*xxxxxxxx*, SCC Channel =*xx* Verify Counter =*xx* xmit buffer =*xxxxxxxx*, receive buffer =*xxxxxxxx*	Data transmitted does not match data received.

VGA54XX - Video Diagnostics Tests

These sections describe the individual Video Graphics Array (VGA) tests. These tests are not available on PowerPC boards that don't have a VGA device on-board.

The firmware now provides support for testing of multiple VGA controllers within PCI configuration space. This means that the VGA diagnostics can now be run on multiple Cirrus Logic VGA 54XX Controllers. This is "only" true for any firmware supported VGA devices.

Examples of where the VGA tests run include:

1. On a PowerPC board that has one (1) Cirrus Logic VGA54XX device on the board and one Cirrus Logic VGA54XX PMC/PCI card attached to the board.
2. On a PowerPC board that has one (1) Cirrus Logic VGA54XX device on the board and a Cirrus Logic VGA54XX PMC card attached to the PMC carrier plugged into the backplane of the chassis.

Entering **VGA54XX** without parameters causes all **VGA** tests to execute in the order shown in the table below.

To run an individual test, add that test name to the **VGA54XX** command.

The individual tests are described in alphabetical order on the following pages.

Table 3-23. VGA543X Test Group

Name	Description
ATTR	Attribute Registers
CRTC	CRT Controller Registers
DSTATE	DAC State Register
EXTN	Extended Registers
GRPH	Graphics Controller
MISC	Miscellaneous Register

Table 3-23. VGA543X Test Group (Continued)

Name	Description
PAL	Color Palette
PCI	PCI Header Verification
PELM	Pixel Mask Register
SEQR	Sequencer Registers
VRAM	Video Memory
BLT	Bit Blitter

ATTR - Attribute Register

Command Input

```
PPCx-Diag>VGA54XX ATTR
```

Description

This test verifies the correct operation of the VGA Attribute Registers. The test proceeds as follows:

1. Each Attribute Register is initialized with one of 256 possible values, with reserved bits being masked off to a value of zero.
2. The Attribute Register is read back to verify that the data that was written to the register in step 1 was written correctly.

Response/Messages

After the command has been issued, the following line is printed:

```
VGA54XX  ATTR: Attribute Registers........Running ->
```

If all parts of the test are completed correctly, then the test passes:

```
VGA54XX  ATTR: Attribute Registers...Running -> PASSED
```

If the test fails, then the display appears as follows:

```
VGA54XX  ATTR: Attribute Registers...Running -> FAILED

VGA54XX/ATTR Test Failure Data:
Read Register: _________ Index register: ________
Value Read: ________ Expected: ________
```

BLT - Bit Blitter

Command Input

```
PPCx-Diag>vga543x blt
```

Description

This test verifies that the Bit BLT of the Cirrus Logic CL-54XX chip is functioning correctly by invoking a blitter operation to copy a block of data from system memory to video DRAM, then invoking a blitter operation to copy the block from one area in video DRAM to another and then finally a blitter operation to copy the block of data back into system memory. The contents of the original block of system memory are compared to that of the destination block. The test fails if the block which was blittered does not match the original block.

Response/Messages

After the command has been issued, the following line is printed:

```
VGA54xx BLT: Cirrus vga54xx BitBLT........Running ->
```

If all parts of the test are completed correctly, then the test passes:

```
VGA54xx BLT: Cirrus vga54xx BitBLT...Running -> PASSED
```

If any part of the test fails, then the display appears as follows:

```
VGA54xx BLT: Cirrus vga54xx BitBLT ..Running -> FAILED

VGA54xx/BLT Test Failure Data:
Memory compare error in BitBLT test

Source       byte at 0x ______,is 0x __ .

Destination  byte at 0x ______,is 0x __ .
```

CRTC - CRT Controller Registers

Command Input

```
PPCx-Diag>VGA54XX CRTC
```

Description

This test verifies the correct operation of the VGA CRT Controller Registers. The test proceeds as follows:

1. Each CRT Controller Register is initialized with one of 256 possible values, with reserved bits being masked off to a value of zero.
2. The CRT Controller Register is read back to verify that the data that was written to the register in step 1 was written correctly.

Response/Messages

After the command has been issued, the following line is printed:

```
VGA54XX CRTC:CRT Controller Registers....Running -->
```

If all parts of the test are completed correctly, then the test passes:

```
VGA54XX CRTC:CRT Controller Registers...Running --> PASSED
```

If the test fails, then the display appears as follows:

```
VGA54XX CRTC:CRT Controller Registers..Running --> FAILED

VGA54XX/CRTC Test Failure Data:
Data Register: ________ Index: _____
Value Read: ________ Expected: _______
```

DSTATE - DAC State Register

Command Input

```
PPCx-Diag>vga54xx dstate
```

Description

Test the DAC State Register. This test verifies that the VGA controller changes when set to the various mode states.

Response/Messages

After the command has been issued, the following line is printed:

```
VGA54XX  DSTATE: DAC State Registers......Running ->
```

If all parts of the test are completed correctly, then the test passes:

```
VGA54XX  DSTATE: DAC State Registers..Running -> PASSED
```

If the test fails, then the display appears as follows:

```
VGA54XX  DSTATE: DAC State Registers..Running -> FAILED

VGA54XX/DSTATE Test Failure Data:
Unexpected state read from DAC State Reg
```

Depending upon which mode failed, then the display appears as follows:

```
Expected read mode (11B) Found: _____
```

Or:

```
Expected write mode (11B) Found: _____
```

EXTN - Extended Registers

Command Input

```
PPCx-Diag>VGA54XX EXTN
```

Description

This test verifies that the Extended Sequencer, Graphics, CRT Controller, and Pel Mask Registers are correctly functioning. Each possible pattern for each of the registers is used with reserved bits being masked to a value of zero.

1. Each extended register is initialized with one of 256 possible values, with reserved bits being masked off to a value of zero.
2. The extended register is read back to verify that the data that was written to the register in step 1 was written correctly.

Response/Messages

After the command has been issued, the following line is printed:

```
VGA54XX  EXTN: Extended Registers........Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
VGA54XX  EXTN: Extended Registers..Running ---> PASSED
```

If the test fails, then the display appears as follows:

```
VGA54XX  EXTN: Extended Registers...Running ---> FAILED

VGA54XX/EXTN Test Failure Data:
Read register: _____ Index Register: _____ loaded with _____
Value read: _________ Expected: _________
```

GRPH - Graphics Controller Registers

Command Input

```
PPCx-Diag>VGA54XX GRPH
```

Description

This test verifies the correct operation of the VGA Graphics Controller Registers. The test proceeds as follows:

1. Each Graphics Controller Register is initialized with one of 256 possible values, with reserved bits being masked off to a value of zero.
2. The Graphics Controller Register is read back to verify that the data that was written to the register in step 1 was written correctly.

Response/Messages

After the command has been issued, the following line is printed:

```
VGA54XX GRPH: Graphics Control Registers ...Running ->
```

If all parts of the test are completed correctly, then the test passes:

```
VGA54XX GRPH: Graphics Control Registers....Running -> PASSED
```

If the test fails, then the display appears as follows:

```
VGA54XX GRPH: Graphics Control Registers ...Running -> FAILED

VGA54XX/GRPH Test Failure Data:
(error message)
```

If the error is in one of the index registers, then *(error message)* is:

```
Index register: _____
Value read: _____ Expected: _____
```

Otherwise, *(error message)* is:

```
Data register: _____
Value read: _____ Expected: _____
```

MISC - Miscellaneous Register

Command Input

```
PPCx-Diag>VGA54XX MISC
```

Description

This test verifies the correct operation of the VGA Miscellaneous Control Register. The test proceeds as follows:

1. Each Graphics Controller Register is initialized with one of 256 possible values, with reserved bits being masked off to a value of zero.
2. The Graphics Controller Register is read back to verify that the data that was written to the register in step 1 was written correctly.

Response/Messages

After the command has been issued, the following line is printed:

```
VGA54XX  MISC: Miscellaneous Registers....Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
VGA54XX  MISC: Miscellaneous Registers....Running ---> PASSED
```

If the test fails, then the display appears as follows:

```
VGA54XX  MISC: Miscellaneous Registers....Running ---> FAILED

VGA54XX/MISC Test Failure Data:
Read Register: _____
Write Register: _____
Value read: ________ Expected: ________
```

PAL - Color Palette

Command Input

```
PPCx-Diag>VGA54XX PAL
```

Description

This test verifies the correct operation of the 256 possible color palette entries. Each palette red, green, and blue entry is verified by checking for the setting of all bits to 1s and 0s.

Response/Messages

After the command has been issued, the following line is printed:

```
VGA54XX  PAL: Palette Register.........Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
VGA54XX  PAL: Palette Register....Running ---> PASSED
```

If the test fails, then the display appears as follows:

```
VGA54XX  PAL: Palette Register....Running ---> FAILED

VGA54XX/PAL Test Failure Data:
Palette index: _____
Value read: _________  red: _________ green: _____ blue: _____
```

PCI - PCI Header Verification

Command Input

```
PPCx-Diag>vga54XX pci
```

Description

This is the PCI header verification test, the purpose of which is to verify that the system has a supported Cirrus Logic graphics controller. The test proceeds as follows:

- Searches the PCI bus for the Cirrus Logic controller by looking at the chip identification register. If a supported Cirrus Logic controller is found, the test passes.

Response/Messages

After the command has been issued, the following line is printed:

```
VGA54XX  PCI: Cirrus vga54xx PCI Access....Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
VGA54XX  PCI: Cirrus vga543x PCI Access ...Running ---> PASSED
```

If the test fails, then the display appears as follows:

```
VGA54XX  PCI: Cirrus vga54xx PCI Access ...Running ---> FAILED

VGA54XX/PCI Test Failure Data:
PCI register test failure
```

PELM - Pixel Mask Register

Command Input

```
PPCx-Diag>VGA543X PELM
```

Description

This test verifies the correct operation of the VGA Pixel Mask Register. The test proceeds as follows:

1. The Pixel Mask Register is initialized with one of 256 possible values, with reserved bits being masked off to a value of zero.
2. The Pixel Mask Register is read back to verify that the data that was written to the register in step 1 was written correctly.

Response/Messages

After the command has been issued, the following line is printed:

```
VGA54XX  PELM: Pixel Mask Register........Running ->
```

If all parts of the test are completed correctly, then the test passes:

```
VGA54XX  PELM: Pixel Mask Register...Running -> PASSED
```

If any part of the test fails, then the display appears as follows:

```
VGA54XX  PELM: Pixel Mask Register...Running -> FAILED

VGA54XX/PELM Test Failure Data:
Value read: ________  Expected: ________
```

SEQR - Sequencer Registers

Command Input

```
PPCx-Diag>VGA54XX SEQR
```

Description

This test verifies the correct operation of the VGA Sequencer Controller Registers. The test proceeds as follows:

1. Each Sequencer Controller Register is initialized with one of 256 possible values, with reserved bits being masked off to a value of zero.
2. The Sequencer Controller Register is read back to verify that the data that was written to the register in step 1 was written correctly.

Response/Messages

After the command has been issued, the following line is printed:

```
VGA54XX  SEQR: Sequencer Registers.......Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
VGA54XX  SEQR: Sequencer Registers....Running ---> PASSED
```

If the test fails, then the display appears as follows:

```
VGA54XX  SEQR: Sequencer Registers...Running ---> FAILED

VGA54XX/SEQR Test Failure Data:
(error message)

If the error is in one of the index registers, then (error
message) is:

Index register: _____
Value read: _____ Expected: _____
```

Otherwise, *(error message)* is:

```
Data register: _____
Value read: _____ Expected: _____
```

VRAM - Video Memory

Command Input

```
PPCx-Diag>VGA54XX VRAM
```

Description

This test verifies the first 1 megabyte of video RAM. Each location is written as a 16-bit value with alternating 1s and 0s.

Response/Messages

After the command has been issued, the following line is printed:

```
VGA54XX  VRAM: Cirrus vga54Xx VRAM Test...Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
VGA54XX  VRAM: Cirrus vga54Xx VRAM.Test...Running ---> PASSED
```

If any part of the test fails, then the display appears as follows:

```
VGA54XX  VRAM: Cirrus vga54Xx VRAM.Test...Running ---> FAILED

VGA54XX/VRAM Test Failure Data:
Data Error: Expected: = 0x____ Actual: =0x_____
Address: 0x_____, offset = ____
```

VME2 - VME Interface ASIC Tests

This section lists the individual VMEchip2 tests, but does not describe them. These tests are available only on the MVME160*x* PowerPC boards. For all other PowerPC boards, these tests are bypassed.

Entering **VME2** without parameters causes all **VME2** tests to execute in the order shown in the table below.

To run an individual test, add that test name to the **VME2** command.

Table 3-24. VME2 Test Group

Name	Description
REGA	Register Access
REGB	Register Walking Bit
TMRA	Tick Timer 1 Increment
TMRB	Tick Timer 2 Increment
TMRC	Prescaler Clock Adjust
TMRD	Tick Timer 1 No Clear On Compare
TMRE	Tick Timer 2 No Clear On Compare
TMRF	Tick Timer 1 Clear On Compare
TMRG	Tick Timer 2 Clear On Compare
TMRH	Tick Timer 1 Overflow Counter
TMRI	Tick Timer 2 Overflow Counter
TMRJ	Watchdog Timer Counter
SWIA	Software Interrupts (Polled Mode)
SWIB	Software Interrupts (Processor Interrupt Mode)
SWIC	Software Interrupts Priority

VME3- Universe VME to PCI Bridge Tests

These sections describe the individual tests which can be used to verify operation of the Universe (tm) and Universe II (tm) VME to PCI Bridge chips.

Entering **VME3** without parameters causes all **VME3** tests to run in the order shown in the table below, except as noted.

To run an individual test, add that test name to the **VME3** command. The individual tests are described in alphabetical order on the following pages.

Table 3-25. VME3 Test Group

Name	Description
REGR	Register Read
REGW	Register walking bits (write/read)

The PPCBUG Diagnostics engine includes a test init function, which is run prior to each of the tests in the test group. For the Universe diagnostics, several things will be tested during test init.

The init phase testing verifies that there is agreement between the board's Base Module Feature Register (BMFR) and the actual installation of the board's Universe chip. If the VME Present bit in the BMFR indicates the Universe is not installed, all post-init phase Universe testing will be bypassed. Whether this is an error condition or not depends on the following sets of conditions. In order to establish whether the Universe is actually installed, the Universe's PCI Configuration Space Vendor ID value (at offset 2) is read. If the Vendor ID indicates that the Universe is installed, but the VME Present bit indicates it should not be, an error will be logged and the currently-running test will exit. If the Vendor ID cannot be read and the VME Present bit indicates the device should be installed, an error will be logged and the currently-running test will exit.

There are currently no active CF parameters for the Universe Tests.

REGR - Register Read

Command Input

```
PPCx-Diag>VME3 REGR
```

Description

This test reads all registers in the Universe chip. The 4 Kilobyte UCSR space is read as 32-bit, 16-bit, and 8-bit values. No check will be made as to the actual contents of the registers. An error in this test would be reported as an unsolicited exception.

Response/Messages

After the command has been issued, the following line is printed:

```
VME3 regr:.............................Running ->
```

If all parts of the test are completed correctly, then the test passes:

```
VME3 regr: Register Read .............Running -> PASSED
```

If any part of the test fails, then the display appears as follows:

```
VME3 regr: Register Read .............Running -> FAILED
```

REGW - Register Write/Read

Command Input

```
PPCx-Diag>VME3 regw
```

Description

This test performs a “read / modify / read / restore / verify” sequence to selected registers in the Universe chip. The registers are part of the 4 Kilobyte UCSR, and are accessed as PCI Memory space. The values written are chosen in order to verify as many device address and data lines as is safely possible. If the registers contain the expected value(s) at the second read and the final verify step, then the test will pass. The test will fail if either the modified value could not be subsequently read, or if the restoration of the original value could not be accomplished.

Response/Messages

After the command has been issued, the following line is printed:

```
VME3 regw: Register Write/Read ............Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
VME3 regw: Register Write/Read :......Running ---> PASSED
```

If any part of the test fails, then the display appears as follows:

```
VME3 regw: Register Write/Read :......Running ---> FAILED

VME3 regw Test Failure Data:
(error message)
```

Refer to the section *VME3 Error Messages* for a list of the error messages and their meaning.

VME3 Error Messages

The VME3 test group error messages generally take the following form:

```
VME3 regr: Register Read:.............Running ---> FAILED

VME3 regr Test Failure Data:
Detail of Failure
```

Table 3-26. VME3 Error Messages

Error Message	Notes
Universe Vendor ID seen in config space, but VME Present bit indicates chip isn't installed. Address =nnnnnnnn, Expected =ddX, Actual =aaX	the Base Module Feature Register contents are shown
Universe Vendor ID not seen in config space, but VME Present bit indicates chip is installed. Address =nnnnnnnn, Expected =eeX, Actual =aaX	the Base Module Feature Register contents are shown
Could not write test value to Universe register. Address =nnnnnnnn, Expected =eeeeeeeeX, Actual =aaaaaaaaX	values are in Hex
Couldn't restore original contents to Universe register. Address =nnnnnnnn, Expected =eeeeeeeeX, Actual =aaaaaaaaX	values are in Hex
Unable to restore original content to Universe register. Address =nnnnnnnn, Expected =eeeeeeeeX, Actual =aaaaaaaaX	values are in Hex
Write Err during restore of original Universe register. Address =nnnnnnnn, Expected =eeeeeeeeX, Actual =aaaaaaaaX	values are in Hex
Couldn't correctly modify contents of Universe register. Address =nnnnnnnn, Expected =eeeeeeeeX, Actual =aaaaaaaaX	values are in Hex

Z8536 - Counter/Timer Tests

This section describes the individual Z8536 CIO counter/timer tests. These tests are not available on the MVME230*x* PowerPC boards.

Entering **Z8536** without parameters causes all **Z8536** tests to execute in the order shown in the following table.

To run an individual test, add that test name to the **Z8536** command.

The individual tests are described in alphabetical order on the following pages.

Table 3-27. Z8536 Test Group

Name	Description
CNT	Counter
LNK	Linked Counter
IRQ	Interrupt
REG	Register

CNT - Counter

Command Input

```
PPCx-Diag>z8536 cnt
```

Description

This test verifies the functionality of the counter in the Z8536 chip.

Response/Messages

After the command has been issued, the following line is printed:

```
Z8536  CNT: Counter......................... Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
Z8536  CNT: Counter......................... Running ---> PASSED
```

If any failures occur, the following is displayed (more descriptive text then follows):

```
Z8536  CNT: Counter......................... Running ---> FAILED

Z8536/CNT Test Failure Data:
(error message)
```

If the test fails because one of the counters does not generate an interrupt request in the correct time frame, the following message is displayed:

```
z8536 Timer A/B/C, No Terminal Count
Counter has not generated a Terminal Count IRQ in allotted time
```

IRQ - Interrupt

Command Input

```
PPCx-Diag>Z8536 IRQ
```

Description

This test verifies that the Z8536 can generate interrupts.

Response/Messages

After the command has been issued, the following line is printed:

```
Z8536 IRQ: Interrupt.....................Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
Z8536 IRQ: Interrupt.................Running ---> PASSED
```

If any failures occur, the following is displayed (more descriptive text then follows):

```
Z8536 IRQ: Interrupt.................Running ---> FAILED

Z8536/CNT Test Failure Data:
(error message)
```

If the test fails because an interrupt request from the Z8536 is pending, after masking the Z8536 interrupt in the IEN register, the following is displayed:

```
Unexpected z8536 IRQ pending
Address =________, Expected =________, Actual =________
```

This test makes use of the Z8536 counter to generate the test interrupt. If after running the counters to “terminal count”, an interrupt has not been requested by the Z8536, the following message is displayed:

```
z8536 IRQ not pending in IST register
Address =________, Expected =________, Actual =________
```

LNK - Linked Counter

Command Input

```
PPCx-Diag>Z8536 LNK
```

Description

This test verifies the functionality of the timers in the Z8536. Counter 1 output is linked to counter 2 input. This test does not check timer accuracy.

Response/Messages

After the command has been issued, the following line is printed:

```
Z8536 LNK: Linked Counter.................. Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
Z8536 LNK: Linked Counter.............Running ---> PASSED
```

If any failures occur, the following is displayed (more descriptive text then follows):

```
Z8536 LNK: Linked Counter.............Running ---> FAILED

Z8536/LNK Test Failure Data:
(error message)
```

If the test fails because “terminal count” does not generate an interrupt request within a reasonable amount of time, the following message is displayed:

```
No Terminal Count occurred with in time limit
```

REG - Register

Command Input

```
PPCx-Diag>z8536 reg
```

Description

This test verifies that all of the Z8536 registers can be written and read. Data patterns verify that every read/write bit can be modified.

Response/Messages

After the command has been issued, the following line is printed:

```
Z8536 REG: Register.....................Running --->
```

If all parts of the test are completed correctly, then the test passes:

```
Z8536 REG: Register.................Running ---> PASSED
```

If any failures occur, the following is displayed (more descriptive text then follows):

```
Z8536 REG: Register.................Running ---> FAILED

Z8536/REG Test Failure Data:
(error message)
```

If the test fails because the pattern written doesn't match the data read back from the Z8536 register, the following message is displayed:

```
Register xxx Miscompare Error:Address =____,Expected =_,Actual =_
```

Related Documentation A

Motorola Computer Group Documents

The Motorola publications listed below are referenced in this manual. You can obtain paper or electronic copies of Motorola Computer Group publications by:

- Contacting your local Motorola sales office
- Visiting Motorola Computer Group's World Wide Web literature site, http://www.motorola.com/computer/literature

.

Table A-1. Motorola Computer Group Documents

Document Title	Publication Number
MCP750 CompactPCI Single Board Computer Installation and Use*	MCP750A/IH1
MCP750 CompactPCI Single Board Computer Programmer's Reference Guide	MCP750A/PG
MVME2100 Single Board Computer Installation and Use	V2100A/IH
MVME2100 Single Board Computer Programmer's Reference Guide	V2100A/PG
MVME2600 Series Single Board Computer Installation and Use	V2600A/IH
MVME2600 Series Single Board Computer Programmer's Reference Guide	V2600A/PG
MVME3600/4600 Series VME Processor Module Installation and Use	V36V46A/IH
MVME3600/4600 Series VME Processor Module Programmer's Reference Guide	V36V46A/PG
MVME2300 VME Processor Modules Installation and Use	V2300A/IH
MVME2300 VME Processor Modules Programmer's Reference Guide	V2300A/PG
MVME5100 Single Board Computer Installation and Use	V5100A/IH
MVME5100 Single Board Computer Programmer's Reference Guide	V5100A/PG

Table A-1. Motorola Computer Group Documents (Continued)

Document Title	Publication Number
MTX Embedded ATX Motherboard Installation and Use	MTXA/IH
MTX Embedded ATX Motherboard Programmer's Reference Guide	MTXA/PG
PMCSpan PMC Adapter Carrier Module Installation and Use	PMCSPANA/IH
PPCBug Firmware Package User's Manual (Parts 1 and 2)	PPCBUGA1/UM PPCBUGA2/UM
TMCP700 Transition Module Installation and Use	TMCP700A/IH1
MVME712M Transition Module and P2 Adapter Board Installation and Use	VME712MA/IH
MVME761 Transition Module Installation and Use	VME761A/IH

Microprocessor and Controller Documents

For additional information, refer to the following table for manufacturers' data sheets or user's manuals. As an additional help, a source for the listed document is also provided. Please note that in many cases, the information is preliminary and the revision levels of the documents are subject to change without notice..

Table A-2. Microprocessor and Controller Documents

Document Title and Source	Publication Number
PowerPC 603™ RISC Microprocessor Technical Summary Literature Distribution Center for Motorola Telephone: (800) 441-2447 FAX: (602) 994-6430 or (303) 675-2150 E-mail: ldcformotorola@hibbertco.com	MPC603/D
PowerPC 603™ RISC Microprocessor User's Manual Literature Distribution Center for Motorola Telephone: (800) 441-2447 FAX: (602) 994-6430 or (303) 675-2150 E-mail: ldcformotorola@hibbertco.com OR IBM Microelectronics Mail Stop A25/862-1 PowerPC Marketing 1000 River Street Essex Junction, Vermont 05452-4299 Telephone: 1-800-PowerPC Telephone: 1-800-769-3772 FAX: 1-800-POWERfax FAX: 1-800-769-3732	MPC603UM/AD MPR603UMU-01
MPC750™ RISC Microprocessor User's Manual Motorola Literature Distribution Center Telephone: (800) 441-2447 or (303) 675-2140 FAX: (303) 675-2150 E-mail: ldcformotorola@hibbertco.com INTERNET: http://motorola.com/sps INTERNET: http://www.mot.com/PowerPC	MPC750UM/AD

Table A-2. Microprocessor and Controller Documents (Continued)

Document Title and Source	Publication Number
PowerPC 604™ RISC Microprocessor User's Manual Literature Distribution Center for Motorola Telephone: (800) 441-2447 FAX: (602) 994-6430 or (303) 675-2150 E-mail: ldcformotorola@hibbertco.com OR IBM Microelectronics Mail Stop A25/862-1 PowerPC Marketing 1000 River Street Essex Junction, Vermont 05452-4299 Telephone: 1-800-PowerPC Telephone: 1-800-769-3772 FAX: 1-800-POWERfax FAX: 1-800-769-3732	MPC604UM/AD MPR604UMU-01
PowerPC™ Microprocessor Family: The Programming Environments Motorola Literature Distribution Center Telephone: (800) 441-2447 FAX: (602) 994-6430 or (303) 675-2150 E-mail: ldcformotorola@hibbertco.com OR IBM Microelectronics Mail Stop A25/862-1 PowerPC Marketing 1000 River Street Essex Junction, Vermont 05452-4299 Telephone: 1-800-PowerPC Telephone: 1-800-769-3772 FAX: 1-800-POWERfax FAX: 1-800-769-3732	MPCFPE/AD MPRPPCFPE-01
MPC2604GA Integrated Secondary Cache for PowerPC Microprocessors Data Sheets Literature Distribution Center for Motorola Telephone: (800) 441-2447 FAX: (602) 994-6430 or (303) 675-2150 E-mail: ldcformotorola@hibbertco.com	MPC2604GA

Table A-2. Microprocessor and Controller Documents (Continued)

Document Title and Source	Publication Number
Alpine™ VGA Family - CL-GD543X/'4X Technical Reference Manual Fourth Edition Cirrus Logic, Inc. (or nearest Sales Office) 3100 West Warren Avenue Fremont, California 94538-6423 Telephone: (510) 623-8300 FAX: (510) 226-2180	385439
DECchip 21040 Ethernet LAN Controller for PCI Hardware Reference Manual Digital Equipment Corporation Maynard, Massachusetts DECchip Information Line Telephone (United States and Canada): 1-800-332-2717 TTY (United States only): 1-800-332-2515 Telephone (outside North America): +1-508-568-6868	EC-N0752-72
DECchip 21140 PCI Fast Ethernet LAN Controller Hardware Reference Manual Digital Equipment Corporation Maynard, Massachusetts DECchip Information Line Telephone (United States and Canada): 1-800-332-2717 TTY (United States only): 1-800-332-2515 Telephone (outside North America): +1-508-568-6868	EC-QC0CA-TE
PC87303VUL (Super I/O™ Sidewinder Lite) Floppy Disk Controller, Keyboard Controller, Real-Time Clock, Dual UARTs, IEEE 1284 Parallel Port, and IDE Interface National Semiconductor Corporation Customer Support Center (or nearest Sales Office) 2900 Semiconductor Drive P.O. Box 58090 Santa Clara, California 95052-8090 Telephone: 1-800-272-9959	PC87303VUL

Table A-2. Microprocessor and Controller Documents (Continued)

Document Title and Source	Publication Number
PC87307VUL (Super I/O™ Enhanced Sidewinder Lite) Floppy Disk Controller,, Keyboard Controller, Real-Time Clock, Dual UARTs, IEEE 1284 Parallel Port, and IDE Interface National Semiconductor Corporation Customer Support Center (or nearest Sales Office) 2900 Semiconductor Drive P.O. Box 58090 Santa Clara, California 95052-8090 Telephone: 1-800-272-9959	PC87307VUL
PC87308VUL (Super I/O™ Enhanced Sidewinder Lite) Floppy Disk Controller, Keyboard Controller, Real-Time Clock, Dual UARTs, IEEE 1284 Parallel Port, and IDE Interface National Semiconductor Corporation Customer Support Center (or nearest Sales Office) 2900 Semiconductor Drive P.O. Box 58090 Santa Clara, California 95052-8090 Telephone: 1-800-272-9959	PC87308VUL
PC16550 UART National Semiconductor Corporation Customer Support Center (or nearest Sales Office) 2900 Semiconductor Drive P.O. Box 58090 Santa Clara, California 95052-8090 Telephone: 1-800-272-9959	PC16550DV
MK48T559 Address/Data Multiplexer 8K x 8 TIMEKEEPER™ SRAM Data Sheet SGS-Thomson Microelectronics Group Faxback (Document-on-Demand) system Carrollton, TX Telephone: (972) 4667-7788	M48T559

Table A-2. Microprocessor and Controller Documents (Continued)

Document Title and Source	Publication Number
SYM 53CXX (was NCR 53C8XX) Family PCI-SCSI I/O Processors Programming Guide Symbios Logic Inc. 1731 Technology Drive, suite 600 San Jose, CA95110 Telephone: (408) 441-1080 Hotline: 1-800-334-5454	T72961II
SCC (Serial Communications Controller) User's Manual (for Z85230 and other Zilog parts) Zilog, Inc. 210 East Hacienda Ave., mail stop C1-0 Campbell, California 95008-6600 Telephone: (408) 370-8016 FAX: (408) 370-8056	DC-8293-02
AMD-645™ Peripheral Bus Controller Data Sheet Advanced Micro Devices, Inc. or VT82C586B PIPC PCI Integrated Peripheral Controller PC97 Compliant PCI-to-ISA Bridge with ACPI, Distributed DMA, Plug and Play, Master Mode PCI-IDE Controller with Ultra DMA-33 USB Controller, Keyboard Controller, and RTC VIA Technologies, Inc. 5020 Brandin Court Fremont, CA 94538 Telephone: (510) 683-3300 FAX: (510) 683-3301	21095A/O VT82C586B
Digital Semiconductor 21154 PCI-to-PCI Bridge Data Sheet Digital Equipment Corporation Maynard, MA Telephone (United States and Canada): 1-800-332-2717 Telephone (Outside North America): +1-508-628-4760	EC-R24JA-TE

Table A-2. Microprocessor and Controller Documents (Continued)

Document Title and Source	Publication Number
Z8536 CIO Counter/Timer and Parallel I/O Unit Product Specification and User's Manual (in Z8000® Family of Products Data Book) Zilog, Inc. 210 East Hacienda Ave., mail stop C1-0 Campbell, California 95008-6600 Telephone: (408) 370-8016 FAX: (408) 370-8056	DC-8319-00
W83C553 Enhanced System I/O Controller with PCI Arbiter (PIB) Winbond Electronics Corporation Winbond Systems Laboratory 2730 Orchard Parkway San Jose, CA 95134 Telephone: 1-408-943-6666 FAX: 1-408-943-6668	W83C553
Universe User Manual Tundra Semiconductor Corporation 603 March Road Kanata, ON K2K 2M5, Canada Telephone: 1-800-267-7231 Telephone: (613) 592-1320 OR 695 High Glen Drive San Jose, California 95133, USA Telephone: (408) 258-3600 FAX: (408) 258-3659	Universe (Part Number 9000000.MD303.01)

Related Specifications

For additional information, refer to the following table for related specifications. As an additional help, a source for the listed document is also provided. Please note that in many cases, the information is preliminary and the revision levels of the documents are subject to change without notice.

Table A-3. Related Specifications

Document Title and Source	Publication Number
ANSI Small Computer System Interface-2 (SCSI-2), Draft Document Global Engineering Documents 15 Inverness Way East Englewood, CO 80112-5704 Telephone: 1-800-854-7179 Telephone: (303) 792-2181	X3.131.1990
Compact PCI Specification PCI Industrial Manufacturers Group (PICMG) 401 Edgewater Pl, Suite 500 Wakefield, MA 01880 Telephone: 781-246-9318 Fax: 781-224-1239	CPCI Rev. 2.1 Dated 9/2/97

Table A-3. Related Specifications (Continued)

Document Title and Source	Publication Number
VME64 Specification VITA (VMEbus International Trade Association) 7825 E. Gelding Drive, Suite 104 Scottsdale, Arizona 85260-3415 Telephone: (602) 951-8866 FAX: (602) 951-0720 **NOTE:** An earlier version of this specification is available as: Versatile Backplane Bus: VMEbus Institute of Electrical and Electronics Engineers, Inc. Publication and Sales Department 345 East 47th Street New York, New York 10017-21633 Telephone: 1-800-678-4333 OR Microprocessor system bus for 1 to 4 byte data Bureau Central de la Commission Electrotechnique Internationale 3, rue de Varembé Geneva, Switzerland	ANSI/VITA 1-1994 ANSI/IEEE Standard 1014-1987 IEC 821 BUS
IEEE - Common Mezzanine Card Specification (CMC) Institute of Electrical and Electronics Engineers, Inc. Publication and Sales Department 345 East 47th Street New York, New York 10017-21633 Telephone: 1-800-678-4333	P1386 Draft 2.0
IEEE - PCI Mezzanine Card Specification (PMC) Institute of Electrical and Electronics Engineers, Inc. Publication and Sales Department 345 East 47th Street New York, New York 10017-21633 Telephone: 1-800-678-4333	P1386.1 Draft 2.0

Table A-3. Related Specifications (Continued)

Document Title and Source	Publication Number
Bidirectional Parallel Port Interface Specification Institute of Electrical and Electronics Engineers, Inc. Publication and Sales Department 345 East 47th Street New York, New York 10017-21633 Telephone: 1-800-678-4333	IEEE Standard 1284
Peripheral Component Interconnect (PCI) Local Bus Specification, Revision 2.1 PCI Special Interest Group 2575 NE Kathryn St. #17 Hillsboro, OR 97124 Telephone: (800) 433-5177 (inside the U.S.) or (503) 693-6232 (outside the U.S.) FAX: (503) 693-8344	PCI Local Bus Specification
PowerPC Reference Platform (PRP) Specification, Third Edition, Version 1.0, Volumes I and II International Business Machines Corporation Power Personal Systems Architecture 11400 Burnet Rd. Austin, TX 78758-3493 Document/Specification Ordering Telephone: 1-800-PowerPC Telephone: 1-800-769-3772 Telephone: 708-296-9332	MPR-PPC-RPU-02
ATX Specification Version 2.01 created by Intel Corporation available on the World Wide Web through Teleport Internet Services at URL http://www.teleport.com/~atx/index.htm	
IEEE Standard for Local Area Networks: Carrier Sense Multiple Access with Collision Detection (CSMA/CD) Access Method and Physical Layer Specifications Institute of Electrical and Electronics Engineers, Inc. Publication and Sales Department 345 East 47th Street New York, New York 10017-21633 Telephone: 1-800-678-4333	IEEE 802.3

Table A-3. Related Specifications (Continued)

Document Title and Source	Publication Number
Information Technology - Local and Metropolitan Networks - Part 3: Carrier Sense Multiple Access with Collision Detection (CSMA/CD) Access Method and Physical Layer Specifications Global Engineering Documents 15 Inverness Way East Englewood, CO 80112-5704 Telephone: 1-800-854-7179 Telephone: (303) 792-2181 *(This document can also be obtained through the national standards body of member countries.)*	ISO/IEC 8802-3
Interface Between Data Terminal Equipment and Data Circuit-Terminating Equipment Employing Serial Binary Data Interchange (EIA-232-D) Electronic Industries Association Engineering Department 2001 Eye Street, N.W. Washington, D.C. 20006	ANSI/EIA-232-D Standard

Index

Numerics

53C8xx SCSI I/O Processor Tests - NCR 3-64

A

ACC1 3-66
ACC2 3-68
ACCESS 3-120
Address and Data Parity Error status 3-9
addressing memory 3-95
ADR 3-95, 3-111
ADR (BBRAM Addressing)
    MK48Txx Timekeeping Tests 3-111
AEM 2-2
ALARM 3-113
ALARM interrupt - ALARM 3-113
Alternating Ones/Zeros - ALTS 3-97
ALTS 3-97
Append Error Messages Mode - AEM 2-2
ATA device
    use with EIDE tests 3-29
ATTR 3-132
Attribute Register - ATTR 3-132
Audio Codec Tests - CS4231 3-29
AUI connection 3-8

B

Battery Backed-Up RAM - RAM 3-116
BAUD 3-84
BAUD (Baud Rates)
    Serial I/O Tests 3-84
Baud Rates - BAUD 3-84
Baud Rates - BAUDS 3-121
BAUDS 3-121
BBRAM addressing - ADR 3-111
BEEP 3-32
BINT
    Basic Interrupt Test 3-22
Bit Blitter - BLT 3-133
Bit Toggle - BTOG 3-98
Bit Toggle - ERREN/PERREN/SERREN 3-9
BLT 3-133
BTOG 3-98

C

CEM 2-3
CF 2-3
Chip Initialization - CINIT 3-6
CINIT 3-6
CL1283 - parallel Interface Tests 3-2
Clear (Zero) Error Counters - ZE 2-15
Clear Error Messages - CEM 2-3
CLK 3-114
CLK (Real Time Clock Function)
    RTC Timekeeping Tests 3-114
CLOAD 3-7
CLOAD(Continuous Load) 3-7
CNCTR 3-8
    connector 3-8
CNT 3-150
CODE 3-100
Code Execution/Copy - CODE 3-100
Codec audio tests 3-29
Color Palette - PAL 3-139
command entry examples 1-3
commands, root-level 2-1

configuration parameters 2-3
Connector
    CNCTR 3-8
Continuous Load
    CLOAD 3-7
controller device documents A-3
controller, Cirrus Logic 3-140
conventions used in the manual 4
Counter - CNT 3-150
Counter/Timer Tests
    CNT (Counter) 3-150
    IRQ (Interrupt) 3-151
    LNK (Linked Counter) 3-152
    REG (Register) 3-153
Counter/Timer Tests - Z8536 3-149
CRT Controller Registers - CRTC 3-134
CRTC 3-134
CS4231 - Audio Codec Tests 3-29

D

DAC State Register - DSTATE 3-135
DE 2-4
debugger
    directory 1-2
    prompt 1-2
DEC
    Ethernet Controller Tests (CLOAD) 3-7
    Ethernet Controller Tests (CNCTR) 3-8
    Ethernet Controller Tests (ERREN) 3-9
    Ethernet Controller Tests (ILR) 3-10
    Ethernet Controller Tests (IOR) 3-11
    Ethernet Controller Tests (REGA) 3-12
    Ethernet Controller Tests (SPACK) 3-13
    Ethernet Controller Tests (XREGA) 3-14
DEC error messages 3-15
DEC Ethernet Controller Tests 3-4
DEC21x40 error messages 3-15
DEM 2-4
description of PPCBug 1-1
Device Access - ACC1 3-66
Device/Register Access - ACCESS 3-120
Device/Register Access - REGA 3-88
DFIFO 3-70
diagnostics
    directory 1-2
    facilities 1-2
    firmware 2-1
    prompt 1-2
    test groups 3-1
    utilities 2-1
directories, switching 2-12
Disable Updating - DISUPD 3-56
Display Error Counters - DE 2-4
Display Error Messages - DEM 2-4
Display Pass Count - DP 2-5
Display/Revise Self Test Mask - MASK 2-11
DISUPD 3-56
DMA - Receive/Transmit DMA 3-122
DMA FIFO - DFIFO 3-70
DP 2-5
DSTATE 3-135

E

EEPT
    EEPROM Test 3-23
EIDE
    test requirement 3-29
EIDE test
    CD test limitations 3-29
EIDE tests
    execution parameters 3-30
    intrusiveness 3-29
    preliminary steps 3-30
    types 3-29
ELPBCK 3-124
Enable Updating - ENUPD 3-57
ENUPD 3-57
ERREN 3-9
error counters 2-4, 2-15
error detection 3-103
error messages
    accumulate 2-2
    buffer 2-2

clear 2-3
DEC21x40 3-15
display 2-4
KBD8730x 3-51, 3-148
L2CACHE 3-63
PCIBUS 3-93
SCC 3-63, 3-128
UART 3-89
Ethernet Controller Tests - DEC21x40 3-4
examples of command entry 1-3
Extended PCI Register Access - XREGA 3-14
Extended Registers - EXTN 3-136
External Loopback - ELPBCK 3-124
External Loopback - LPBKE 3-87
EXTN 3-136

G

general commands 2-1
Generic PCI/PMC Slot Tests - PCIBUS 3-91
Graphics Controller Register 3-138
Graphics Controller Registers - GRPH 3-137
graphics tests 3-130
GRPH 3-137

H

HE 1-2, 1-3, 2-5
header verification 3-140
Help - HE 2-5
Help command 1-2
Help Extended - HEX 2-8
help screen 1-3, 2-5
HEX 2-8

I

I/O processor tests 3-64
I/O Resource Register Access - IOR 3-11
ILPBCK 3-125
ILR 3-10
indexed registers 3-11
INET
Intel Ethernet Controller Tests 3-20
INET Error Messages 3-26
initialization, chip 3-6
INST
Internal Self Test 3-24
installation 1-6
Intel Ethernet Controller Tests
Error Messages 3-26
PERT 3-20
SERT 3-21
Intel Ethernet Controller Tests (BINT) 3-22
Intel Ethernet Controller Tests (EEPT) 3-23
Intel Ethernet Controller Tests (INST) 3-24
Intel Ethernet Controller Tests (MDIT) 3-23
Intel Ethernet Controller Tests (MPACK) 3-26
Intel Ethernet Controller Tests (SPACK) 3-25
Intel tests 3-20
Internal Loopback - ILPBCK 3-125
Internal Loopback - LPBK 3-86
Interrupt - IRQ 3-42, 3-151
Interrupt Line Register Access - ILR 3-10
Interrupt Request - IRQ 3-85, 3-126
Interrupts - IRQ 3-72
IOR 3-11
IRQ 3-42, 3-72, 3-85, 3-126, 3-151
PCI/ISA Bridge Test 3-42
IRQ (Interrupt Request)
Serial I/O Tests 3-85
ISABRDGE - PCI/ISA Bridge Tests 3-41

K

KBCONF 3-45
KBD8730x error messages 3-51, 3-148
KBFAT 3-46
KBFAT (Keyboard Test) 3-46
KCCONF 3-47
KCEXT 3-48
Keyboard Controller Confidence/Extended - KCCONF 3-47
Keyboard Controller Tests
KBFAT (Keyboard Test) 3-46

KCCONF (Keyboard Controller Confidence/Extended 3-47
KCEXT (Keyboard/Mouse Controller Extended Test) 3-48
MSCONF (Mouse Device Confidence/Extended) 3-49
MSFAT (Mouse Test) 3-50
Keyboard Device Confidence/Extended - KBCONF 3-45
Keyboard Test - KBFAT 3-46
Keyboard/Mouse Controller Extended Test - KCEXT 3-48

L

L2CACHE Error Messages 3-63
LA 2-8
LC 2-9
LE 2-9
Level 2 Cache Tests
DISUPD (Disable Updating) 3-56
ENUPD (Enable Updating) 3-57
PATTERN (Write Thru Pattern) 3-58
SIZE (Verify Cache Size) 3-59
WBFL (Write Back w/Flush) 3-60
WBINV (Write Back w/Invalidate) 3-61
WRTHRU (Write Thru) 3-62
Level 2 Cache Tests - L2CACHE 3-55
LF 2-10
Line Feed Suppression Mode - LF 2-10
Linked Counter - LNK 3-152
LN 2-10
LNK 3-152
Local Parity Memory Error Detection - PED 3-103
Local RAM Test
MARCH (March Pattern) 3-101
Local RAM Tests - RAM 3-94
Loop Always Mode - LA 2-8
Loop Non-Verbose Mode - LN 2-10
loopback plug 3-8
Loop-Continue Mode - LC 2-9
Loop-On-Error Mode - LE 2-9
lowercase 2-2, 3-2
LPBK 3-86
LPBK (Internal Loopback)
Serial I/O Test 3-86
LPBKE 3-87

M

manual conventions 4
MARCH 3-101
MARCH (March Pattern)
Local RAM Test 3-101
march pattern 3-101
MASK 2-11
MDIT
MDI Interface Test 3-23
MDMC 3-127
Memory Addressing - ADR 3-95
Memory Refresh Testing - REF 3-107
microprocessor documents A-3
MIEN 3-77
MISC 3-138
Miscellaneous Register - MISC 3-138
MK48Txx Timekeeping Tests
ADR (BBRAM Addressing) 3-111
Modem Control - MDMC 3-127
monitor
debug 1-2
Mouse Device Confidence/Extended - MSCONF 3-49
Mouse Test - MSFAT 3-50
MPACK
Multiple Packet Interrupt Loopback Test 3-26
MSCONF 3-49, 3-148
MSFAT 3-50

N

NCR 53C8xx registers
ACC2 - Register Access 3-68
NCR 53C8xx SCSI I/O Processor Tests 3-64
Non-Verbose Mode - NV 2-12
NV 2-12

INDEX

O

overview of firmware 1-1

P

PAL 3-139
PAR8730x - Parallel Port Test 3-81
parallel interface tests 3-2
Parallel Interface Tests - CSL1283 3-2
Parallel Port Test
    REG (Register) 3-82
Parallel Port Test - PAR8730x 3-81
pass count 2-5
PATS 3-102
PATTERN 3-58
pattern march 3-101
PC8730x - Keyboard Controller Tests 3-44
PCI 3-75, 3-140
PCI Access - PCI 3-75
PCI Bus Tests
    REG (PCI/PMC Slot Register Access) 3-92
PCI Header Register Access - REGA 3-12
PCI Header Verification - PCI 3-140
PCI/ISA Bridge Tests 3-41
    IRQ 3-42
    REG (Register) 3-43
PCI/PMC Slot Register Access - REG 3-92
PCIBUS Error Messages 3-93
PED 3-103
PELM 3-141
PERM 3-105
Permutations - PERM 3-105
PERREN 3-9
PERT
    Parity Error Response Test 3-20
Pixel Mask Register - PELM 3-141
PowerPC board 1-1
PPC1-Bug> 1-2
PPC1-Diag> 1-2
PPCBug
    overview 1-1

Q

QST 2-13
Quick Self Test - QST 2-13
Quick Write/Read - QUIK 3-106
QUIK 3-106

R

RAM 3-116
RAM - Local RAM Tests 3-94
Random Data - RNDM 3-109
Real Time Clock Function - CLK 3-114
Receive/Transmit DMA - DMA 3-122
REF 3-107
REG 3-3, 3-43, 3-82, 3-92, 3-153
REG (PCI/PMC Slot Register Access) 3-92
REG (Register) 3-43
REGA 3-12, 3-88
REGA (Device/Register Access)
    Serial I/O Tests 3-88
Register - REG 3-3, 3-43, 3-82, 3-153
Register Access - ACC2 3-68
related documentation A-1
related specifications A-9
restart mode 3-2
RNDM 3-109
root-level command examples 1-3
root-level commands 2-1
RTC - MK48Txx Timekeeping Tests 3-110
RTC Timekeeping Tests
    CLK (Real Time Clock Function) 3-114
    RAM (Battery Backed-Up RAM) 3-116

S

SCC - Serial Communication Controller (Z85230) Tests 3-118
SCC error messages 3-128
SCC Tests
    BAUDS (Baud Rates) 3-121
scope 2-1
SCRIPTS 3-77
SCRIPTS Processor - SCRIPTs 3-77
SCSI FIFO - SFIFO 3-80

SCSI I/O Processor Tests
PCI (PCI Access) 3-75
SCRIPTS (SCRIPTs Processor) 3-77
SCSI I/O Processor Tests - NCR 3-64
SCSI Tests
ACC1 - Device Access 3-66
SD 2-12
SE 2-13
Self Test - ST 2-13
Self Test Mask 2-11
SEQR 3-142
Sequencer Controller Register 3-142
Sequencer Registers - SEQR 3-142
Serial I/O Tests
BAUD (Baud Rates) 3-84
IRQ (Interrupt Request) 3-85
LPBK (Internal Loopback) 3-86
REGA (Device/Register Access 3-88
SERREN 3-9
SERT
System Enable Response Test 3-21
SFIFO 3-80
Single Packet Send/Receive - SPACK 3-13
Single Step Mode 3-77
SIZE 3-59
SPACK 3-13
Single Packet Interrupt Loopback Test 3-25
ST 2-13
Stop-On-Error Mode - SE 2-13
subcommands 1-3
subdirectory-level command examples 1-4
switch directories 1-2
Switch Directories - SD 2-12
System Mode 2-10

T

test descriptions 3-1
test directory 2-11
test failure 2-11
Test Group Configuration Parameters Editor - CF 2-3
Timekeeper 3-116
typeface, meaning of 4

U

UART - Serial Input/Output Tests 3-83
UART error messages 3-89
uppercase 2-2, 3-2
utilities 2-1
utility command entry 1-3

V

Verify Cache Size - SIZE 3-59
Verify Chip ID - ID 3-38
VGA controller 3-135
VGA CRT Controller Register 3-134
VGA543X - Video Diagnostics Tests 3-130
Video Diagnostics Tests
BLT (Bit Blitter) 3-133
PAL (Color Palette) 3-139
PCI (PCI Header Verification) 3-140
SEQR (Sequencer Registers) 3-142
VRAM (Video Memory) 3-143
Video Diagnostics Tests - VGA543X 3-130
Video Memory - VRAM 3-143
VME Interface ASIC Tests - VME2 3-144
VME2 tests 3-144
VME3 Tests
REGR (Register Read) 3-146
REGW (Register Wrtie/Read) 3-147
VMEchip2 3-144
VRAM 3-143

W

WATCHDOG 3-117
Watchdog Time-Out Reset - WATCHDOG 3-117
WBFL 3-60
WBINV 3-61
World Wide Web address A-1
Write Back w/Flush - WBFL 3-60
Write Back w/Invalidate - WBINV 3-61
write/read 3-106

INDEX

WriteThru - WRTHRU 3-62
WriteThru Pattern - PATTERN 3-58
WRTHRU 3-62

X

XREGA 3-14

Z

ZE 2-15
Zero Pass Count - ZP 2-15
ZP 2-15

Artisan Technology Group is an independent supplier of quality pre-owned equipment

Gold-standard solutions

Extend the life of your critical industrial, commercial, and military systems with our superior service and support.

We buy equipment

Planning to upgrade your current equipment? Have surplus equipment taking up shelf space? We'll give it a new home.

Learn more!

Visit us at **artisantg.com** for more info on price quotes, drivers, technical specifications, manuals, and documentation.

Artisan Scientific Corporation dba Artisan Technology Group is not an affiliate, representative, or authorized distributor for any manufacturer listed herein.

We're here to make your life easier. How can we help you today?

(217) 352-9330 | sales@artisantg.com | artisantg.com

ARTISAN® TECHNOLOGY GROUP